

Medtronic

Cardiac Rhythm Disease Management

Product Performance Report Important Patient Management Information for Physicians



This report is available online at www.medtronic.com/CRDMProductPerformance

A Message from the Vice President

Dear Customer,

At Medtronic, product quality and reliability have been and will continue to be a priority. For over 29 years, Medtronic has compiled and produced product performance reports with one primary goal, to provide you with the product information you need to best care for your patients.

Our commitment to you is best expressed in Medtronic's mission: "To strive without reserve for the greatest possible reliability and quality in our products; to be the unsurpassed standard of comparison and to be recognized as a company of dedication, honesty, integrity, and service." To this end, we continually explore new ways to expand, improve, and learn from our product performance systems and measures.

Our quality goals cannot be reached alone. We welcome your collaboration, insight, and recommendations. Please contact our Technical Services Department at 1 (800) 723-4636 with your feedback comments and any questions.

Your participation and assistance in returning explanted products are also critical. Returned products are tested and evaluated so that we can fully measure the performance of our devices. Please refer to the instructions on the next page for assistance in returning products to the Medtronic CRDM Returned Product Analysis Laboratory.

As we constantly strive to exceed your expectations, we thank you for your dedication to improving and saving the lives of those suffering from cardiac rhythm disorders.

With appreciation and warm regards,

Tim Samsel Vice President, Quality and Regulatory Medtronic Cardiac Rhythm Disease Management Medtronic, Inc.

Contact Information

We invite our customers to use these telephone numbers to call with suggestions, inquiries, or specific problems related to our products.

US Technical Services Department

Phone: 1 (800) 723-4636 (Tachy) 1 (800) 505-4636 (Brady) Fax: 1 (800) 824-2362 www.medtronic.com/corporate/contact.jsp

For questions related to this CRDM Product

Performance Report, please call US Technical Services at the number above, or write to:

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For questions related to returning explanted product or returning product that shows signs of malfunction, please contact:

Outside the United States:

Your Medtronic representative or international technical center at the number above.

Within the United States: Your Medtronic representative or

CRDM Returned Product Analysis Laboratory

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Date cutoff for this edition is March 12, 2013 for devices and February 1, 2013 for PSR leads data

This report is available online at www.medtronic.com/CRDM ProductPerformance

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Introduction

All product performance reports are not created equal. For 29 years, Medtronic has monitored performance via both returned product analysis and multicenter clinical studies.

This Product Performance Report (PPR) presents device survival estimates, advisory summaries, performance notes, and other information pertinent to assessing the performance of Medtronic implantable pulse generators (IPGs), implantable cardioverter defibrillators (ICDs), cardiac resynchronization therapy (CRT) devices, and implantable pacing and defibrillation leads.

This Product Performance Report has been prepared in accordance with International Standard ISO 5841- 2:2000(E).

The survival estimates provided in this report are considered to be representative of worldwide performance.

Survival Estimates

Medtronic, like other companies, monitors CRT, ICD, and IPG device performance using returned product analysis. We also monitor CRT, ICD, and IPG device performance using an active multicenter clinical study.

Returned product analysis is a passive approach to assessing product performance. This approach provides a suitable measure of product performance only when a significant number of explanted products are returned to the manufacturer. Returned product analysis provides a measure of hardware performance, but not necessarily the total clinical performance (e.g., the incidence of complications such as infection, erosion, muscle stimulation, etc. are not estimated).

The survival estimates provided in this report for CRT, ICD, and IPG devices are based on returned product analysis. This approach is suitable because a significant number of explanted generators are returned for analysis.

Lead performance is monitored differently. In contrast to CRT, ICD, and IPG devices, a very small percentage of leads are returned to the manufacturer due to the difficulty of explanting them. For leads, an active clinical study provides more accurate survival estimates compared to estimates based solely on returned product analysis.

Survival estimates for leads are based on clinical observations recorded via Medtronic CRDM's System Longevity Study. This multicenter clinical study is designed to record clinical observations representative of the total clinical experience. Therefore, the lead survival estimates include both lead hardware failure and lead-related medical complications, and do not differentiate a lead hardware failure from other clinical events such as exit block, perforation, dislodgement, or concurrent pulse generator failure. The actuarial life table method is applied to the data collected for CRT, ICD, and IPG devices and leads to provide the survival estimates included in this report. A general introduction to understanding this method of survival analysis is given later in this introduction.

ICD Charge Times

Since May 2000, Medtronic has provided important information on charge time performance of ICDs. The information provided in this report shows how ICD charge time can vary during the time a device is implanted. The information is presented in graphical format showing charge time as a function of implant time. The data for charge times are collected from devices enrolled in the Product Surveillance Registry.

Advisory Summaries

This Product Performance Report includes summaries of all advisories applicable to the performance of the products included in the report. An advisory is added to the report when any product affected by the advisory remains in service and at risk of experiencing the behavior described in the advisory. The advisory will remain in the report until Medtronic estimates no product affected by the advisory remains active, or the risk of experiencing the behavior described in the advisory has passed.

For most advisories, the products subject to the advisory retain essentially the same survival probability as the products of the same model(s) not affected by the advisory. For those advisories where the survival probabilities of the affected and non-affected populations do differ significantly, Medtronic will provide separate survival data for each population. The separate survival data will remain in the report until Medtronic estimates no affected product remains in active service.

Performance Notes

This report concludes with a number of Performance Notes developed by Medtronic to provide additional product performance information relevant to follow-up practice and patient management.

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

How You Can Help

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of the reason for explant or removal from use. The procedures for returning products vary by geographic location.

Mailer kits with prepaid US postage are available for use within the United States to send CRTs, ICDs, IPGs, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet US postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of explanted products from non-clinical sources, such as funeral homes, and will assume responsibility for storage and disposal of the product once received.

Mailer kits can be obtained by contacting the Returned Product Lab. For information on how to contact the Lab, refer to the Contact Information page of this report.

We continually strive to improve this CRDM Product Performance Report. In keeping with this philosophy, we ask for your suggestions on the content and format of this report, as well as any information you have regarding the performance of Medtronic products. For information on how to comment on this report, see the Contact Information page of this report.

Overview of Survival Analysis

Medtronic uses the Cutler-Ederer actuarial life table method to estimate the length of time over which devices and leads will perform within performance limits established by Medtronic. This probability to perform within performance limits over time is called the *survival probability*.

Devices and leads are followed until an *event* occurs where the device or lead ceases to operate within performance limits. The length of time from implant to the event is recorded for individual devices and leads in the *population sample*. The population sample for CRT, ICD, and IPG devices is made up of patients whose devices are registered as implanted in the United States. For leads, the population sample is the patients enrolled in our multicenter, international prospective Product Surveillance Registry.

For IPGs and ICDs, the events can be normal battery depletion or a device malfunction. For leads, the events are complications as defined in the study protocol.

The actuarial life table method allows Medtronic to account for devices and leads removed from service for reasons unrelated to performance and for device and leads still in service. Devices and leads removed for reasons unrelated to performance or are still in service are said to be suspended. Examples of devices and leads removed from service for reasons unrelated to performance include:

- removed to upgrade the device or lead
- no longer in service due to the death of the patient for reasons unrelated to the device or leads
- implanted in patients who are lost to follow-up

For each suspension, the device or lead has performed within performance limits for a period of time, after which its performance is unknown.

An Example

The following example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads. The example is intended to provide an overview of the analysis process. The definitions of malfunctions and complications, and other details specific to calculating device and lead survival estimates, are provided in the articles *Method for Estimating CRT, ICD, and IPG Device Performance (page 6)* and *Method for Estimating Lead Performance (page 74)*.

This simple example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads.

Figure 1

Implant times for devices of 16 patients. Gray bars with a yellow X indicate devices removed from service due to an event. Blue bars indicate suspended devices.

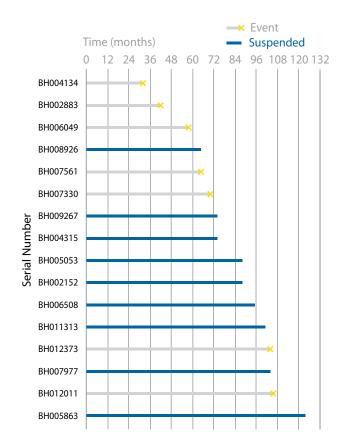


Figure 1 illustrates 16 patients who have implanted devices. The first patient's device (serial number BH004134) operated within performance limits for 32 months. At that time an event occurred. The fourth patient's device (serial number BH008926) did not have an event but is suspended, perhaps because it was still in service at the time of the analysis. This patient had 66 months of implant experience. In this example, Figure 1 shows that seven of the 16 devices suffered events, and nine are suspended.

The first step in the life table method is to divide the implant time into intervals of a specific length. This example will use 12-month intervals. The number of devices entered, suspended, and removed due to an event are counted and summarized, as shown in Table 1. For the first two intervals, all 16 devices survived and none were removed. In the interval (24-36 months), device BH004134 was removed due to an event. Therefore the table entries show that 16 entered the interval, none were suspended, and one was removed due to an event.

For the interval from 36-48 months, only 15 devices entered the interval and one was removed for an event. The remaining intervals are examined and the data entered in columns A, B, and C in like manner. The rest of the columns are filled in using calculations on the data in columns A, B, and C.

The *Effective Sample Size* (**D**) is the number of devices with full opportunity to experience a qualifying event in the interval. This is computed by subtracting one half the number suspended in the interval from the number that entered the interval. This calculation more accurately reflects the number of devices that could have experienced a qualifying event than simply using the number that entered the interval. Using the number of devices that enter an interval overestimates the sample size because the suspended devices do not complete the interval. Ignoring the suspended devices underestimates the sample size because suspended devices are not credited with their full service time. Using one half the number of suspended devices effectively splits the difference.

The next column in the table is the *Proportion with Event* (E). This is the proportion of devices that had an event in the interval. It is calculated by dividing the *Number of Events* (C) by the *Effective Sample Size* (D). The number can be interpreted as the estimated rate at which events occur in the time interval.

The Interval Survival Probability (\mathbf{F}) is the estimate of probability of surviving to the end of the interval assuming the device was working at the beginning of the interval. It is calculated as 1 minus the *Proportion with Event* (\mathbf{E}). This number can be interpreted as the estimated rate at which events **do not** occur in the time interval.

Introduction continued

The Cumulative Survival Probabilities (G) from the last column of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data shown in Table 1.

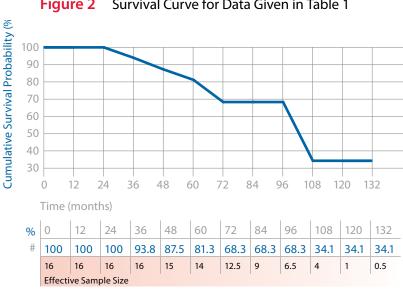
	А	В	с	D	E	F	G
Interval in Months	Number Entered	Number Suspended	Number of Events	Effective Sample Size	Proportion with Event	Interval Survival Probability	Cumulative Survival Probability
0	16	0	0	16	0.000	1.000	1.000
0-12	16	0	0	16	0.000	1.000	1.000
12-24	16	0	0	16	0.000	1.000	1.000
24-36	16	0	1	16	0.063	0.938	0.938
36-48	15	0	1	15	0.067	0.933	0.875
48-60	14	0	1	14	0.071	0.929	0.813
60-72	13	1	2	12.5	0.160	0.840	0.683
72-84	10	2	0	9	0.000	1.000	0.683
84-96	8	3	0	6.5	0.000	1.000	0.683
96-108	5	2	2	4	0.500	0.500	0.341
108-120	1	0	0	1	0.000	1.000	0.341
120-132	1	1	0	0.5	0.000	1.000	0.341

Table 1Life Table for Figure 1

Definitions:

Α	В	C	D	E	F	G
Number Entered	Number Suspended	Number of Events	Effective Sample Size	Proportion with Event	Interval Survival Probability	Cumulative Survival Probability
Number of devices active at the start of the interval	Number of devices removed from service for reasons other than an event	Number of units removed from service due to an event	Number of units with full opportunity to experience a qualifying event in the interval. Computed by subtracting one half the Number Suspended from the Number Entered.	Proportion of devices that had an event in the interval. Computed by dividing the Number of Events by the Effective Sample Size.	The probability of surviving to the end of the interval, assuming the device was working at the beginning of the interval. Computed as 1 minus the Proportion With Event.	The overall probability of surviving to the end of the interval. Computed by multiplying the Interval Survival Probability by the previous interval's Cumulative Survival Probability.

Cumulative Survival Probability (G) is the estimate of the unconditional probability of surviving to the end of the interval. It is computed by multiplying the *Interval Survival Probability* (F) by the previous interval's Cumulative Survival Probability. The probability of surviving to 132 months in the example is estimated for the table to be 0.341, or 34.1%. The *Cumulative Survival Probabilities* (G) of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data in Table 1.



Survival Curve for Data Given in Table 1 Figure 2

Confidence Intervals

Since survival curves are based on a sample of the device and lead population, they are only estimates of survival. The larger the effective sample size, the more confident the estimate. A confidence interval can be calculated to assess the confidence in an estimate. In the Product Performance Report, Medtronic provides a 95% confidence interval. This can be interpreted as meaning that 95% of the time, the true survival of the device will fall somewhere in the interval.

Survival Curves in the Product **Performance Report**

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRTs, ICDs, and IPGs, and when the number entered is less than 50 for leads. The survival charts in the Product Performance Report show the effective sample size for each year interval where Medtronic has experience. When the effective sample size reaches 100 for CRTs, ICDs, and IPGs or when the number entered reaches 50 for leads, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using 1-month intervals (for CRT, ICD, and IPG devices) or 3-month intervals (for leads).

A number of references are available for additional information on survival analysis using the Cutler-Ederer life table method.¹

¹ Lee, Elisa T.(2003) Statistical Methods for Survival Data Analysis – 3rd Edition (Wiley Series in Probability and Statistics).

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

The performance of CRT, ICD, and IPG devices is expressed in terms of device survival estimates, where "survival" refers to the function of the device, not the survival of the patient. These survival estimates are intended to illustrate the probability that a device will survive for a given number of years with neither malfunction nor battery depletion.

The survival estimates are determined from the analysis of Medtronic CRDM's United States device registration data and US returned product analysis data. These data are presented graphically and numerically.

Because this analysis is based on returned product analysis, the performance data does not reflect any device-related medical complications such as erosion, infection, muscle stimulation, or muscle inhibition.

Categorization of Depleted and Malfunctioning Devices for Survival Analysis

For survival estimation, every device returned to Medtronic CRDM and analyzed in the CRDM Returned Product Analysis laboratory is assigned to one of three categories. The device 1) is functioning normally, 2) has reached normal battery depletion, or 3) has malfunctioned. This categorization is combined with data from our device registry for the total number of implants and the implant durations to create the survival curves presented on the following pages.

Definition of Malfunction

Medtronic CRDM considers a device as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction or battery depletion, the device must have been returned to Medtronic and analyzed.

Devices damaged after explant, damaged due to failure to heed warnings or contraindications in the labeling, or damaged due to interaction with other implanted devices (including leads) are not considered device malfunctions.

A device subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic. Not all malfunctions expose the patient to a loss of pacing or defibrillation therapy. Some malfunctions included in the following survival estimates may not have been detected at all by the physician or the patient. These malfunctions, however, are included in the survival estimates and provide important feedback to our product development organization.

To provide insight into the nature of malfunctions, each malfunction is categorized as Malfunction with Compromised Therapy Function or Malfunction without Compromised Therapy Function. A summary of these malfunctions is presented for the most recently market-released models.

For this report, Normal Battery Depletion, Malfunction with Compromised Therapy Function, and Malfunction without Compromised Therapy Function are defined as follows:

Normal Battery Depletion – The condition when:

- (a) a device is returned with no associated complaint and the device has reached its elective replacement indicator(s) with implant time that meets or exceeds the nominal (50 percentile) predicted longevity at default (labeled) settings, or
- (b) a device is returned and the device has reached its elective replacement indicator(s) with implant time exceeding 80% of the expected longevity calculated using the available device setting information.

Medtronic CRDM establishes expected longevity by statistically characterizing the power consumed by the device and the power available from the device battery. This characterization is applied to a number of parameter configurations to derive a statistical mean longevity value and standard deviation for each parameter configuration. The statistical mean value minus three standard deviations is used as the expected longevity for determining if a battery depleted normally.

continued

The Standard Actuarial Method is used to estimate IPG and ICD survival. This product performance report has been prepared in accordance with International Standard ISO 5841-2:2000(E).

For reference purposes, the following pages include estimated longevities for each model. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

Malfunction with Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that compromised pacing or defibrillation therapy (including complete loss or partial degradation), while implanted and in service, as confirmed by returned product analysis.

Examples: Sudden loss of battery voltage; accelerated current drain such that low battery was not detected before loss of therapy; sudden malfunction during defibrillation therapy resulting in aborted delivery of therapy, intermittent malfunction where therapy is compromised while in the malfunction state.

Malfunction without Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that *did not* compromise pacing or defibrillation therapy, while implanted and in service, as confirmed by returned product analysis.

Examples: Error affecting diagnostic functions, telemetry function, data storage; malfunction of a component that causes battery to lose power quickly enough to cause premature battery depletion, but slowly enough that the condition is detected through normal follow-up before therapy is lost; mechanical problems with connector header that do not affect therapy.

Expanded Malfunction Detail

The malfunctions are further divided into categories that identify the subject area of the malfunction. The malfunctions are divided into the following subject areas:

Electrical Component – Findings linked to electrical components such as integrated circuits, resistors, capacitors, diodes, etc.

Electrical Interconnect – Findings linked to the connections between electrical components such as wires, solder joints, wire bonds, etc.

Battery – Findings linked to the battery and its components

Software/Firmware – Findings linked to software or firmware function

Possible Early Battery Depletion – Findings where the actual reported implant time is less than 80% of the expected longevity calculated using the available device setting information with no device malfunction observed. There may not be sufficient device setting information to determine conclusively if battery depletion was normal or premature in the absence of a specific root cause finding. However, returned devices meeting the above criteria are conservatively classified as Possible Early Battery Depletion malfunctions.

Other – Findings related to other components such as insulators, grommets, setscrews, and packaging, and findings where analysis is inconclusive

Returned Product Analysis Process

Analysis of returned product is performed according to written procedures. These procedures determine the minimum analysis required. The analysis required varies depending on the type of device, age of the device, the associated information received with the device, actual experience with models of similar design, and other factors. Additional analysis is performed as necessary to investigate a performance concern from a customer, or to collect specific reliability data.

When a device is returned with a performance concern from a customer, the general analysis process includes a preliminary analysis of the device in its as-received condition, followed by an automated functional test using test equipment equivalent to the equipment used in manufacturing.

When a malfunction is identified, failure analysis is performed to provide the detailed information necessary to investigate possible causes and actions. Medtronic CRDM maintains in-house expertise and performs its failure analysis using facilities it owns and supports. This capability permits detailed failure analysis.

continued

Medtronic CRDM adjusts all-cause survival estimates to account for underreporting. While this lowers our all-cause survival estimates, we feel it gives a more accurate perspective on real performance.

Statistical Methods for Survival Analysis

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed evenly within the intervals (Cutler-Ederer Method), is used to determine estimates of IPG and ICD survival. This method is commonly used by medical researchers and clinicians.

Implant times are calculated from the implant date to the earlier of the explant date or the cutoff date of the report. From this data an estimate of the probability of device survival is calculated at each monthly interval.

On the following pages, each graph includes a survival curve where events include malfunctions and normal battery depletions. This survival curve is a good representation of the probability a device will survive a period of time without malfunction and without battery depletion. For example, if a device survival probability is 95% after 5 years of service, then the device has a 5% chance of being removed due to battery depletion or malfunction in the first 5 years following implant.

In addition, a second curve is included to show survival excluding normal battery depletion. This curve is a good representation of the probability for a device to survive without malfunction. This curve includes only malfunctions as events and excludes normal battery depletion.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRT, ICD, and IPG devices. The survival charts in the Product Performance Report show the effective sample size for each year interval where we have experience. When the effective sample size reaches 100, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using one-month intervals.

The data in the tables are rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have one or more malfunctions or battery depletions. This occurs because, even with the malfunctions or battery depletions, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way to indicate the degree of certainty of the estimates. Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors, and the complementary log-log method is used to produce the confidence bounds.

Sample Size and How the Population and Population Samples Are Defined

The population sample from which the survival estimates are derived is comprised of the devices registered as implanted in the United States as of the report cutoff date. The number of registered implants, as well as an estimate of the number that remain in active service, is listed for each model. To be included in the population, the device must have been registered with Medtronic's registration system and implanted for at least one day.

This sample based on US implants is considered to be representative of the worldwide population, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

A CRT, ICD, or IPG model or model family will be included in this report when it has accumulated at least 10,000 implant months and will remain in the report as long as at least 500 devices remain active.

Methods Used to Adjust for Underreporting of Malfunction and Battery Depletion

The tables on the following pages show the actual number of malfunctions and battery depletions recorded by the analysis lab for US registered devices. Since not all devices are returned to Medtronic CRDM for analysis, these numbers underestimate the true number of malfunctions and battery depletions. To more accurately estimate the all-cause device survival probabilities, the number of malfunctions and battery depletions used to plot each interval of the all-cause survival curves is adjusted (multiplied) by a factor that is based on an estimate of the magnitude of underreporting. The magnitude of underreporting is estimated by analyzing experience in Medtronic's Device And Registrant Tracking (DART) system.

The DART system is an important element of Medtronic's Quality System. The DART system is designed to meet or exceed the US FDA's device tracking requirements set forth by the Safe Medical Devices Act. In the United States, over 98% of Medtronic's CRT, ICD, and IPG implants become registered in the DART system. continued

Because pacemakers do not cure the patient's underlying health problem, when a pacemaker stops functioning (due to either normal battery replacement or malfunction) it is replaced with a new pacemaker. Therefore, the replacement recorded in the DART system is a good indication that the previous pacemaker experienced either battery depletion or malfunction. The fraction of replaced devices that are subsequently returned can be used to estimate the correction factor for the under reporting of the combination of battery depletion and malfunction.

Note that devices of patients who have expired do not factor into the calculation of the correction. It is possible some proportion of these device experienced battery depletion or malfunction. Since these are not counted into the correction factor based on the return rate of replaced devices, a correction factor based only on the return rate of replaced devices may still underestimate the true rate of battery depletion and malfunction. However, devices that are replaced because the patient is receiving a system upgrade or are removed because the patient no longer needs it (e.g., due to heart transplant) do contribute to the calculation of the correction factor and therefore impart an opposite bias.

Also note that this method of calculating the correction factor cannot distinguish between devices that are removed due to malfunction and those due to normal battery depletion. It might seem intuitive that devices that unexpectedly malfunction should be much more likely to be returned to the manufacturer than a device with ordinary normal battery depletion. But this has not been conclusively demonstrated. Therefore, this method only provides a correction factor reflecting the combination of battery depletion and malfunction.

No adjustment for underreporting is applied to the malfunction-free survival curve because a method for estimating malfunction-only underreporting has not been developed.

Adjustments to Registered Implants to Compensate for Unreported Devices Removed from Service

Devices are at times removed from service for reasons other than device malfunction or battery depletion. Examples are devices removed from service due to nondevice related patient mortality and devices removed due to changes in the patient's medical condition. Because an accurate estimate of device survival depends on an accurate estimate of the number of devices in service, it is important not to overstate the number of devices in service.

To ensure the number of devices in service is not overstated, Medtronic addresses this underreporting in two ways. Regular updates obtained from the Social Security Administration about deceased persons is used to update Medtronic's DART data about patients who have died but whose deaths had not been reported to Medtronic. In addition, the patient mortality rate derived from our DART system is monitored and compared to published mortality rates for comparable patient populations. If, during calculation of the survival curves, the patient mortality indicated by the data in DART is significantly different from published rates, an adjustment is applied to correct the difference.

7299 InSync Sentry

299 InSync Sentry				Product Characteristics	
US Market Release	Apr-05	Malfunctions (US)	180	NBD Code	VVED
Registered US Implants	31,200	Therapy Function Not Compromised	169	Serial Number Prefix	PRK
Estimated Active US Implants	2,250	Electrical Component	18	Max Delivered Energy	35 J
Normal Battery Depletions (US)	9,582	Possible Early Battery Depletion	147	Estimated Longevity	See page 21
Advisories	None	Software Malfunction	2		
		Other	2		

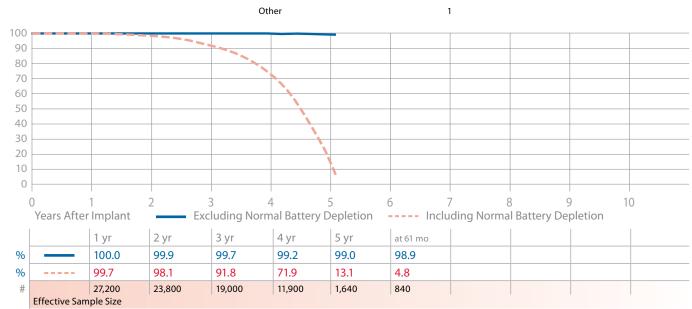
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10

Therapy Function Compromised

Electrical Component

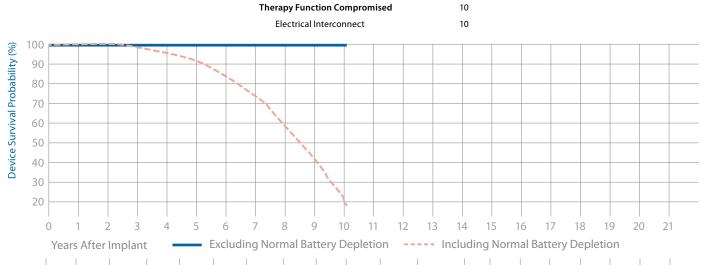
Device Survival Probability (%)





8040 InSync

US Market Release	Aug-01	Malfunctions (US)	36	NBG Code	DDDR
Registered US Implants	15,300	Therapy Function Not Compromised	26	Serial Number Prefix	PIN
Estimated Active US Implants	1,370	Electrical Component	4	Estimated Longevity	See page 22
Normal Battery Depletions (US)	1,346	Electrical Interconnect	16		
Advisories	None	Possible Early Battery Depletion	3		
		Other	3		

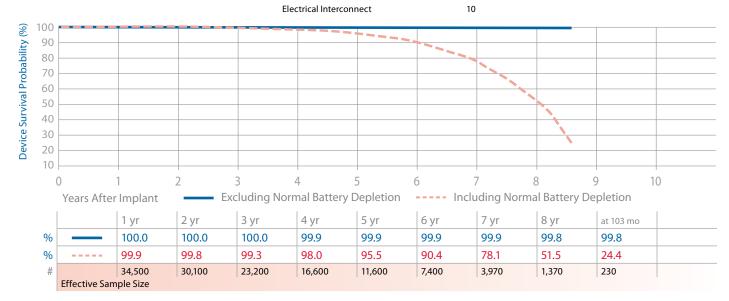


		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	at 121 mo				
%		100.0	100.0	99.9	99.8	99.7	99.6	99.5	99.5	99.4	99.4	99.4				
%		99.8	99.5	98.0	95.7	90.8	83.5	73.1	58.6	40.6	19.8	17.7				
#		12,300	10,100	8,110	6,370	4,970	3,720	2,620	1,620	840	240	150				
	Effective Sample Size															

8042 InSync III

US Market Release	Feb-03	Malfunctions (US)	24	NBG Code	DDDR
Registered US Implants	39,500	Therapy Function Not Compromised	14	Serial Number Prefix	PKF
Estimated Active US Implants	14,800	Electrical Component	2	Estimated Longevity	See page 22
Normal Battery Depletions (US)	1,821	Electrical Interconnect	3		
Advisories	None	Possible Early Battery Depletion	1		
		Other	8		

Therapy Function Compromised



12 Medtronic CRDM Product Performance Report www.medtronic.com/CRDMProductPerformance **Product Characteristics**

10

C154DWK, C164AWK, C174AWK Concerto

Product Characteristics

			(N)	(A)				(N)	(A)		
JS Mar	rket Release		May-06	May-06	Malfun	ctions (US)		1,203	1,298	NBD Code	DDED
egiste	ered US Implan	ts	81,300	3,500	Thera	py Function No	ot Compromise	d 1,166	1,284	Serial Number Prefix	PVU, PVT, PVR
stima	ited Active US I	mplants	27,000	200	El	ectrical Compo	nent	515	1,280	Max Delivered Energy	35 J
lorma	al Battery Deple	etions (US)	13,508	264	El	ectrical Interco	nnect	2	0	Estimated Longevity	See page 21
	ories: See pag		otential		Sc	oftware/Firmwa	ire	3	0		
educe	ed Device Long	jevity			Po	ossible Early Bat	tery Depletion	636	4	(N) = Non-advisory population	ı
	mance Note: S		-		01	ther		10	0	(A) = Advisory population	
	alies in MOSFET Technology	Integrated			Thera	py Function Co	ompromised	37	14		
					El	ectrical Compo	nent	35	12		
					El	ectrical Interco	nnect	2	1		
					O	ther		0	1		
									1		
100											
90					-		C154DW	K, D164AWK,0	2174AWk	(Non-advisory population) 97.19	%
80			· · · · · · · · · · · · · · · · · · ·								
70											
60							C154DWK, D16	 54AWK,C174A	.WK (Adv	sory population) 51.2%	
50 40											
30							1				
20							1				
10					<u>\</u>		1				
0											
	0	1	2	3		4	5 6	5	7	8 9	10
	Years After	Implant		Excludir	ng Nori	mal Battery I	Depletion	In	cluding	y Normal Battery Depleti	on
	Non-Adv	1 yr	2 yr	3 yr		4 yr	5 yr	at 63 mo			
%		100.0	99.8	99.5		98.3	97.1	97.1			
		99.8	00.4	0.00 5		70.2	44.0				
%			98.4	93.5		79.3	41.9	14.1			
% #		72,800	98.4 64,100	53,70		79.3 33,600	41.9 6,280	14.1 860			
	Effective Sam	72,800									
	Effective Sam	72,800 pple Size	64,100	53,70		33,600					
#		72,800 pple Size	64,100 2 yr	53,70 3 yr		33,600 at 43 mo					
	Effective Sam	72,800 pple Size	64,100	53,70		33,600					

3,120 Effective Sample Size

D224TRK, D234TRK, D204TRM, D214TRM Consulta CRT-D/CRT-D M4

Product Characteristics

19

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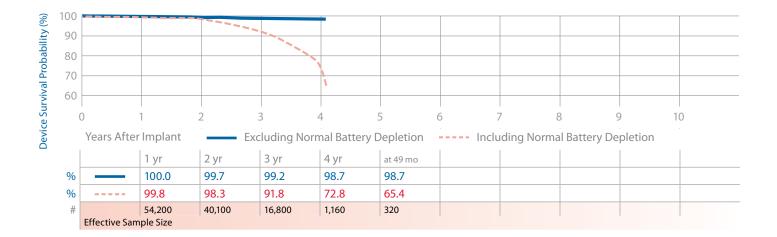
10

US Market Release	Sep-08	Malfunctions (US)	340	NBD Code	DDED
Registered US Implants	64,700	Therapy Function Not Compromised	330	Serial Number Prefix	PUD
Estimated Active US Implants	48,770	Electrical Component	17	Max Delivered Energy	35 J
Normal Battery Depletions (US)	1,568	Electrical Interconnect	1	Estimated Longevity	See page 21
Advisories	None	Possible Early Battery Depletion	288		
		Software Malfunction	5		

Other

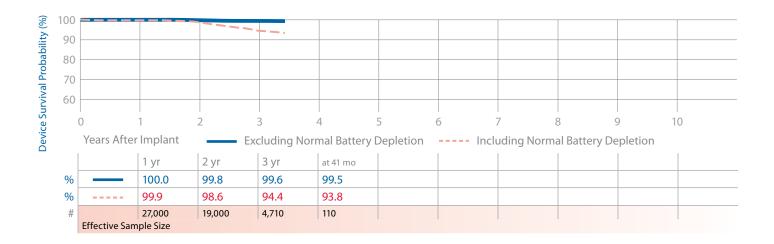
Therapy Function Compromised

Electrical Component



D274TRK, D294TRK Concerto II CRT-D

US Market Release	Aug-09	Malfunctions (US)	73	NBD Code	DDED
Registered US Implants	30,100	Therapy Function Not Compromised	72	Serial Number Prefix	PZV
Estimated Active US Implants	24,000	Electrical Component	6	Max Delivered Energy	35 J
Normal Battery Depletions (US)	332	Possible Early Battery Depletion	57	Estimated Longevity	See page 21
		Software/Firmware	1		
Advisories	None	Other	8		
		Therapy Function Compromised	1		
		Electrical Component	1		



D264TRM, D284TRK Maximo II CRT-D/CRT-D M4

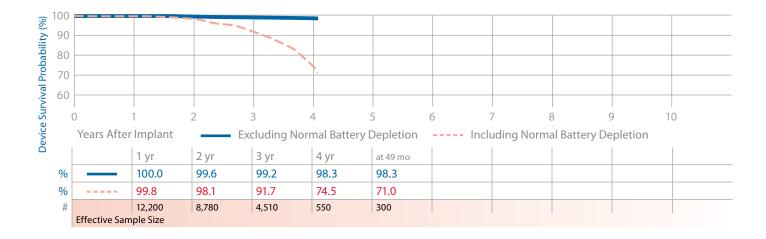
US Market Release	Sep-08	Malfunctions (US)	86	NBD Code	DDED
Registered US Implants	14,500	Therapy Function Not Compromised	84	Serial Number Prefix	PZP
Estimated Active US Implants	10,600	Electrical Component	3	Max Delivered Energy	35 J
Normal Battery Depletions (US)	422	Possible Early Battery Depletion	75	Estimated Longevity	See page 21
Advisories	None	Other	6		
		Therapy Function Compromised	2		

Electrical Component

Product Characteristics

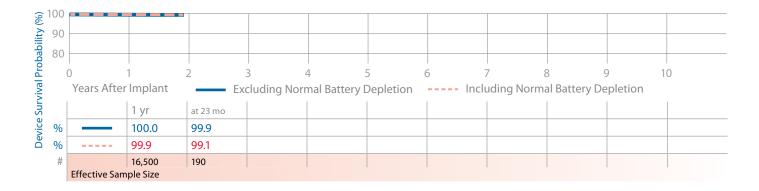
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NBD Code	DDED
Serial Number Prefix	PZP
Max Delivered Energy	35 J
Estimated Longevity	See page 21



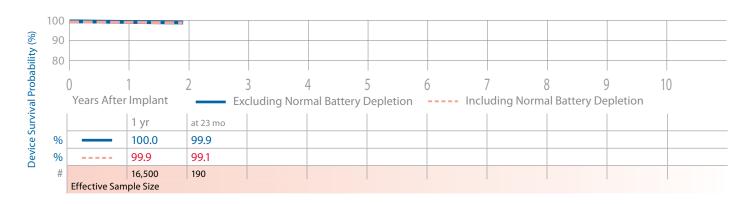
D314TRG, D354TRG, D314TRM, D354TRM Protecta XT CRT-D/CRT-D M4 Product Characteristics

US Market Release	Mar-11	Malfunctions (US)	16	NBD Code	DDED
Registered US Implants	39,300	Therapy Function Not Compromised	14	Serial Number Prefix	PFS
Estimated Active US Implants	37,440	Electrical Component	5	Max Delivered Energy	35J
Normal Battery Depletions (US)	21	Possible Early Battery Depletion	1	Estimated Longevity	See page 21
Advisories	None	Other	8		
		Therapy Function Compromised	2		
		Electrical Component	2		



D334TRG, D364TRG, D334TRM, D364TRM Protecta CRT-D/CRT-D M4

US Market Release Mar-11 Malfunctions (US) NBD Code DDED 2 **Registered US Implants** Serial Number Prefix PSO 6,570 **Therapy Function Not Compromised** 1 Estimated Active US Implants 6,240 Other Max Delivered Energy 35J 1 Normal Battery Depletions (US) 1 **Therapy Function Compromised Estimated Longevity** See page 21 1 Advisories None **Electrical Component** 1



C2TR01 Syncra CRT-P

US Market Release	Mar-11	Malfunctions (US)	4	NBG Code	OOED
Registered US Implants	5,400	Therapy Function Not Compromised	4	Serial Number Prefix	PZX
Estimated Active US Implants	4,990	Other	4	Max Delivered Energy	NA
Normal Battery Depletions (US)	0	Therapy Function Compromised	0	Estimated Longevity	See page 22
Advisories	None				



Product Characteristics

C3TR01, C4TR01 Consulta CRT-P

US Market Release	Mar-11	Malfunctions (US)
Registered US Implants	6,900	Therapy Function Not Compromised
Estimated Active US Implants	6,450	Therapy Function Compromised
Normal Battery Depletions (US)	1	
Advisories	None	

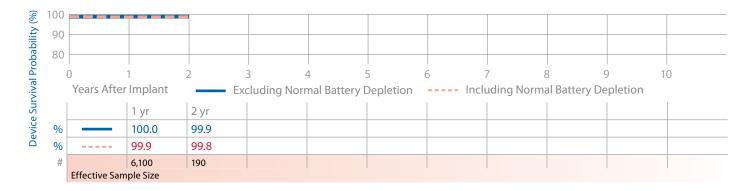
Product Characteristics

0

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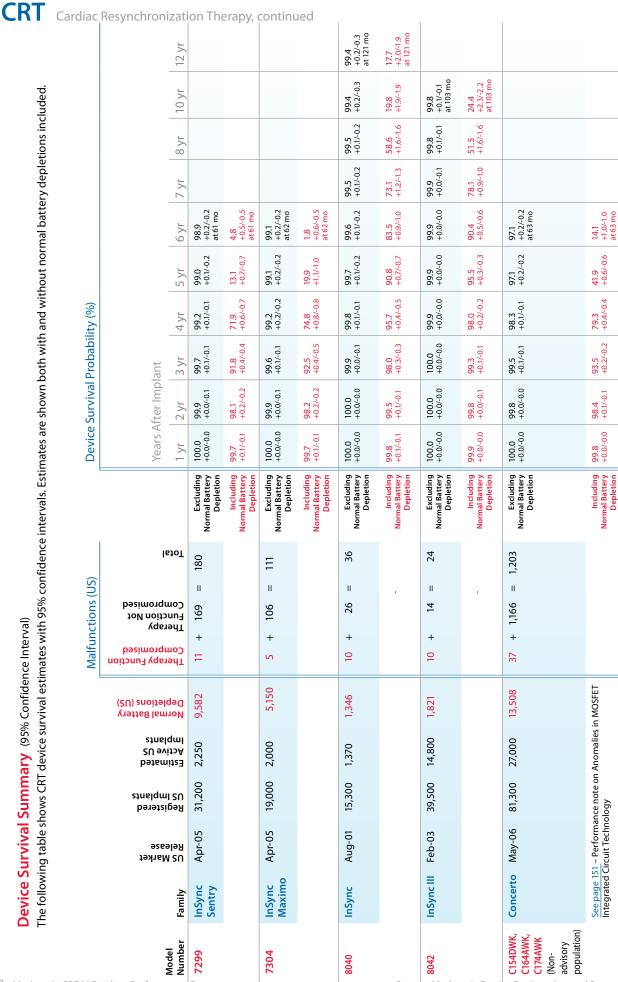
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NBG Code	OAED
Serial Number Prefix	PVX
Max Delivered Energy	NA
Estimated Longevity	See page 22



Device Survival Summary (95% Confidence Interval)

The following table shows CRT device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included.



18 Medtronic CRDM Product Performance Report www.medtronic.com/CRDMProductPerformance Source: Medtronic Device Registration and Returned Product Analysis Data as of March 12, 2013

		9 yr											
		8 yr											
		7 yr											
		6 yr											
		5 yr 6				98.7 +0.2/-0.2 at 49 mo	65.4 +2.6/-2.8 at 49 mo			98.3 +0.4/-0.5 at 49 mo	71.0 +2.5/-2.7 at 49 mo		
(%)		4 yr	51.2 +2.2/-2.2 at 43 mo	8.1 +1.5/-1.3 at 43 mo		98.7 +0.2/-0.2	72.8 +1.3/-1.4	99.5 +0.1/-0.2 at 41 mo	93.8 +0.5/-0.5 at 41 mo	98.3 +0.4/-0.5	74.5 +1.9/-2.0		
robabilit	int	3 yr	79.1 +1.6/-1.7	60.0 +1.9/-2.0		99.2 +0.1/-0.1	91.8 +0.3/-0.3	99.6 +0.1/-0.1	94.4 +0.4/-0.4	99.2 +0.2/-0.2	91.7 +0.6/-0.7		
Device Survival Probability (%)	Years After Implant	2 yr	99.4 +0.2/-0.3	97.5 +0.5/-0.6		99.7 +0.0/-0.1	98.3 +0.1/-0.1	99.8 +0.0/-0.1	98.6 +0.1/-0.2	99.6 +0.1/-0.1	98.1 +0.2/-0.3	99.9 +0.0/-0.0 at 23 mo	99.1 +0.3/-0.6 at 23 mo
Device 9	Years Af	1 yr	99.8 +0.1/-0.2	99.8 +0.1/-0.3		100.0 +0.0/-0.0	99.8 +0.0/-0.0	100.0 +0.0/-0.0	99.9 +0.0/-0.1	100.0 +0.0/-0.0	99.8 +0.1/-0.1	100.0 +0.0/-0.0	99.9 +0.0/-0.1
L			Excluding Normal Battery Depletion	Including Normal Battery Depletion		Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	le	toT	1,298			340		73		86		16	
is (US)	iction Not npromised	ron Cor	1,284 =			330 =		72 =		84 =		4 	
functions (US)	npromised stapy oction Not	τοι	+			+		+		+		+	
Malf	rapy iction	au∃ adT	14			-							
	mal Battery (SU) snoiteld)		264	ced	MOSFET	1,568		332		422		21	
	bətem ZU əvi stnele	ţэА	200	ntial Redu	nomalies i	48,770		24,000		10,600		37,440	
	istered apalants	I SN ნəუ	3,500	2009 Pote	note on A Jy	64,700		30,100		14,500		39,300	
	arket Asse	yek Solo	May-06	age 142–	rformance Technolog	Sep-08		Aug-09		Sep-08		Mar-11	
	14 - 11	Family	Concerto	Advisories: <u>See page 142</u> – 2009 Potential Reduced Device Longevity	See page 151 – Performance note on Anomalies in MOSFET Integrated Circuit Technology	Consulta CRT-D/ CRT-D M4		Concerto II / CRT-D		Maximo II S CRT-D/ CRT-D M4		Protecta XT N CRT-D/ CRT-D M4	
	-	Number	C154DWK, C164AWK, C174AWK (Advisory population)			D224TRK, D234TRK, D204TRM, D214TRM		D274TRK, D294TRK		D264TRM, D284TRK		D314TRG, D354TRG, D314TRM, D354TRM	

continued

Source: Medtronic Device Registration and Returned Product Analysis Data as of March 12, 2013

Device Survival Summary continued

		9 yr						
		8 yr						
		7 yr						
		6 yr						
		5 yr						
(%)		4 yr						
bability		3 yr 2						
Irvival Pro	Years After Implant	2 yr 3	99.9 +0.0/-0.0 at 23 mo	99.1 +0.3/-0.6 at 23 mo	99.9 +0.1/-0.1	99.8 +0.1/-0.2	99.9 +0.1/-0.1	99.8 +0.1/-0.2
Device Survival Probability (%)	Years Afte	1 yr	100.0 +0.0/-0.0	99.9 +0.0/-0.1	100.0 +0.0/-0.0	99.9 +0.0/-0.1	100.0 +0.0/-0.0	99.9 +0.0/-0.1
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	le	toT	7		4		0	
(INS)	bəsimoıqr	רסו	Ш		Ш		Ш	
tions	rapy otion Not	in∃ 94T	- +		+ 4		0 +	
Malfunctions (US)	rapy otion besimorqm	INT	-		0		0	
E	yaftery (SU) snoiteic		-		0		-	
	bətemi SU əvi stnalo	ţЪА	6,240		4,990		6,450	
	SU əvi	US Esti F2A	6,570 6,240		5,400 4,990		6,900 6,450	
	stnslqml b9tsmi VU 9vi	Rel Re <u>c</u> US Esti TSE						
	ease jistered dmfants inated ive US	Rel Re <u>c</u> US Esti TSE	6,570		5,400		6,900	

CRT Cardiac Resynchronization Therapy, continued

Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

					E	stimated	d Longev	/ity		Floctivo	Replacement	
					y**						ERI)***	End of
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	Life (EOL) Battery Voltage
7299	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.8 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7304	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.8 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI

					Es	timated	Longe	vity			mmended	
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage Voltage	nent (RRT)***	End of Service (EOS)
C154DWK, C164AWK, C174AWK	Concerto	DR+LV true	38 cc 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.3	4.3 6.8 8.0	4.8 8.0 9.8	5.0 8.8 10.9	≤ 2.62 V	_	3 month after RRT or > 16-second charge time
D224TRK, D234TRK, D204TRM, D214TRM	Consulta CRT-D CRT-D M4	DR+LV true	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT or > 16-second charge time
D274TRK D294TRK	Concerto II	DR+LV true	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT or > 16-second charge time
D284TRK, D264TRM	Maximo II CRT-D CRT-D M4	DR+LV true	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT or > 16-second charge time
D314TRG, D354TRG, D314TRM, D354TRM	Protecta XT CRT-D CRT-D M4	CRT-D	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT
D334TRG, D364TRG, D334TRM, D364TRM	Protecta CRT-D CRT-D M4	CRT-D	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT

* Volume and mass differ by connector style.

 ** A full charge is a full energy the rapeutic shock or capacitor reformation.

*** The minimum time between ERI and EOL (or RRT and EOS) is 3 months (100% pacing, two charges per month).

‡ Pacing mode is DDD for CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).

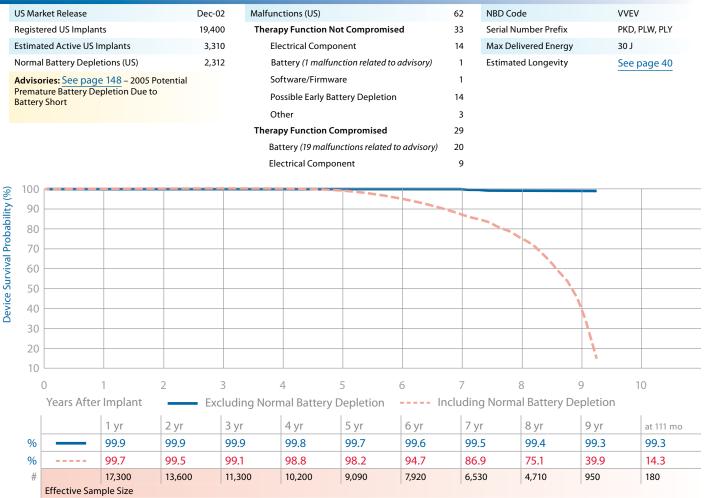
Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

		Estimated Lor	ngevity		
Model Number	Family	Amplitude Setting	500 Lead Ω	1,000 Lead Ω	Elective Replacement Time Indicators
8040	InSync	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	11.9 8.9 6.6	13.7 11.4 9.1	*
8042	InSync III	Low 2.5 V (A, RV, LV) Nominal 3.5 V (A, RV, LV) High 5.0 V (A, RV, LV)	8.3 5.9 4.1	9.9 7.8 6.0	*
C2TR01	Syncra CRT-P	Low 2.5 V (A, RV) Normal 3.5 V (A, RV) High 5.0 V (A, RV)	8.7 6.0 3.3	10.7 8.2 5.1	*
C3TR01 C4TR01	Consulta CRT-P	Low 2.5 V (A, RV) Normal 3.5 V (A, RV) High 5.0 V (A, RV)	8.7 6.0 3.3	10.7 8.2 5.1	*

*Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).

7230Cx, B, E Marquis VR



7231Cx GEM III VR

ants S Implants Sleetions (US) : See page 156 on ICD Battery	1, 3,	900 ,612	Electrical Com Battery Malfur	nction Battery Depletion Compromised Iponent rconnect		22 Max	al Number Prefix	ду	PJL 30 J See page 4
oletions (US) : <u>See page 156</u> - on ICD Battery	3,	,612	Battery Malfur Possible Early Other herapy Function Electrical Com Electrical Inter	nction Battery Depletion Compromised Iponent rconnect	n	1 Estin 4 3 10 8 1			
: See page 156 - on ICD Battery		-	Possible Early Other herapy Function Electrical Com Electrical Inter	Battery Depletion Compromised uponent rconnect	n	4 3 10 8 1	mated Longevity	y 	See page 4
on ICD Battery		Th	Other nerapy Function Electrical Com Electrical Inter	Compromised ponent rconnect	n	3 10 8 1		-	
		Th	Electrical Inter	rconnect	· · · · ·	10 8 1		-	
		Th	Electrical Com Electrical Inter	rconnect		8		-	
			Electrical Inter	rconnect		1		-	
						1		-	
			Battery Malfur			1			
					1				
								<u> </u>	
1	2	3	4	5	6	7	8	9	10
er Implant	—— E	Excluding N	lormal Batter	y Depletion	Ir	ncluding No	rmal Battery	Depletion	
1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	at 106 mo	
99.9	99.9	99.8	99.8	99.8	99.7	99.7	99.7	99.7	
	99.5	99.1	98.7	97.3	89.7	78.5	53.3	10.2	
99.8		12,500	11,000	9,630	7.910	5,900	3,020	350	
6	1 yr	1 yr 2 yr 99.9 99.9 99.8 99.5	1 yr 2 yr 3 yr 99.9 99.9 99.8 99.8 99.5 99.1	1 yr 2 yr 3 yr 4 yr 99.9 99.9 99.8 99.8 99.8 99.5 99.1 98.7	1 yr 2 yr 3 yr 4 yr 5 yr 99.9 99.9 99.8 99.8 99.8 99.8 99.5 99.1 98.7 97.3	1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 99.9 99.9 99.8 99.8 99.8 99.7 99.8 99.5 99.1 98.7 97.3 89.7	1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 99.9 99.9 99.8 99.8 99.8 99.7 99.7 99.8 99.5 99.1 98.7 97.3 89.7 78.5	1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 99.9 99.9 99.8 99.8 99.8 99.7 99.7 99.7 99.8 99.5 99.1 98.7 97.3 89.7 78.5 53.3	1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr at 106 mo 99.9 99.9 99.8 99.8 99.8 99.7 99.7 99.7 99.7 99.8 99.5 99.1 98.7 97.3 89.7 78.5 53.3 10.2

7232B, Cx, E Maximo VR

US Market Release Malfunctions (US) 79 NBD Code VVEV Oct-03 **Registered US Implants** 44,300 **Therapy Function Not Compromised** 63 Serial Number Prefix PRN, PVF, PVG 35 J **Estimated Active US Implants** 18,500 Electrical Component 27 Max Delivered Energy Normal Battery Depletions (US) 2,937 Possible Early Battery Depletion 23 Estimated Longevity See page 40 Other 13 Advisories: See page 148 – 2005 Potential Premature Battery Depletion Due to **Therapy Function Compromised** 16 **Battery Short Electrical Component** 13 Electrical Interconnect 1 Possible Early Battery Depletion 1 Other 1 100 Device Survival Probability (%) 90 -80 70 60 50 0 2 3 4 5 6 8 9 10 7 Years After Implant **Excluding Normal Battery Depletion** ----- Including Normal Battery Depletion 2 yr 3 yr 4 yr 5 yr 8 yr 1 yr 6 yr 7 yr at 99 mo 99.9 99.8 % 100.0 99.9 99.9 99.8 99.8 99.8 99.7 % 99.7 99.1 70.4 53.6 99.9 99.5 97.7 91.5 83.2 40,800 36,700 32,800 28,800 24,300 18,900 11,700 2,090 350 # Effective Sample Size

7274 Marquis DR

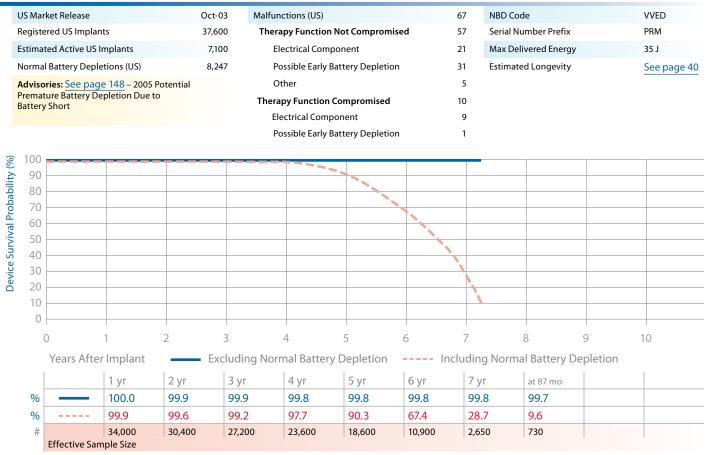
Product Characteristics

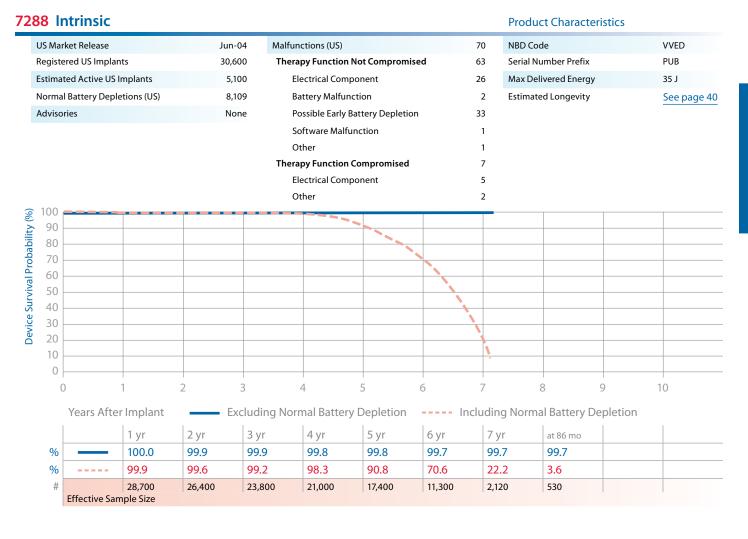
Product Characteristics

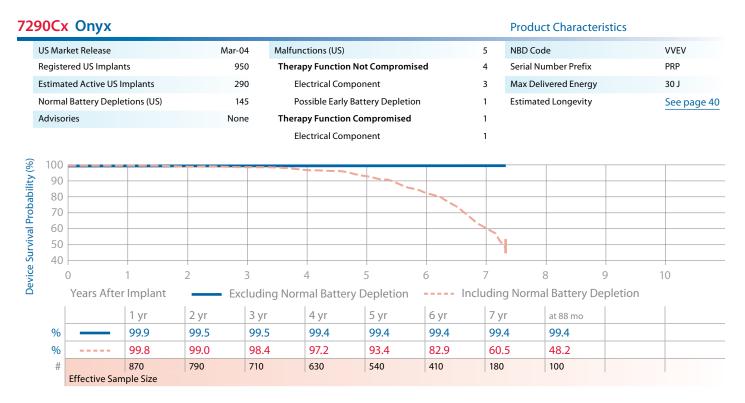
US Ma	arket Release		Mar-0	02 Ma	Ilfunctions (US)			204	NBD Code	VVED
Regist	tered US Implar	nts	48,40	00 TI	herapy Function I	Not Compromis	sed	97	Serial Number Prefix	РКС
Estima	ated Active US I	mplants	2,90	0	Battery (3 malfu	inctions related	to advisory)	6	Max Delivered Energy	30 J
Norm	al Battery Deple	etions (US)	8,84	0	Electrical Comp	onent		30	Estimated Longevity	See page 40
	ories: See pag				Possible Early B	attery Depletio	n	51		
	ature Battery De ry Short	epletion Due to	0		Other			10		
	,			т	herapy Function (Compromised		107		
					Battery (73 malf	functions related	to advisory)	80		
					Electrical Comp	onent		27		
100 90 80 70 60 50 40		_		_						
90										
80										
70										
60										
50										
40										
30 ²⁰										
10										
0										
0	0	1	2	3	4	5	6	7	8 9	10
	Years Afte	r Implant	_		Normal Battery	-	0	ncludir	ig Normal Battery Dep	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7)		
%		99.9	99.9	99.8	99.6	99.4	99.3	99		
%		99.9	99.5	99.6	99.0	99.4	72.6	34		
%0 #		43,000	34,600	26,600	22,500	18,500	12,100	4,1		
Ť	Effective San	1 1	54,000	20,000	22,500	10,500	12,100	+,1	50 500	

Source: Medtronic Device Registration and Returned Product Analysis Data as of March 12, 2013

7278 Maximo DR







D154ATG, D154DRG EnTrust

IS Market Release		Jun	-05	Malfunctio	ons (US)		12		NBD Code			DDED
egistered US Implants		28,2	200	Therapy	Function N	ot Compromise	d 11	1	Serial Nur	nber Prefix		PNR
stimated Active US Impl	lants	9,0	040		rical Compo alfunctions re	onent elated to advisory		8	Max Deliv	ered Energy		35 J
lormal Battery Depletion	ns (US)	4,	524	Elect	rical Interco	nnect		1	Estimated	Longevity		See pag
dvisories: See page 13	<mark>39</mark> – 2012			Softv	ware Malfun	ction		3				
otential Rapid Battery D	epletion					ttery Depletion lated to advisory)		'5				
				Othe	r			4				
				Therapy	Function Co	ompromised	1	4				
					rical Compo			4				
				(2 mc	infunction rel	lated to advisory))					
100	_		_					•				
100 90								•				
90												
90 80												
90 80 70												
90 80 70 60												
90 80 70 60 50												
90 80 70 60 50 40		2	3		1		6	7		3	9	10
90 80 70 60 50 40 30	1 nplant	2 E	0				0	7 uding		Battery D	-	
90 80 70 60 50 40 30 Vears After Im			0	ig Norma			0	7 uding at 83	Normal		-	
90 80 70 60 50 40 30 Vears After In 1	yr	2 2 yr 99.9	xcludin	ig Norma 4	l Battery	Depletion	Inclu	1	Normal		-	
90 80 70 60 50 40 30 0 Years After In % 10	yr 00.0	2 yr	xcludin 3 yr	ig Norma 4 9	I Battery yr	Depletion 5 yr	Inclu	at 83	Normal		-	

28 Medtronic CRDM Product Performance Report www.medtronic.com/CRDMProductPerformance

D154AWG, D164AWG Virtuoso DR

			(N)	(A)				(N)	(A)			
5 Mar	ket Release		May-06	May-06	Malfunc	tions (US)		6	540	1,872	NBD Code		DDED
giste	ered US Implan	ts	72,700	4,100	Therap	y Function No	ot Compromise	d é	514	1,859	Serial Number Prefix		PVV, PUL
tima	ted Active US I	mplants	44,300	300	Ele	ctrical Compo	nent	4	165	1,858	Max Delivered Energy		35 J
orma	l Battery Deple	etions (US)	2,496	107	Ele	ctrical Intercor	nnect		2	0	Estimated Longevity		See page 4
lviso	ries: See pag	e 142 – 2009 F	otential	Possible Early Battery Depletion					117	0			
	ed Device Long			Software Malfunction					1	0			
rfor	mance Note: S	ee page 151		Other					29	1			
Anomalies in MOSFET Integrated Circlennology			Circuit		Therapy Function Compromised				26	13			
					Ele	ctrical Compo	nent		24	13			
					Pos	sible Early Bat	tery Depletion		1	0			
					Otl	her			1	0			
100								D15	4A\W/	5 D164A	WG (Non-advisory populat	ion) 98 5%	
90										3, 810 1, 4			
80													
70 60					$\mathbf{\Lambda}$			1					
50													
40						D154AWG	, D164AWG (Adv	isory pop	ulatio	on) 46.0%			
30					<u>``</u>								
20													
10													
0						*							
	0	1	2	3	4	4	5	6		7	8 9		10
	Years After	Implant		Evoludir	a Norm	nal Battery [Doplation		Inc	ludina	Normal Battery Dep	lation	
		ппріані	1	1		iai battery L			Inc	luaing	Normal battery Dep	netion	1
	Non-Adv	1 yr	2 yr	3 yr		4 yr	5 yr	6 yr		at 74 r	no		
%		100.0	99.9	99.9		99.5	98.6	98.5		98.5			
%		99.9	99.7	99.4		98.0	93.0	74.7		68.0			
#	F((67,700	62,300	56,60	00	45,100	23,700	2,920		590			
	Effective Sam	ipie Size											
%	Advisory	1 vr	2 yr	3 yr		4 yr	at 10 m a						
%	AUVISOLY	1 yr 100.0	99.9	90.5		4 yr 49.5	at 49 mo						
		99.9	99.6	84.1		13.9	6.6						
#		1 2 2 . 2	99.0	04.1		10.9	0.0						
#		3,810	3,490	2,760	h	410	250						

D154VRC EnTrust VR

US Market Release	Jun-05
Registered US Implants	14,500
Estimated Active US Implants	7,200
Normal Battery Depletions (US)	509

Advisories: See page 139 – 2012 Potential Rapid Battery Depletion

Malfunctions (US)
Therapy Function Not Compromised
Battery (2 malfunctions related to advisory)
Electrical Component (28 malfunctions related to advisory)
Possible Early Battery Depletion (3 malfunctions related to advisory)
Other (1 malfunction related to advisory)
Therapy Function Compromised
Electrical Component (8 malfunctions related to advisory)

Product Characteristics

Product Characteristics

94 78

2

42

24

10 16 16

NBD Code	VVEV
Serial Number Prefix	PNT
Max Delivered Energy	35 J
Estimated Longevity	See page 41

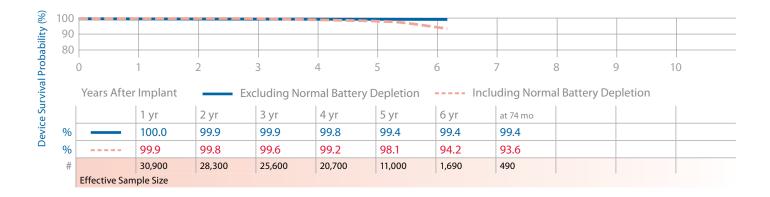
(%)	100		_									
ity	90											
lideo	80											
Prob		0	1	2	3	4	5	6	7	8	9	10
rvival I		Years After	Implant	Exc	luding Norr	nal Battery [Depletion	Inclu	uding Norm	al Battery De	epletion	

Years After Implant Excluding Normal Battery Depletion ----- Including Normal Battery Depletion

e Su			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	at 88 mo	
evic	%		100.0	99.9	99.8	99.7	99.4	99.2	98.9	98.8	
õ	%		99.9	99.6	99.4	98.9	98.0	92.5	85.4	82.1	
	#		13,700	12,400	11,200	9,890	8,430	6,410	1,460	180	
		Effective Sam	ple Size								

D154VWC, D164VWC Virtuoso VR

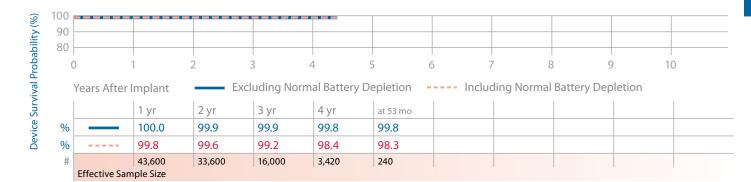
US Market Release	May-06	Malfunctions (US)	138	NBD Code	VVEV
Registered US Implants	33,100	Therapy Function Not Compromised	126	Serial Number Prefix	PUN, PUP
Estimated Active US Implants 21,600		Electrical Component (4 malfunctions related to advisory)	98	Max Delivered Energy	35 J
Normal Battery Depletions (US)	233	Electrical Interconnect	1	Estimated Longevity	See page 41
Adviceries: Soo page 142, 2000 Peter	tial	Possible Early Battery Depletion	12		
Advisories: See page 142–2009 Potential Reduced Device Longevity		Other	15		
		Therapy Function Compromised	12		
Performance Note: See page 151 – And MOSFET Integrated Circuit Technology	omalies in	Electrical Component	12		



D224DRG, D234DRG, D204DRM, D214DRM Secura DR/DR M4

US Market Release	Sep-08	Malfunctions (US)	46	NBD Code	DDED
Registered US Implants	49,500	Therapy Function Not Compromised	37	Serial Number Prefix	PUG
Estimated Active US Implants	41,900	Electrical Component	11	Max Delivered Energy	35 J
Normal Battery Depletions (US)	127	Possible Early Battery Depletion	14	Estimated Longevity	See page 41
Advisories	None	Software Malfunction	9		
		Other	3		
		Therapy Function Compromised	9		
		Electrical Component	7		
		Possible Early Battery Depletion	1		
		Software Malfunction	1		

Product Characteristics



D224VRC, D234VRC, D204VRM, D214VRM Secura VR/VR M4

LIS Marke	et Release		Sep	-08	Malfunctions (US)			21	NBD Code		VVEV	
	ed US Implants			800	Therapy Function	n Not Compromi	ised	17	Serial Number Pi	efix	PUX	
	d Active US Imp			800	Electrical Con	•	Jeu -	3	Max Delivered E		35 J	
	Battery Depleti	•	10,0	27		Battery Depletic	an	5	Estimated Longe		See pag	10.0
Advisorie	, ,	013 (05)	No	one	Software Mal			2	Estimated Longe	vity		Je 4
Auvisorie	63		N.	JIE	Other	runction		2				
					Therapy Function	n Compromised		4				
					Electrical Con	•		3				
					Electrical con	nponent		5				
					Software/Firm	nware		1				
100 90 80 0		1	2	3		nware	6	1	8	9	10	
90 - 80 - 0) 1 Years After I	1	2	3	4 9 4 4 yr 99.8	5		7	g Normal Batte	-		

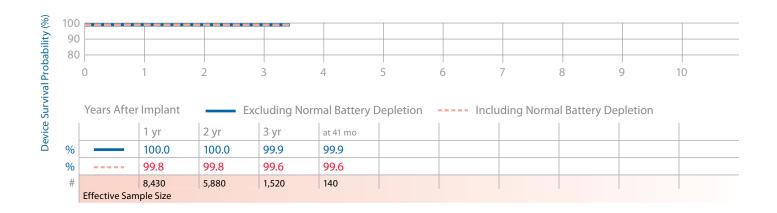
17,200 Effective Sample Size

D274DRG, D294DRG Virtuoso II DR

S Mai	ket Release		Au	ıg-09	Malfunctions (US)			5	NBD Code		VVED
egiste	ered US Implan	its	2	2,200	Therapy Function	n Not Compro	mised	4	Serial Numb	er Prefix	PZT
stima	ted Active US I	mplants	1	9,100	Battery Malfu	nction		1	Max Delivere	ed Energy	35 J
orma	l Battery Deple	etions (US)		21	Other			3	Estimated Lo	ongevity	See page
dviso	ries			None	Therapy Function	n Compromis	ed	1			
					Electrical Con	nponent		1			
100					-						
90											
80											
	0	1	2	3	4	5	6	7	8	9	10
	0	1	2	3	4	5	6	7	8	9	10
	Years After	r Implant		Fxcludir	ng Normal Batte	rv Depletio	n	Includir	ng Normal Ba	attery Depl	etion
		1 yr	2 yr	3 yr							
0/					at 41 mo						
%		100.0	100.0	99.9	99.9						
		99.9	99.8	99.6	99.5						
%		22.2									

D274VRC, D294VRC Virtuoso II VR

274VRC, D294VRC Virtu	oso II VR			Product Characteristics	
US Market Release	Aug-09	Malfunctions (US)	3	NBD Code	VVEV
Registered US Implants	9,100	Therapy Function Not Compromised	3	Serial Number Prefix	PZR
Estimated Active US Implants	8,000	Electrical Component	1	Max Delivered Energy	35 J
Normal Battery Depletions (US)	8	Possible Early Battery Depletion	1	Estimated Longevity	See page 4
Advisories	None	Software Malfunction	1		
		Therapy Function Compromised	0		



D264DRM, D284DRG Maximo II DR/DR M4

US Market Release	Sep-08	Malfunctions (US)	13	NBD Code	VVED
Registered US Implants	19,100	Therapy Function Not Compromised	9	Serial Number Prefix	PZM
Estimated Active US Implants	16,100	Electrical Component	4	Max Delivered Energy	35 J
Normal Battery Depletions (US)	45	Possible Early Battery Depletion	4	Estimated Longevity	See page 4
Advisories	None	Other	1		
		Therapy Function Compromised	4		

Electrical Component

Product Characteristics

4

NBD Code	VVED
Serial Number Prefix	PZM
Max Delivered Energy	35 J
Estimated Longevity	See page 41

(%	100											
<u>ح</u>	90											
ilit	80											
robał	(0	1	2	3	4	5	6	7	8	9 1	10

	Years Afte	rlmplant		Securing No.	ormal Pattor	y Depletion	Inclu	ding Norma	Patton/Do	plation	
	I ears Arte		1			y Depletion	Inclu			pietion	I
		1 yr	2 yr	3 yr	4 yr	at 53 mo					
%)	100.0	100.0	99.9	99.9	99.9					
%		99.9	99.7	99.4	98.5	98.5					
#	ŧ .	16,900	12,700	7,290	1,930	190					
	Effective San	nple Size									

D264VRM, D284VRC Maximo II VR/VR M4

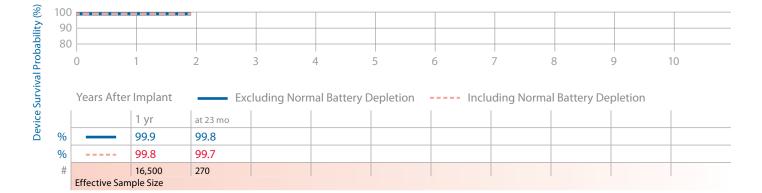
)264V	/RM, D284	WRC Ma	aximo II V	R/VR M4	4				Product Cha	racteristics	
US Ma	arket Release		Sep-0	3 Malfur	nctions (US)			9	NBD Code		VVEV
Regis	tered US Implan	ts	12,30) Thera	apy Function	n Not Compro	mised	6	Serial Number F	Prefix	PZN
Estim	ated Active US Ir	mplants	10,50) E	lectrical Com	nponent		3	Max Delivered E	inergy	35 J
Norm	al Battery Deple	tions (US)	2	5 P	ossible Early	Battery Deple	etion	1	Estimated Long	evity	See page 41
Advis	ories		Non	e So	oftware Malf	functionn		2			
				Thera	apy Functior	o Compromis	ed	3			
				E	lectrical Com	nponent		2			
				S	oftware Malf	function		1			
Device Survival Probability (%) 8 6 01	0 0 Years After	1	2 2 Exc 2 yr 99.9	3	4 mal Batter 4 yr 99.9	5 7y Depletio at 52 mo 99.9	1	7 Includin	g Normal Batt	9 ery Depletion	n
%		99.8	99.6	99.3	99.1	99.1					
#	Effective Sam	11,200 ple Size	8,350	4,650	1,090	260					

D314DRG, D354DRG, D314DRM, D354DRM Protecta XT DR/DR M4

Product Characteristics

Product Characteristics

US Market Release	Mar-11	Malfunctions (US)	15	NBD Code	DDED
Registered US Implants	34,200	Therapy Function Not Compromised	13	Serial Number Prefix	PSK
Estimated Active US Implants	32,900	Electrical Component	6	Max Delivered Energy	35 J
Normal Battery Depletions (US)	9	Other	7	Estimated Longevity	See page 4
Advisorie	None	Therapy Function Compromised	2		
		Electrical Component	2		



D314VRG, D354VRG, D314VRM, D354VRM Protecta XT VR/VR M4

US Market Release 10 NBD Code VVEV Mar-11 Malfunctions (US) **Registered US Implants** 14,200 **Therapy Function Not Compromised** 9 Serial Number Prefix PSA Estimated Active US Implants 13,700 **Electrical Component** 1 Max Delivered Energy 35 J Normal Battery Depletions (US) 5 Other 8 Estimated Longevity See page 41 Advisories **Therapy Function Compromised** None 1 **Electrical Component** 1 Device Survival Probability (%) 100 90 80 3 2 4 5 6 7 8 9 10 1 Years After Implant **Excluding Normal Battery Depletion** ----- Including Normal Battery Depletion 1 yr at 23 mo 99.9 99.8 % % 99.8 99.5 # 130 6,900 **Effective Sample Size**

D334DRG, D364DRG, D334DRM, D364DRM Protecta DR/DR M4

US Market Release Mar-11 Malfunctions (US) 7 NBD Code DDED **Registered US Implants** 9,400 **Therapy Function Not Compromised** 5 Serial Number Prefix PSP Estimated Active US Implants 3 Max Delivered Energy 35 J 9,000 **Electrical Component** Normal Battery Depletions (US) Other 2 2 Estimated Longevity See page 41 Advisories None **Therapy Function Compromised** 2 **Electrical Component** 2 100 Device Survival Probability (%) 90 80 2 3 5 7 8 0 1 4 6 9 10 Years After Implant **Excluding Normal Battery Depletion** ----- Including Normal Battery Depletion 1 yr at 23 mo % 99.9 99.9 % 99.8 99.7 # 270 16,500 **Effective Sample Size**

D334VRG, D364VRG, D334VRM, D364VRM Protecta VR/VR M4

NBD Code **US Market Release** Mar-11 Malfunctions (US) 1 VVEV **Registered US Implants** PSX 5,500 **Therapy Function Not Compromised** Serial Number Prefix 0 **Estimated Active US Implants** 5,300 **Therapy Function Compromised** Max Delivered Energy 35 J 1 Normal Battery Depletions (US) **Electrical Component** Estimated Longevity 1 1 See page 41 Advisories None Device Survival Probability (%) 100 90 80 2 3 4 5 6 7 8 9 10 0 1 Years After Implant Excluding Normal Battery Depletion ----- Including Normal Battery Depletion 1 yr at 23 mo 99.9 99.8 % % 99.8 99.5 # 6,900 130 **Effective Sample Size**

Product Characteristics

Device Survival Summary (95% Confidence Interval)

The following table shows ICD device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included.

· .	ntable Card															
		10 yr	99.3 +0.2/-0.3 at 111 mo	14.3 +2.3/-2.1 at 111 mo	99.7 +0.1/-0.1 at 106 mo	10.2 +1.1/-1.1 at 106 mo	99.7 +0.1/-0.1 at 99 mo	53.6 +2.7/-2.7 at 99 mo								
		8 yr	99.4 +0.1/-0.2	75.1 +1.0/-1.0	99.7 +0.1/-0.1	53.3 +1.2/-1.2	99.8 +0.1/-0.1	70.4 +1.0/-1.0	99.1 +0.1/-0.1 at 90 mo	0.8 +0.3/-0.2 at 90 mo	99.7 +0.1/-0.1 at 87 mo	9.6 +0.8/-0.8 at 87 mo	99.7 +0.1/-0.1 at 86 mo	3.6 +0.6/-0.5 at 86 mo	99.4 +0.4/-0.9 at 88 mo	48.2 +5.4/-5.6 at 88 mo
		7 yr	99.5 +0.1/-0.2	86.9 +0.7/-0.7	99.7 +0.1/-0.1	78.5 +0.9/-0.9	99.8 +0.0/-0.1	83.2 +0.5/-0.5	99.2 +0.1/-0.1	34.2 +0.8/-0.8	99.8 +0.1/-0.1	28.7 +0.8/-0.8	99.7 +0.1/-0.1	22.2 +0.8/-0.8	99.4 +0.4/-0.9	60.5 +4.5/-4.9
		6 yr	99.6 +0.1/-0.1	94.7 +0.4/-0.5	99.7 +0.1/-0.1	89.7 +0.6/-0.6	99.8 +0.0/-0.1	91.5 +0.3/-0.4	99.3 +0.1/-0.1	72.6 +0.6/-0.7	99.8 +0.1/-0.1	67.4 +0.7/-0.7	99.7 +0.1/-0.1	70.6 +0.7/-0.7	99.4 +0.4/-0.9	82.9 +2.9/-3.4
		5 yr	99.7 +0.1/-0.1	98.2 +0.2/-0.3	99.8 +0.1/-0.1	97.3 +0.3/-0.3	99.8 +0.0/-0.0	97.7 +0.2/-0.2	99.4 +0.1/-0.1	92.1 +0.3/-0.4	99.8 +0.0/-0.1	90.3 +0.4/-0.4	99.8 +0.1/-0.1	90.8 +0.4/-0.4	99.4 +0.4/-0.9	93.4 +1.7/-2.2
(%)		4 yr	99.8 +0.1/-0.1	98.8 +0.2/-0.2	99.8 +0.1/-0.1	98.7 +0.2/-0.2	9.99 +0.0/-0.0	99.1 +0.1/-0.1	99.6 +0.1/-0.1	97.3 +0.2/-0.2	99.8 +0.0/-0.1	97.7 +0.2/-0.2	99.8 +0.0/-0.1	98.3 +0.2/-0.2	99.4 +0.4/-0.9	97.2 +1.0/-1.5
Device Survival Probability (%)	nt	3 yr	99.9 +0.0/-0.1	99.1 +0.1/-0.2	99.8 +0.1/-0.1	99.1 +0.1/-0.2	9.99 +0.0/-0.0	99.5 +0.1/-0.1	99.8 +0.0/-0.1	98.6 +0.1/-0.1	9.99 +0.0/-0.0	99.2 +0.1/-0.1	9.9 +0.0/-0.0	99.2 +0.1/-0.1	99.5 +0.3/-0.8	98.4 +0.7/-1.1
Survival P	Years After Implant	2 yr	99.9 +0.0/-0.1	99.5 +0.1/-0.1	99.9 +0.0/-0.1	99.5 +0.1/-0.1	9.99 +0.0/-0.0	99.7 +0.0/-0.1	99.9 +0.0/-0.0	99.5 +0.1/-0.1	9.9 +0.0/-0.0	99.6 +0.1/-0.1	99.9 +0.0/-0.0	99.6 +0.1/-0.1	99.5 +0.3/-0.8	99.0 +0.5/-0.9
Device 5	Years Af	1 yr	99.9 +0.0/-0.0	99.7 +0.1/-0.1	99.9 +0.0/-0.0	99.8 +0.1/-0.1	100.0 +0.0/-0.0	99.9 +0.0/-0.0	9.99 +0.0/-0.0+	99.8 +0.0/-0.1	100.0 +0.0/-0.0	9.99 0.0-/0.0+	100.0 +0.0/-0.0	9.99 +0.0/-0.0	99.9 +0.1/-0.8	99.8 +0.1/-0.6
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	le	tot	62	(20) set)	40		79	(0) et)	204	(76) et)	67	(0) et)	70		ъ	
ctions (US)	rtapy oction Not besimorqn	noJ	33 =	+ (1) (20 y-related subset)	30 =		63 =	+ (0) = ((-related subset)	97 =	+ (3) = (7 -related subset)	57 =	+ (0) = ((-related subset)	63 =		4	
	irapy npromised		κ +	+ () ry-rela	۳ +		+		6 +	+ (i	دم +	+ (I -relat	+		+	
Malfun	rapy iction			0				£.		~						
		əqT	29	(19) (advisor	10		16	(<mark>0)</mark> (advisory	107	(73) (advisory	10	(<mark>0)</mark> (advisory	2		-	
	۲۹۹۴۶۹۲۹ اهس (SU) snoiteld	Dep	2,312 29		3,612 10		2,937 16			(73) (advisory	8,247 10	(<mark>0)</mark> (advisory	8,109 7		145 1	
	(SU) snoiteld	Acti Nor Dep				D Battery			107	(73) (advisory		(<mark>0)</mark> (advisory				
	ive US Iants Mail Battery Dietions (US)	USU Esti Acti Imp Imp Imp	2,312		3,612	e note on ICD Battery	2,937	i Potential Premature Battery	8,840 107	(73) (advisory	8,247	(<mark>0)</mark> (advisory	8,109		145	
	mplants ive US inated mated matery bletions (US)	Rele USI Inp Mor Dep	3,310 2,312		1,900 3,612	- Performance note on ICD Battery avior	18,500 2,937	i Potential Premature Battery	2,900 8,840 107	(73) (advisory	7,100 8,247	(<mark>0)</mark> (advisory	5,100 8,109		290 145	
	esese jistered mplants ive US ilants ilants ilants ilatery ilatery	Rele USI Inp Mor Dep	19,400 3,310 2,312	Advisories: <u>See page 148</u> – 2005 Potential Premature Battery (19) Depletion <u>Due to Battery</u> Short (advis	17,400 1,900 3,612	See page 156 – Performance note on ICD Battery Discharge Behavior	44,300 18,500 2,937	Advisories: <u>See page 148</u> – 2005 Potential Premature Battery (0) Depletion Due to Battery Short (advisor)	48,400 2,900 8,840 107	Advisories: <u>See page 148</u> – 2005 Potential Premature Battery (73) Depletion Due to Battery Short (advisory	37,600 7,100 8,247		30,600 5,100 8,109		950 290 145	

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Implantable Cardioverter Defibrillators, continued

Device S	Device Survival Summary continued	ummar	y conti	inued	E	Malfunctions		Device 5	Device Survival Probability (%)	robability	(%)					
		təhrkət 9269	bərətsi stnslqm	bətem ZU əvi Stnsl	mal Battery sletions	rtepy iction irapy iction Not basimorqu basimorqu		Years Af	Years After Implant	ıt						
Model Number	Family	eles US I	I SN ნəუ	its∃ itoA qml	Nor Dep	an∃ 9dT		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr
D154ATG, D154DRG	EnTrust	Jun-05	28,200	9,040	4,524	14 + 111 = 125	Excluding Normal Battery Depletion	100.0 +0.0/-0.0	9.99 +0.0/-0.0+	99.8 +0.0/-0.1	99.7 +0.1/-0.1	99.4 +0.1/-0.1	99.4 +0.1/-0.1	99.3 +0.1/-0.1 at 83 mo		
	Advisories: <u>See page 139</u> – 2012 Potential Rapid Battery Depletion	ee page 139	- 2012 Pot	ential Rapid E	Battery	(2) + (10) = (12)(advisory-related subset)	Including Normal Battery Depletion	99.8 +0.0/-0.1	99.6 +0.1/-0.1	99.1 +0.1/-0.1	97.9 +0.2/-0.2	90.7 +0.4/-0.4	70.2 +0.7/-0.7	34.1 +1.4/-1.4 at 83 mo		
D154AWG D164AWG (Non-advisory population)	Virtuoso DR	May-06	72,700	44,300	2,496	26 + 614 = 640	Excluding Normal Battery Depletion	100.0 +0.0/-0.0	99.9 +0.0/-0.0	99.9 +0.0/-0.0	99.5 +0.1/-0.1	98.6 +0.1/-0.1	98.5 +0.1/-0.1	98.5 +0.1/-0.2 at 74 mo		
							Including Normal Battery Depletion	99.9 +0.0/-0.0	9.7 +0.0/-0.0	99.4 +0.1/-0.1	98.0 +0.1/-0.1	93.0 +0.3/-0.3	74.7 +0.9/-0.9	68.0 +1.6/-1.7 at 74 mo		
D154AWG D164AWG (Advisory population)	Virtuoso DR	May-06	4,100	300	107	1 3 + 1,859 = 1,872	Excluding Normal Battery Depletion	100.0 +0.0/-0.0	99.9 +0.1/-0.2	90.5 +1.0/-1.1	49.5 +1.9/-1.9	46.0 +1.9/-1.9 at 49 mo				
	Advisories: <u>See page 142</u> – 2009 Potential Reduced Device Longevity	ee page 142	– 2009 Pot	ential Reduce	ed Device		Including Normal Battery Depletion	99.9 +0.1/-0.1	99.6 +0.2/-0.3	84.1 +1.2/-1.3	13.9 +1.5/-1.4	6.6 +1.2/-1.0 at 49 mo				
	See page 151 – Performance note on Anomalies in MOSFET Integrated Circuit Technology	 Performanc Suit Technolo 	e note on J gy	Anomalies in	MOSFET											
D154VRC	EnTrust VR	Jun-05	14,500	7,200	509	16 + 78 = 94	Excluding Normal Battery Depletion	100.0 +0.0/-0.0	99.9 +0.0/-0.1	99.8 +0.1/-0.1	99.7 +0.1/-0.1	99.4 +0.1/-0.2	99.2 +0.2/-0.2	98.9 +0.2/-0.3	98.8 +0.3/-0.3 at 88 mo	
	Advisories: <u>See page 139</u> – 2012 Potential Rapid Battery Depletion	ee page 139	- 2012 Pot	ential Rapid E	Battery	(8) + (34) = (42)(advisory-related subset)	Including Normal Battery Depletion	99.9 +0.0/-0.1	99.6 +0.1/-0.1	99.4 +0.1/-0.2	98.9 +0.2/-0.2	98.0 +0.3/-0.3	92.5 +0.6/-0.6	85.4 +0.9/-1.0	82.1 +2.0/-2.2 at 88 mo	
D154VWC D164VWC (Non-advisory population)	Virtuoso VR	May-06	33,100	21,600	233	12 + 126 = 138	Excluding Normal Battery Depletion	100.0 +0.0/-0.0	99.9 +0.0/-0.0	9.99 	99.8 +0.1/-0.1	99.4 +0.1/-0.1	99.4 +0.1/-0.1	99.4 +0.1/-0.1 at 74 mo		
	Advisories: <u>See page 142</u> – 2009 Potential Reduced Device Longevity	ee page 142	– 2009 Pot	ential Reduce	ed Device	(0) + (4) = (4) (advisory-related subset)	Including Normal Battery Depletion	9.99 +0.0/-0.0	99.8 +0.0/-0.1	99.6 +0.1/-0.1	99.2 +0.1/-0.1	98.1 +0.2/-0.2	94.2 +0.6/-0.7	93.6 +0.8/-0.9 at 74 mo		
	<u>See page 151</u> – Performance note on Anomalies in MOSFET Integrated Circuit Technology	 Performanc suit Technolo 	ce note on <i>i</i> gy	Anomalies in	MOSFET											

continued

continued

	-	8 yr								
		7 yr								
		6 yr								
		5 yr								
(%)		4 yr								
bability	- 	3 yr								
Device Survival Probability (%)	Years After Implant	2 yr	99.9 +0.0/-0.1 at 23 mo	99.7 +0.1/-0.1 at 23 mo	99.8 +0.1/-0.4 at 23 mo	99.5 +0.2/-0.4 at 23 mo	99.9 +0.0/-0.1 at 23 mo	99.7 +0.1/-0.1 at 23 mo	99.8 +0.1/-0.4 at 23 mo	99.5 +0.2/-0.4 at 23 mo
Device St	Years Aft	1 yr	9.09 +0.0/-0.0	99.8 +0.0/-0.1	99.9 +0.0/-0.1	99.8 +0.1/-0.1	9.99 +0.0/-0.0	99.8 +0.0/-0.1	99.9 +0.0/-0.1	99.8 +0.1/-0.1
			Excluding Normal Battery Depletion	Including Normal Battery Depletion						
	le:	юТ	15		10		~			
			<i>(</i>		-				-	
ions	erapy toN nottor b92imorqm	Col	13 =		6		ی ۲		0	
Malfunctions	erapy action erapy action Not mpromised	IO) INJ IVJ	II		Ш		П		П	
Malfunctions	erapy Prapy Action Not		+ 13		11 60 +		+		 0 +	
Malfunctions	erapy action promised promised promised	Iml Pd De De De De De De De De De De De De De	2 + 13 =		H + -		2 + 2		 0 +	
Malfunctions	olants rmal Battery pletions actory mpromised promised	US Est Mo De Fui Co Co Co Co Co Co Co Co Co	9 2 + 13 =		5 + 9 =		2 + 5 =		- - + - -	
Malfunctions	Implants inated ive US plants pletions pletions promised promised	Rei Rei Action No No No No Co No Co No Co No Co Co Co Co Co Co Co Co Co Co Co Co Co	32,900 9 2 + 13 =		13,700 5 1 + 9 =		9,000 2 + 5 =		5,300 1 1 + 0 =	
Malfunctions	easee jistered implants rive US rive VS rive V	Rei Rei Action No No No No Co No Co No Co No Co Co Co Co Co Co Co Co Co Co Co Co Co	34,200 32,900 9 2 + 13 =		14,200 13,700 5 1 + 9 =		9,400 9,000 2 2 + 5 =		5,500 5,300 1 1 + 0 =	

Source: Medtronic Device Registration and Returned Product Analysis Data as of March 12, 2013

Device Survival Summary continued

continued

Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

					Es	stimated	Longev	ity		Elective	Replacement	
					×**						RI)***	End of
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	Life (EOL) Battery Voltage
7230	Marquis VR	B, Cx, E	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.9 7.3 8.5	5.2 8.0 9.3	5.4 8.5 10.0	5.5 8.7 10.4	≤ 2.62 V	> 16-second charge time	3 months after ERI
7231Cx	GEM III VR	Cx	39 cc 77 g	30 J	Monthly Quarterly Semiannual	4.3 6.0 6.6	4.7 6.8 7.5	5.0 7.4 8.5	5.2 7.8 8.9	≤ 2.55 V	_	\leq 2.40 V
7232 Cx, E	Maximo VR	B, Cx, E	39 cc 76 g	35 J	Monthly Quarterly Semiannual	4.4 7.0 8.2	4.7 7.5 9.0	4.8 8.0 9.7	4.9 8.3 10.0	≤ 2.62 V	> 16-second charge time	3 months after ERI
7274	Marquis DR	DR+LV	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.0 5.6 6.2	4.4 6.4 7.2	4.8 7.1 8.1	4.9 7.5 8.6	≤ 2.62 V	> 16-second charge time	3 months after ERI
7278	Maximo DR	DR	39 cc 77 g	35 J	Monthly Quarterly Semiannual	3.7 5.3 6.0	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7288	Intrinsic	DR	38 cc 76 g	35 J	Monthly Quarterly Semiannual	3.7 5.3 6.0	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7290Cx	Onyx	Cx	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.8 5.0 5.4	4.1 5.6 6.1	4.3 6.2 6.7	4.5 6.4 7.0	≤ 2.55 V		≤ 2.40 V

* Volume and mass differ by connector style.

 ** A full charge is a full energy the rapeutic shock or capacitor reformation.

 **** The minimum time between ERI and EOL is 3 months (100% pacing, two charges per month).

‡ Pacing mode is VVI for single chamber models and DDD for dual chamber and CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).

§ For Model 7271 and 7227 devices, if charge time exceeds 30 seconds, the device is at EOL. Immediate replacement is recommended. If three consecutive charge cycles exceed 30 seconds, the "charge circuit inactive" indicator is tripped and all therapies except emergency VVI pacing are disabled.

Referenc	e Chart cor	ntinued				Estimate	d Longe	vity		Recomr Replac (RRT	ement	
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Service (EOS)
D154ATG, D154DRG	EnTrust	DR	35 cc 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.1	4.2 6.1 7.0	4.4 6.8 7.9	4.6 7.0 8.3	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154AWG, D164AWG	Virtuoso DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.1 6.3 7.3	4.5 7.3 8.7	4.8 8.3 10.1	5.0 8.8 11.0	≤ 2.62 V	_	3 months after RRT or > 16-second charge time
D154VRC	EnTrust VR	Сх	35 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 7.5 9.0	5.0 8.3 10.0	5.2 8.8 10.7	5.3 9.0 11.0	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154VWC, D164VWC	Virtuoso	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 8.1 10.0	5.1 9.0 11.2	5.3 9.6 12.3	5.4 10.0 12.9	≤ 2.62 V	_	3 months after RRT or > 16-second charge time
D224DRG, D234DRG, D204DRM, D214DRM	Secura DR/ DR M4	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.1 5.7	4.1 6.1 7.0	4.5 7.0 8.3	4.7 7.5 9.0	≤ 2.63 V	_	3 months after RRT or > 16-second charge time
D224VRC, D234VRC, D204VRM, D214VRM	Secura VR/ VR M4	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.7 7.8	4.7 7.7 8.9	4.9 8.1 9.8	5.0 8.4 10.3	≤ 2.63 V	_	3 months after RRT or > 19-second charge time
D274DRG, D294DRG	Virtuoso II DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.1 5.7	4.1 6.0 7.0	4.5 7.0 8.3	4.7 7.5 9.0	≤ 2.63 V	_	3 months after RRT or > 16-second charge time
D274VRC, D294VRC	Virtuoso II VR	Cx	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.7 7.8	4.7 7.5 8.9	4.9 8.1 9.8,	5.0 8.4 10.3	≤ 2.63 V	_	3 months after RRT or > 19-second charge time
D284DRG, D264DRM	Maximo II DR/DR M4	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.1 5.7	4.1 6.1 7.0	4.5 7.0 8.2	4.6 7.5 9.0	≤ 2.63 V	_	3 months after RRT or > 16-second charge time
D284VRC, D264VRM	Maximo II VR/ VR M4	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.6 7.7	4.6 7.4 8.8	4.9 8.1 9.7	5.0 8.4 10.2	≤ 2.63 V	—	3 months after RRT or > 19-second charge time
D314DRG, D354DRG, D314DRM, D354DRM	Protecta XT DR/DR M4	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.1 5.7	4.1 6.0 7.0	4.5 7.0 8.3	4.7 7.5 9.0	≤ 2.63 V	_	3 months after RRT
D314VRG, D354VRG, D314VRM, D354VRM	Protecta XT VR/VR M4	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.7 7.8	4.7 7.5 8.9	4.9 8.1 9.8	5.0 8.4 10.3	≤ 2.63 V	_	3 months after RRT
D334DRG, D364DRG, D334DRM, D364DRM	Protecta DR/ DR M4	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.1 5.7	4.1 6.0 7.0	4.5 7.0 8.3	4.7 7.5 9.0	≤ 2.63 V	-	3 months after RRT
D334VRG, D364VRG, D334VRM, D364VRM	Protecta VR/ VR M4	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.7 7.8	4.7 7.5 8.9	4.9 8.1 9.8	5.0 8.4 10.3	≤ 2.63 V	_	3 months after RRT

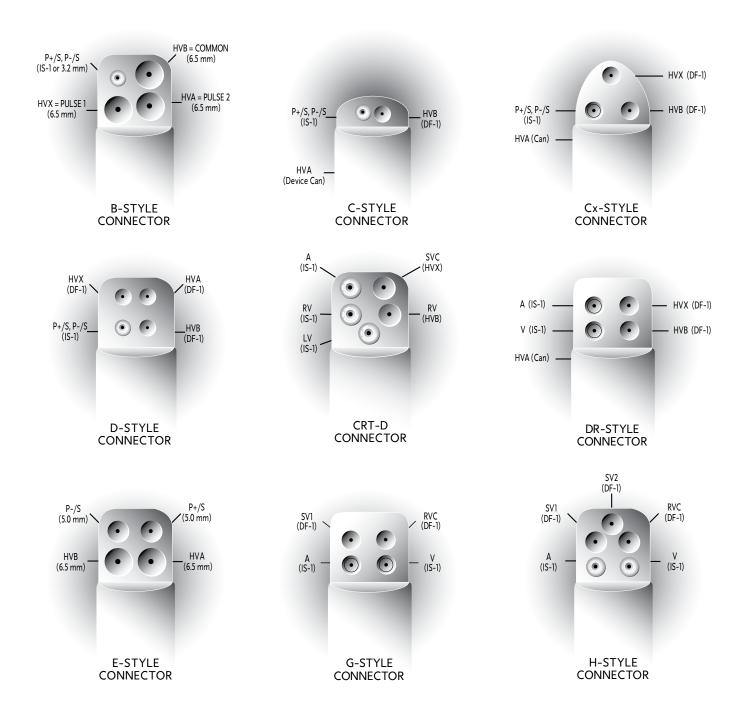
* Volume and mass differ by connector style.

** A full charge is a full energy therapeutic shock or capacitor reformation.

*** The minimum time between RRT and EOS is 3 months (100% pacing, two charges per month).

‡ Pacing mode is VVI for single chamber models and DDD for dual chamber models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel.

ICD Connector Styles



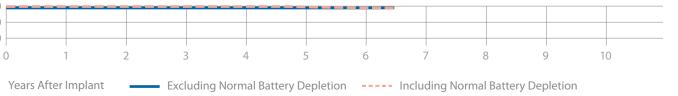
Adapta DR ADDR01, ADDR03, ADDR06, ADD01

-				
US Market Release	Jul-06	Malfunctions (US)	64	
Registered US Implants	342,700	Therapy Function Not Compromised	42	
Estimated Active US Implants	281,900	Electrical Component	36	
Normal Battery Depletions (US)	375	Electrical Interconnect	1	
Performance Note: See page 149 –		Other	5	
Performance note on Dual Chamber Pa with Measurement Lock-up ERI	cemakers	Therapy Function Compromised	22	
		Electrical Component	18	
		Electrical Interconnect	2	
		Other	2	
ā 100 — — — — — — — — — — — — —				

Product Characteristics

Product Characteristics

NBG Code DDDR, DDD Serial Number Prefix PWB, PWD, PWC, PWF, NWB, NWC, NWD, NWF
PWC, PWF, NWB, NWC, NWD, NWF
Estimated Longevity See page 74



100											
90											
80											
(0	1	2	3	4	5	6	7	8	9	10
	Years After	Implant 1 yr	I.	1	mal Battery 4 yr		1	luding Norn	nal Batter	y Depletion	n
%	Years After		Ex 2 yr 100.0	cluding Nor 3 yr 100.0	mal Battery 4 yr 100.0	Depletion 5 yr 100.0	Inc 6 yr 100.0	J	nal Batter	y Depletion	n
	Years After	1 yr	2 yr	3 yr	4 yr	5 yr	бyr	at 77 mo	nal Batter	y Depletion	n
%		1 yr 100.0	2 yr 100.0	3 yr 100.0	4 yr 100.0	5 yr 100.0	6 yr 100.0	at 77 mo	nal Batter	y Depletion	n

Adapta DR ADDRL1

JS Market Release	Jul-06	Malfunctions (US)				NBG Code		DDDR
Registered US Implants	73,900	Therapy Funct	tion Not Comp	romised	9	Serial Number P	refix	PWE, NWE
Estimated Active US Implants	66,700	Electrical C	Component		5	Estimated Long	evity	See page
Normal Battery Depletions (US)	23	Electrical l	nterconnect		1			
Performance Note: <u>See page 149</u> –		Other			3			
Performance note on Dual Chamber Pace Measurement Lock-up ERI	makers with	Therapy Funct	tion Comprom	sed	3			
		Electrical In	nterconnect		1			
		Other			2			
100								
90								
80	3	4	5	6	7	8	9	10

ice S			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 76 mo		
Dev	%		100.0	100.0	100.0	100.0	100.0	100.0	100.0		
	%		100.0	100.0	99.9	99.8	99.6	99.4	99.4		
	#		56,800	39,000	24,000	12,400	4,990	840	170		
		Effective Sam	ple Size								

Source: Medtronic Device Registration and Returned Product Analysis Data as of March 12, 2013

Adapta DR ADDRS1

US Market Release	Jul-06
Registered US Implants	33,300
Estimated Active US Implants	24,900
Normal Battery Depletions (US)	274
Performance Note: <u>See page 149</u> - Performance note on Dual Chambe Measurement Lock-up ERI	

Malfunctions (US)							
Therapy Function Not Compromised							
Electrical Component							
Possible Early Battery Depletion							
Other							
Therapy Function Compromised							
Electrical Component							
Other							

Product Characteristics

NBG Code	DDDR
Serial Number Prefix	PWA, NWA
Estimated Longevity	See page 74

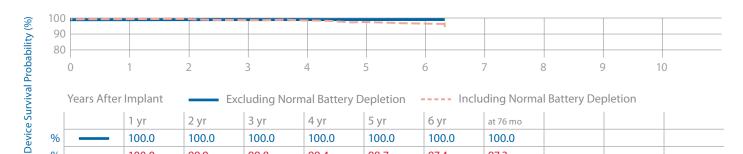
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90)										
80)						· • •				
	0	1	2	3	1	5	6	7	8	0	10
	0	I	2	5	Т	5	0	7	0	2	10
	N/ A.C.		_	1 I. M				. I			
	Years After	Implant	EX	cluding Nor	mal Battery	Depletion	Inc	luding Nor	mal Battery	Depletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 74 mo			
%		100.0	100.0	100.0	100.0	100.0	99.9	99.9			
		1		1	-						

	Years After	Implant	Exc	luding Norm	nal Battery D	epletion	Inclu	ding Norma	Battery Dep	oletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 74 mo			
%		100.0	100.0	100.0	100.0	100.0	99.9	99.9			
%		99.9	99.8	99.6	98.8	95.6	83.6	81.5			
#		26,500	19,700	13,400	8,160	3,790	530	160			

26,500 Effective Sample Size

Adapta SR ADSR01, ADSR03, ADSR06

•					
US Market Release	Jul-06	Malfunctions (US)	8	NBG Code	SSIR
Registered US Implants	64,600	Therapy Function Not Compromised	4	Serial Number Prefix	NWN, NWM, NWP,
Estimated Active US Implants	45,500	Electrical Component	2		PWP, PWM, PWN
Normal Battery Depletions (US)	151	Electrical Interconnect	1	Estimated Longevity	See page 74
		Possible Early Battery Depletion	1		
Advisories	None	Therapy Function Compromised	4		
		Electrical Component	3		
		Electrical Interconnect	1		



% 100.0 99.9 99.8 99.4 98.7 97.4 97.3 # 52,800 27,000 390 38,800 17,000 8,560 1,960 **Effective Sample Size**

US Marl	ket Release		Jul-(06 Malfu	nctions (US)			0	NBG Code		VDD
legiste	ered US Implant	s	1,00	00 Ther	apy Function	Not Compromi	sed	0	Serial Number	Prefix	PWG, NWG
stimat	ted Active US In	nplants	76	50 Ther	apy Function	Compromised		0	Estimated Long	gevity	See page
Normal	l Battery Deplet	tions (US)		1							
Perform	mance Note: <u>See</u> mance note on E akers with Meas	Dual Chamber	up ERI								
100 90 80											
90 80	0	1	2	3	4	5	6	7	8	9	10
90 80	0 Years After	1 yr	2 Ex 2 yr	cluding Nor 3 yr	rmal Battery	/ Depletion	Ind	7 7 cludin	g Normal Bat	-	
90 80	-		2 Ex	cluding Nor	rmal Battery	/ Depletion	Inc	7 7 cludin	Ū	-	

Effective Sample Size

Advisa DR / DR MRI+C82 A2DR01, A3DR01, A4DR01, A5DR01 Ensura MRI EN1DR01 Product Characteristics

US Mar	rket Release		Apr-11	Malfunc	tions (US)			0	NBG Code		OAE - DDDR OOE - DDDR
Registe	ered US Implant	s	1,120	Therap	y Function No	ot Compromis	ed	0	Serial Number Pre	fix	PZK, PZJ, PZL, PZW
Estima	ted Active US Im	plants	1,100	Therap	y Function Co	ompromised		0	Estimated Longev	ity	See page 74, 75
Norma	l Battery Deplet	ions (US)	0								
Perform	mance Note: <u>See</u> mance note on D akers with Meas	ual Chamber	up ERI								
(%)											
001 00											
90 90											
Pro	0 1	2	2 3	4	Ľ	5 6	5	 7	8	9 10	
Device Survival Probability (%) 08 00 00 001	Years After	Implant	Exclu	uding Norm	nal Battery I	Depletion	Inc	luding l	Normal Battery	Depletion	
evic		1 yr	2 yr	at 35 mo							
□ %		100.0	100.0	100.0							
%		100.0	100.0	100.0							
#		7,230	3,090	130							
	Effective Sam	ple Size									

Mar-03

11,100

900

2,808

AT500 AT501, 7253 US Market Release

Registered US Implants

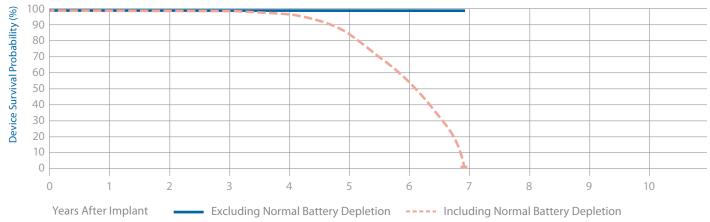
Estimated Active US Implants

Normal Battery Depletions (US)

Performance Note: See page 154 -Performance note on AT500 Pacing System Follow-Up Protocol

Product Characteristics

Malfunctions (US)	9	NBG Code	DDDRP
Therapy Function Not Compromised	4	Serial Number Prefix	IJF
Electrical Component	1	Estimated Longevity	See page 74
Possible Early Battery Depletion	3		
Therapy Function Compromised	5		
Electrical Component	3		
Electrical Interconnect	1		
Possible Early Battery Depletion	1		



		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	at 83 mo		
%		100.0	100.0	100.0	99.9	99.9	99.9	99.9		
%		99.9	99.8	99.4	97.5	85.5	55.2	1.4		
#		10,700	9,960	9,150	8,290	6,280	2,880	180		
	Fff C	1 61								

Malfunctions (US)

Therapy Function Not Compromised

Electrical Component

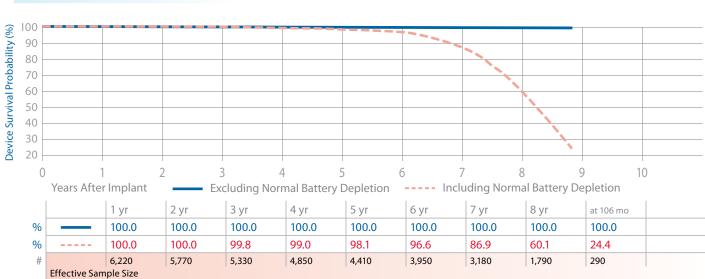
Therapy Function Compromised

Effective Sample Size

EnPulse DR E1DR01, E1DR03, E1DR06

US Market Release	Dec-03
Registered US Implants	6,800
Estimated Active US Implants	1,600
Normal Battery Depletions (US)	1,095
Performance Note: <u>See page 149</u> – Performance note on Dual Chamber	1

Pacemakers with Measurement Lock-up ERI



Product Characteristics

NBG Code

Serial Number Prefix

Estimated Longevity

1

1

1

0

DDDR

PRA, PRB, PRE

See page 74

EnPulse DR E1DR21

Device Survival Probability (%)

20

Ó

nPulse DR E1DR21				Product Characteristics	
US Market Release	Dec-03	Malfunctions (US)	0	NBG Code	DDDR
Registered US Implants	1,900	Therapy Function Not Compromised	0	Serial Number Prefix	PPT
Estimated Active US Implants	160	Therapy Function Compromised	0	Estimated Longevity	See page 7
Normal Battery Depletions (US)	373				
Performance Note: See page 149 –					

Performance note on Dual Chamber

Pacemakers with Measurement Lock-up ERI

2

3

5	100			 		 1	
5	90			 			
200	80						
Ź	70						
3	60						
<u></u>	50						
5	40						
į	30						
	50				1 <u>1</u>		

4

	Years After	Implant	Exc	luding Norr	nal Battery I	Depletion	Inc	luding Norm	al Battery D	epletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 80 mo			
%		100.0	100.0	100.0	100.0	100.0	100.0	100.0			
%		100.0	99.6	98.6	96.2	91.9	61.3	23.4			
#		1,640	1,490	1,330	1,160	970	460	110			
	Effective Sam	ple Size									

5

1

7

6

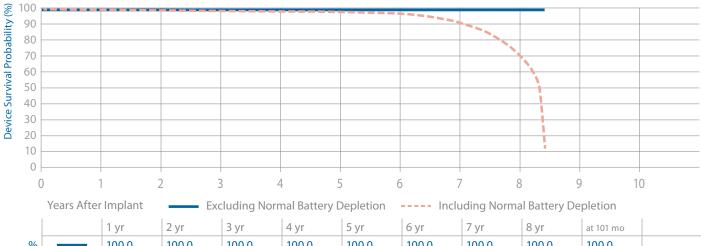
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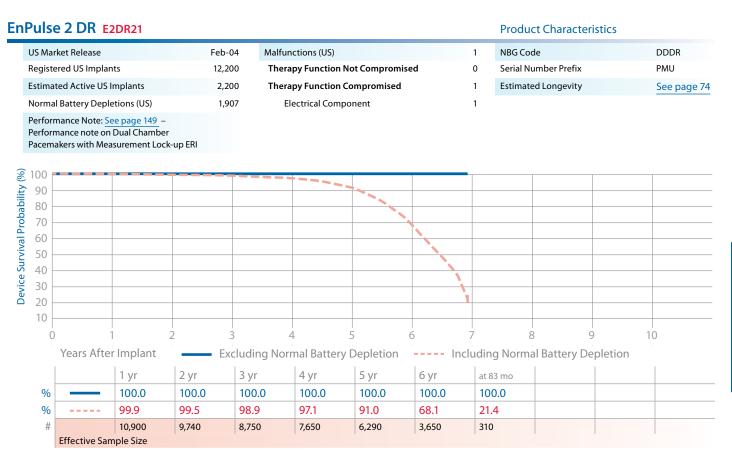
8

EnPulse 2 DR E2DR01, E2DR03, E2DR06, E2D01, E2D03

US Market Release	Feb-04	Malfunctions (US)	28	NBG Code	DDDR
Registered US Implants	100,800	Therapy Function Not Compromised	22	Serial Number Prefix	PNB, PNC, PNH
Estimated Active US Implants	45,100	Electrical Component	17	Estimated Longevity	See page 74
Normal Battery Depletions (US)	5,735	Possible Early Battery Depletion	2		
Performance Note: See page 149 –		Other	3		
Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI		Therapy Function Compromised	6		
Pacemakers with Measurement Lock-up Eki		Electrical Component	3		
		Electrical Interconnect	2		
		Battery Malfunction	1		



		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	at 101 mo	
%		100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	
%		99.9	99.9	99.8	99.4	98.7	97.2	91.5	70.5	13.0	
#		94,800	87,600	80,500	73,800	67,100	60,300	38,800	9,560	250	
	Effective Sam	ple Size									



EnPulse 2 DR E2DR31, E2DR33

US Market Release	Feb-04	Malfunctions (US)	0	NBG Code	DDDR
Registered US Implants	590	Therapy Function Not Compromised	0	Serial Number Prefix	PNL, PNM
Estimated Active US Implants	400	Therapy Function Compromised	0	Estimated Longevity	See page 7
Normal Battery Depletions (US)	8				

Performance Note: See page 149 -

Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI

Effective Sample Size

100 90

5 80											
2	0	1	2	3	4	5	б	7 8	3 9	9 1	0
3											
	Years After	Implant	Exc	luding Norn	nal Battery D)epletion	Inclu	iding Norma	l Battery De	pletion	
5	i cuis / i cci	implant		, adding Horn		piction	incre		Duttery De	piction	
j		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 99 mo	
8 %		100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	
د %		100.0	100.0	100.0	100.0	100.0	99.6	98.8	98.4	98.4	
/0		100.0	100.0	100.0	100.0	100.0	99.0	50.0	90. T	JU. T	
#		1,400	1,360	1,330	1,280	1,180	1,120	730	210	110	



EnPulse 2 SR E2SR01, E2SR03, E2SR06

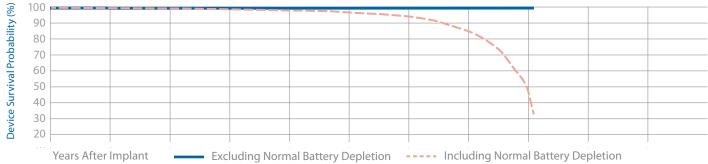
US Market Release	Dec-03	Malfunctions (US)	6	NBG Code	SSIR
Registered US Implants	25,500	Therapy Function Not Compromised	5	Serial Number Prefix	PMW, PMY,
Estimated Active US Implants 7,200		Electrical Component	2		PNA
Normal Battery Depletions (US)	1,341	Possible Early Battery Depletion	1	Estimated Longevity	See page 74
Advisories	None	Other	2		
		Therapy Function Compromised	1		

Other

Product Characteristics

1

NBG Code	SSIR
Serial Number Prefix	PMW, PMY, PNA
Estimated Longevity	See page 74



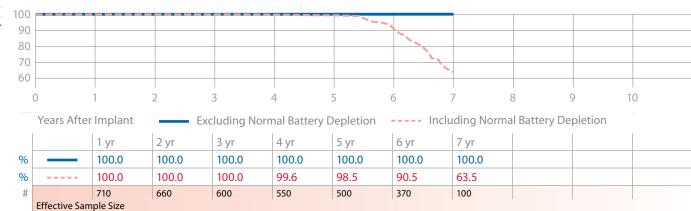
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 97 mo
%		100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	99.9
%		99.9	99.8	99.4	98.8	97.3	94.3	85.0	47.4	32.0
#		22,600	19,600	17,100	15,000	12,800	10,700	5,500	410	130
	Effective Sample Size									

EnPulse 2 VDD E2VDD01

US Market Release	Dec-03	Malfunctions (US)	0	NBG Code	VDD
Registered US Implants	640	Therapy Function Not Compromised	0	Serial Number Prefix	PMV
Estimated Active US Implants	190	Therapy Function Compromised	0	Estimated Longevity	See page 7
Normal Battery Depletions (US)	66				

Performance Note: See page 149 -Performance note on Dual Chamber

Pacemakers with Measurement Lock-up ERI



EnRhythm DR P1501DR

US Market Release	May-05	Malfunctions (US)	5,950	NBG Code	DDDRP
Registered US Implants	110,100	Therapy Function Not Compromised	5,897	Serial Number Prefix	PNP
Estimated Active US Implants	67,300	Battery (215 malfunctions related to advisory)	5,763	Estimated Longevity	See page 74
Normal Battery Depletions (US)	1,013	Electrical Component (2 malfunctions related to advisory)	38		
Advisories: See page 140 – 2010 Low B		Possible Early Battery Depletion	37		
Voltage Displayed at Device Interrogation Performance Note: See page 151 – Anomalies in		Electrical Interconnect	2		
MOSFET Integrated Circuit Technology		Other	57		
		Therapy Function Compromised	53		
		Electrical Component	37		
		Electrical Interconnect	4		
		Battery Malfunction	5		
		Possible Early Battery Depletion	2		
		Other	5		

00 F										
90										
80										
70										
60							· · ·			
50								1		
[Years Afte	1 yr	2 yr	3 yr	ormal Battery 4 yr	5 yr	6 yr	7 yr	mal Battery D	
%		100.0	100.0	99.9	99.1	96.2	89.4	85.4	85.0	
/0										
%		99.9	99.9	99.6	97.9	91.8	76.8	61.1	54.6	

EnR	hyt	hm MRI	EMDR01							Produ	ct Characte	ristics	
ι	JS Mar	ket Release		N/A	Malfund	ctions (US)			6	NBG Cod	de		DDDRP
R	legiste	ered US Implant	s	110) Therap	Therapy Function Not Compromised			6	Serial Number Prefix			PTA
E	stimat	ted Active US In	nplants	80) Ba	ttery Malfuncti	on		6	Estimated Longevity			See page 74
Ν	lormal	Battery Deplet	tions (US)	() Therap	by Function Co	mpromised		0				
A	dviso	ries		None	2								
Device Survival Probability (%)	100 90 80 0 1 2 Years After Implant		2 3		4 di	-	6 Inc	7 Iuding		al Battery D	9 Pepletion	10	
NIN			1 yr	2 yr	3 yr	at 41 mo							
Ce S	%		100.0	100.0	100.0	100.0							
Jevi	%		100.0	100.0	100.0	100.0							
	#		160	150	120	100							
		Effective Sam	ple Size										

Kappa 400 DR KDR401, KDR403

S Market	t Release		Jan-	-98	Malfund	tions (US)			27	NBG Cod	de	DDD/RO
egistere	d US Implan	its	46,6	500	Therap	y Function N	lot Comprom	ised	15	Serial Nu	umber Prefix	PER, PET
stimated	d Active US I	mplants	4,2	200	Ele	ctrical Comp	onent		10	Estimate	ed Longevity	See page
ormal Ba	attery Deple	etions (US)	7,8	855	Electrical Interconnect				1			
dvisorie	s		No	one	Po	ssible Early Ba	attery Depleti	on	2			
					Ot	her			2			
					Therap	y Function C	ompromised		12			
					Ele	ctrical Comp	onent		6			
					Ele	ctrical Interco	onnect		6			
00												
90 -												
80 -												
70												
60												
50												
40												
30 — 20 —												
10												
0			1									

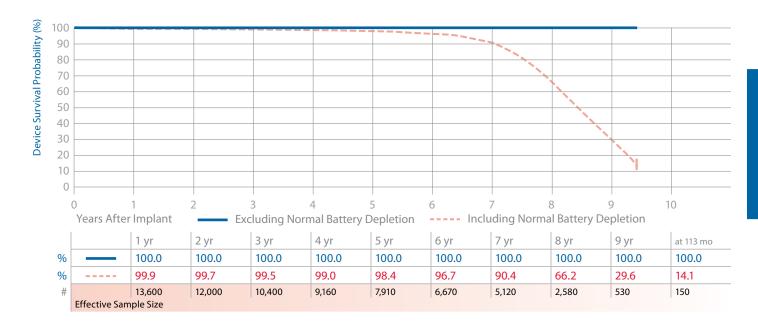
01		100.0	100.0	100.0	100.0	00.0	00.0	00.0	00.0	00.0	
%		100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9	99.9	
%		99.9	99.8	99.7	99.4	98.8	97.1	88.1	58.9	8.0	
#		44,200	41,100	37,900	34,800	31,400	27,700	21,200	9,730	670	
	Effective Sam	ple Size									

Kappa 400 SR KSR401, KSR403

US Market Release	Feb-98	Malfunctions (US)	5	NBG Code	SSIR
Registered US Implants	15,300	Therapy Function Not Compromised	4	Serial Number Prefix	PEU, PGD
Estimated Active US Implants	1,500	Electrical Component	3	Estimated Longevity	See page 75
Normal Battery Depletions (US)	1,512	Possible Early Battery Depletion	1		
Advisories	None	Therapy Function Compromised	1		
		Electrical Interconnect	1		

Product Characteristics

Product Characteristics



Карра 700 D кD701, кD703, кD706

US Mai	rket Release		Jan-9	99 M	alfunctions (US)			0	NBG Code	e		DDD
Registe	ered US Implan	ts	32	20 1	Therapy Function Not Compromised			0	Serial Number Prefix			PHK, PHM, PHL
Estima	ted Active US li	mplants	6	57 1	Therapy Function Compromised			0	Estimated	d Longevity		See page 75
Norma	l Battery Deple	etions (US)	1	21								
	ories: See page	<mark>e 143</mark> – 2009 Po nnect Wires	tential									
Perforr	mance Note: Se mance note on akers with Mea		up FRI									
100												
100												
80										7		
0) 1	1) :	3	4	5	6	7	8	 }	9	10
	Years After			-	lormal Battery	-		ludir		al Battery De	epletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7)	yr	8 yr	at 98 mo	
%		100.0	100.0	100.0	100.0	100.0	100.0	10	0.0	100.0	100.0	
%		100.0	100.0	100.0	99.0	98.0	95.8	94	ł.7	86.4	84.8	
#		290	260	230	210	200	170	16	0	120	100	
	Effective Sam	nple Size										

Kappa 700 DR KDR701, KDR703, KDR706

Device Survival Probability (%)

#

US Market	t Release		Jan-9	9 Malfun	ctions (US)		75	2 NBG Cod	de	
Registered	d US Implan	ts	205,80	0 Thera	py Function No	ot Compromise	d 63	3 Serial Nu	umber Prefix	
Estimated	Active US I	mplants	23,80	0 Ele	ectrical Compo	nent	20	6		
Normal Ba	Normal Battery Depletions (US) 34,757			7 Ele	ectrical Intercor	nnect	1	9 Estimate	ed Longevity	
		<mark>143</mark> – 2009 Pote	ential	Ba	ttery Malfunctio	on		1		
	S <mark>eparation of Interconnect Wires</mark> Performance Note: <u>See page 149</u> – Performance note on Dual Chamber Pacemak			Ро	ssible Early Batt	tery Depletion		4		
				Ot	her		1.	3		
	urement Lo		uccinakers	Thera	py Function Co	mpromised	68	9		
				Ele	ectrical Compo	nent	1	7		
					ctrical Intercon		67	1		
					7 malfunctions					
				Ро	ssible Early Batt	tery Depletion		1		
<u> </u>										
90								1		
80 - 70 -										
60										
50										
40										
30										
20										
10									· · · · · · · · · · · · · · · · · · ·	
0										
0	1		2 3	2	l 5	5 6	5 7	, 8	3 9)
V	ears After	Implant	Evc	luding Norr	nal Battery D	Doplation	Inclu	iding Norma	al Battery De	plation
	ears Arter		EXC	-	i dattery L				1	-
		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	9 yr
%		100.0	99.9	99.9	99.9	99.9	99.9	99.7	99.6	99.4
%		99.9	99.8	99.6	99.1	98.0	95.4	85.9	59.3	10.9

Product Characteristics

NBG Code	DDD/RO
Serial Number Prefix	PGU, PGY, PGW
Estimated Longevity	See page 75

40,600

3,060

10

180,500

Effective Sample Size

165,500

151,000

136,500

122,400

107,000

81,800

Kappa 700 DR KDR721

US Market Release	Feb-99	Malfunctions (US)
Registered US Implants	9,800	Therapy Function Not Compromised
Estimated Active US Implants	750	Electrical Component
Normal Battery Depletions (US)	1,346	Therapy Function Compromised

Advisories: See page 143 – 2009 Potential Separation of Interconnect Wires

99.9

8,630

Effective Sample Size

99.5

7,620

98.7

6,650

96.6

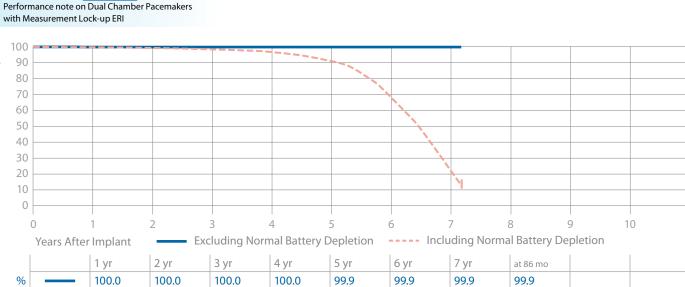
5,640

Performance Note: See page 149 -

Device Survival Probability (%)

%

#



90.7

4,450

68.9

2,260

22.2

320

12.3

120

Electrical Interconnect

Source: Medtronic Device Registration and Returned Product Analysis Data as of March 12, 2013

5

1

1

4

4

DDD/RO
PGR
See page 75

Kappa 700 SR KSR701, KSR703, KSR706

US Market Release Jan-99 Malfunctions (US) 30 NBG Code SSIR PHT, PHW, **Registered US Implants** 55,100 **Therapy Function Not Compromised** 6 Serial Number Prefix PHU Estimated Active US Implants 6,000 **Electrical Component** 2 Normal Battery Depletions (US) 5,100 1 Estimated Longevity **Electrical Interconnect** See page 75 Possible Early Battery Depletion Advisories: See page 143 – 2009 Potential 1 Separation of Interconnect Wires Other 2 **Therapy Function Compromised** 24 Electrical Component 4 Electrical Interconnect 20 (17 malfunctions related to advisory) 100 Device Survival Probability (%) 90 80 70 60 50 40 30 20 10 0 2 3 4 5 6 8 9 10 7 Years After Implant **Excluding Normal Battery Depletion** Including Normal Battery Depletion ----1 yr 2 yr 3 yr 4 yr 5 yr бyr 7 yr 8 yr 9 yr at 115 mo % 100.0 100.0 100.0 100.0 100.0 100.0 99.9 99.9 99.8 99.8 % 99.9 99.7 99.3 98.5 97.0 93.6 84.4 61.5 29.2 9.1 # 48,300 41,700 35,700 30,600 26,000 21,400 15,400 7,640 1,640 150 Effective Sample Size

Kappa 800 DR KDR801, KDR803

	DDD/RO
Normal Battery Depletions (US) 736 Electrical Interconnect 3 Performance Note: See page 149 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI 3	PKW, PKY
Performance Note: See page 149 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	See page 75
Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	
90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 90 <	
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	Years After Implant		Excluding Normal Battery Depletion Including Normal Battery Depletion								
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	at 109 mo
%		100.0	100.0	100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9
%		100.0	99.8	99.6	99.4	98.6	96.5	87.6	64.8	28.1	23.8
#		4,580	4,250	3,910	3,590	3,260	2,940	2,390	1,340	220	170
	Effective Sam	ple Size									

Source: Medtronic Device Registration and Returned Product Analysis Data as of March 12, 2013

Карра 900 DR кDR901, кDR903, кDR906

		et Release		Jan-02	Malfunctions (US		79	NBG Cod			DDR/RO
Regi	ister	red US Implant	S	125,200	Therapy Functi	on Not Compromised	26	Serial Nu	mber Prefix		PKM, PKN, PK
Estir	Estimated Active US Implants 26,100			26,100	Electrical Co	omponent	16	Estimate	d Longevity		See page 75
Norr	mal	Battery Deplet	tions (US)	19,708	Electrical In	terconnect	4				
Adv	Advisories: See page 143 – 2009 Potential Separation of Interconnect Wires Performance Note: See page 149 –			tential	Other		6				
Sepa					Therapy Functi	on Compromised	53				
Per				Electrical Co	omponent	9					
Per	rfori	mance note or	n Dual Chamber asurement Locl		Electrical In	terconnect	44				
10	00										
9	90										
8	30							-			
7	70							<u> </u>			
6	50										
5	50										
10 9 7 6 5 4 3 2	10										
3	30										
2	20										
. 1	10										
	0								1		
			1	1						1	1

Years After Implant _____ Excluding Normal Battery Depletion _---- Including Normal Battery Depletion

		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	at 107 mo
%		100.0	100.0	100.0	100.0	100.0	100.0	99.9	99.9	99.9
%		99.9	99.9	99.7	99.3	98.4	96.3	87.9	60.2	4.0
#		117,400	108,000	98,900	90,200	81,500	72,400	55,000	25,800	1,030
	Effective Sam	ple Size								

Kappa 900 SR KSR901, KSR903, KSR906

US Market Release	Jan-02
Registered US Implants	37,000
Estimated Active US Implants	6,200
Normal Battery Depletions (US)	3,176
Advisories: See page 143 – 2009 Potential Separation of Interconnect Wires	

32,000

Effective Sample Size

27,600

24,000

20,700

#

Malfunctions (US)
Therapy Function Not Compromised
Electrical Component
Possible Early Battery Depletion
Therapy Function Compromised
Electrical Interconnect (8 malfunctions related to advisory)

Product Characteristics

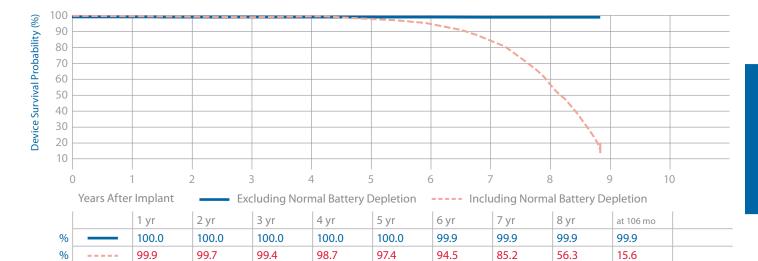
17

8

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1 9 9

NBG Code	SSIR
Serial Number Prefix	PLF, PLG, PLH
Estimated Longevity	See page 75



17,700

14,900

9,880

3,670

270

Jan-02

650

75

81

Malfunctions (US)

Other

Therapy Function Not Compromised

Therapy Function Compromised

Карра 900 VDD курро1

Estimated Active US Implants

Normal Battery Depletions (US)

US Market Release

Registered US Implants

Product Characteristics

1

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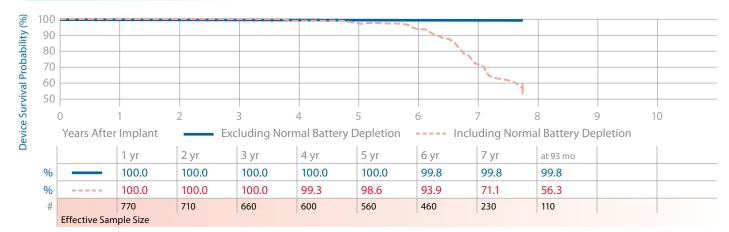
NBG Code	VDD
Serial Number Prefix	PLE
Estimated Longevity	See page 75

Advisories: See page 143 – 2009 Potential Separation of Interconnect Wires

Performance Note: See page 149 -

Performance note on Dual Chamber

Pacemakers with Measurement Lock-up ERI



Kappa 920 DR KDR921

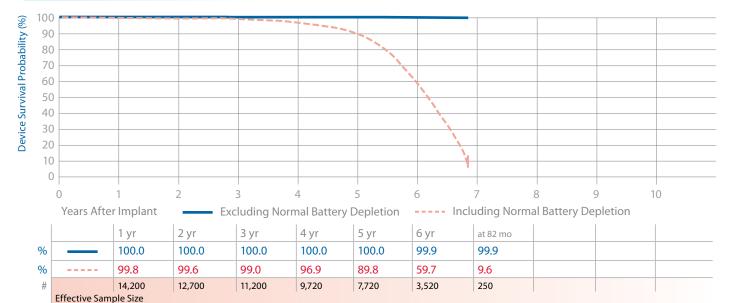
US Market Release	Jan-02	Malfunctions (US)
Registered US Implants	16,300	Therapy Function Not Co
Estimated Active US Implants	1,500	Electrical Component
Normal Battery Depletions (US)	2,779	Other
Advisories: See page 143 – 2009		Therapy Function Comp
Potential Separation of Interconnect Wires		Electrical Interconnec

Performance Note: See page 149 -

Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI

Compromised nt oromised (3 malfunctions related to advisory)

5	NBG Code	DDD/RO
2	Serial Number Prefix	PKR
1	Estimated Longevity	See page 75
1		
3		
3		



Prodigy SR 8158, 8160, 8161, 8162

US Market Release	Oct-95	Malfunctions (US)	5	NBG Code	SSIR
Registered US Implants	22,200	Therapy Function Not Compromised	3	Serial Number Prefix	PEM, PED, PEE,
Estimated Active US Implants	2,200	Battery Malfunction	1	Senai Number Prenx	PEF
Normal Battery Depletions (US)	1,396	Possible Early Battery Depletion	1	Estimated Longevity	See page 75
Advisories	None	Other	1		
		Therapy Function Compromised	2		

Electrical Component

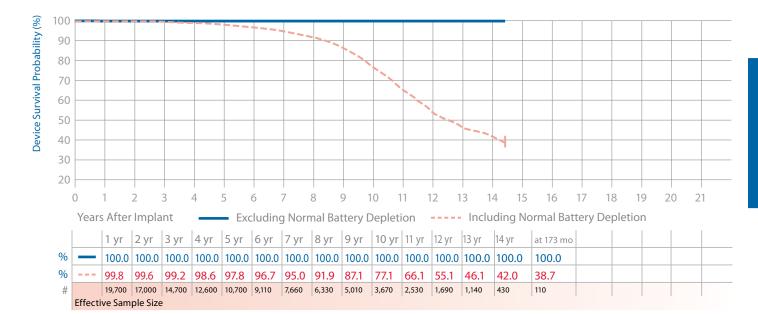
Electrical Interconnect

Product Characteristics

Product Characteristics

1

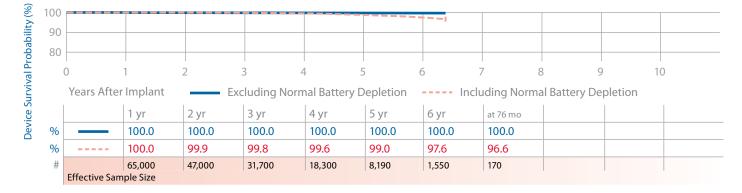
1



Sensia DR SEDR01, SED01

	1.01				((IIC)						
	rket Release		Jul-0		functions (US)			24	NBG Code	DDD, DDD	
-	Registered US Implants			D Th	erapy Function	-	ised	14	Serial Number P	refix	
Estima	ited Active US I	mplants	90,10	0	Electrical Comp	onent		11			NWL, NWK
Norma	al Battery Deple	etions (US)	17	1	Electrical Interc	onnect		1	Estimated Longe	evity	See page
	mance Note: Se				Other			2			
	note on Dual Chamber Pacemakers with Measurement Lock-up ER				Therapy Function Compromised			10			
					Electrical Comp	onent		4			
					Electrical Interc	onnect		1		G Code DDD, DDDR PWL, PWK, NWL, NWK imated Longevity See page 7 See page 7 See page 7 See page 7 10 10 10 10 10 10 10 10 10 10	
					Other			5			
<mark>8</mark> 100											
io 80											
dor 00		1						7			10
/al F	0	I	2	3	4	5	6	/	8	9	10
Device Survival Probability % 06	Years After	r Implant	Exc	luding N	ormal Battery	Depletion	In	cludin	g Normal Batte	ery Deple	tion
e S		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	at	76 mo		
% Jevi		100.0	100.0	100.0	100.0	100.0	100.0	10	0.0		
%		100.0	100.0	99.8	99.6	99.1	98.5	98	.3		
#		97,700	75,200	53,800	33,400	15,900	3,270	54	0		
	Effective San	nple Size									

Se	ensia SR SESR01, SES01				Product Characteristics	
	US Market Release	Jul-06	Malfunctions (US)	7	NBG Code	SSIR, SSI
	Registered US Implants	83,000	Therapy Function Not Compromised	6	Serial Number Prefix	PWR, PWS,
	Estimated Active US Implants	58,000	Electrical Component	4		NWR, NWS
	Normal Battery Depletions (US)	135	Other	2	Estimated Longevit	See page 75
	Advisories	None	Therapy Function Compromised	1		
			Electrical Interconnect	1		



Sigma 100 S \$\$103, \$\$106

US Market Release Malfunctions (US) Aug-99 **Registered US Implants** 830 Estimated Active US Implants 110 26

Therapy Function Not Compromised Therapy Function Compromised

Product Characteristics

0	NBG Code	SSI
0	Serial Number Prefix	PJG, PJH
0	Estimated Longevity	See page 75

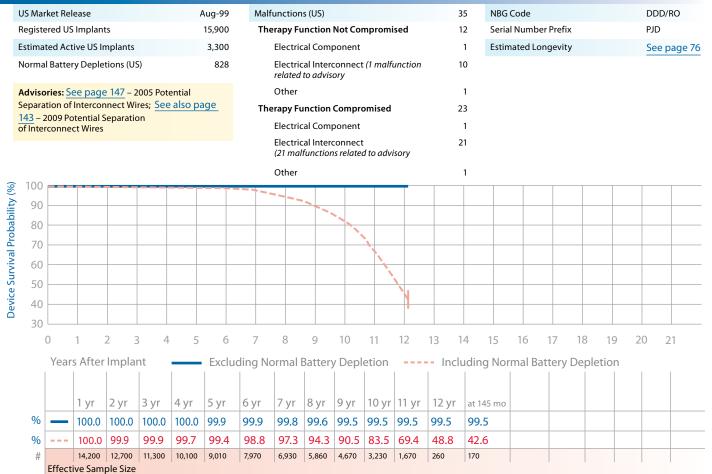
Normal Battery Depletions (US) Advisories: See page 147 – 2005 Potential

Separation of Interconnect Wires

(%)	100											
~					T			1				
ilit	90											
robability	80											
p	00											
al P			1	2	3	4	5 (6 7	7 8	3	9 1	C
Irvivi		Years After	r Implant	Ex	cluding Norr	mal Battery [Depletion	Inclu	uding Norma	al Battery De	epletion	
Device Su			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	at 113 mo
	%		100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0
	%		100.0	100.0	99.6	99.6	98.8	98.8	97.0	93.7	85.3	82.2
	#		620	490	390	320	250	220	190	150	120	100
		Effective Sam	ple Size									

Sigma 200 DR SDR203

Product Characteristics



Sigma 200 SR SSR203, SS203

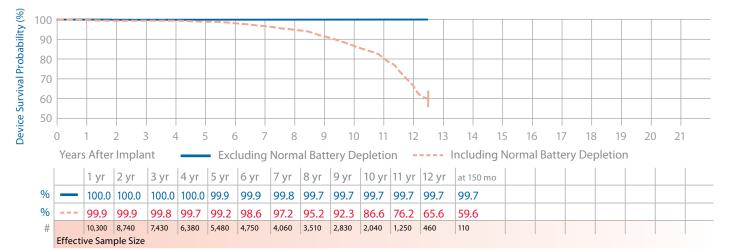
US Market Release	Sep-99
Registered US Implants	12,100
Estimated Active US Implants	1,800
Normal Battery Depletions (US)	397

Advisories: See page 147 – 2005 Potential Separation of Interconnect Wires; See also page 143 – 2009 Potential Separation of Interconnect Wires

Malfunctions (US)
Therapy Function Not Compromised
Therapy Function Compromised
Electrical Interconnect (13 malfunctions related to advisory)

Product Characteristics

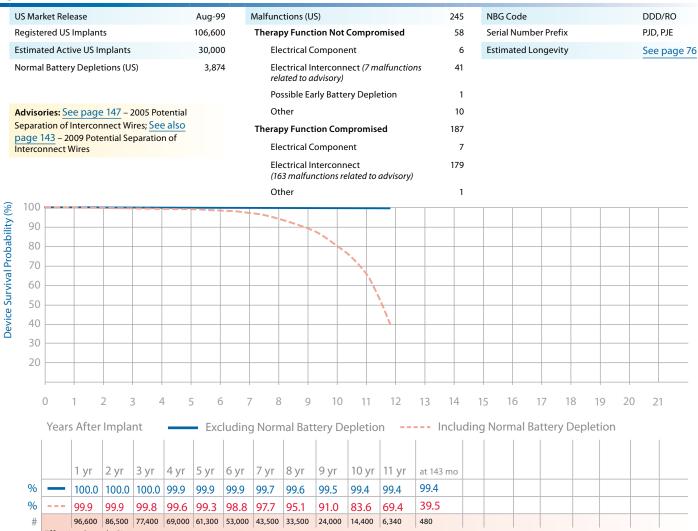
NBG Code	SSIR
Serial Number Prefix	PJG
Estimated Longevity	See page 76



Source: Medtronic Device Registration and Returned Product Analysis Data as of March 12, 2013

Sigma 300 DR SDR303, SDR306

Product Characteristics



Effective Sample Size

Sigma 300 SR SSR303, SSR306

	ket Rele				•		NA-16		(110)				50	NBG Code					SIR
			_			ug-99 4,000		nctions					52 11	Serial Numb	D f				IG, PJH
Registered US Implants									ot Compr	omised									
Estimated Active US Implants						0,800			l Compoi				1	Estimated L	ongevit	:y		5	ee page
Normal Battery Depletions (US)						1,243			I Intercor advisory		nalfunctio	ons	8						
Advisories: See page 147 – 2005 Potential						(Other					2							
Separation of Interconnect Wires; See also page 143 – 2009 Potential Separation of						Ther	apy Fun	ction Co	mpromi	sed		41							
	nnect V		ntiai sep	aration	U		E	lectrica	l Compo	nent			3						
									l Intercor				38						
100							(37 malfu	nctions r	elated to	advisory)								
100																			
90								_											
80																			
70																			
60																			
50																			
40																			
10																			
(0	1 2	2 3	4	5	6	7	8	9 1	0 11	12	13	14	15 16	17	18	19	20	21
	Years	After	Implar	nt		Excluc	ling No	rmal Ba	attery [Depletio	on	Ir	ncludin	g Normal B	attery	Depl	etion		
		1 yr	2 yr	3 yr	4 yr	5 yr	б yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	at 146 mo					
%	—	100.0	100.0	100.0	100.0	100.0	99.9	99.8	99.7	99.7	99.7	99.6	99.6	98.6					
%		99.9	99.9	99.7	99.5	99.2	98.6	97.5	95.6	92.1	85.8	76.0	62.7	58.2					
#		47,100	40,000	34,100	29,300	25,300	21,000	16,800	13,000	9,320	5,640	2,810	580	250					
	Effecti	ve Samp	ole Size					1			1	1		1		1	1	1	1

Product Characteristics

Product Characteristics

Sigma 300 VDD svDD303

5					
US Market Release	Sep-99	Malfunctions (US)	1	NBG Code	VDDD
Registered US Implants	650	Therapy Function Not Compromised	0	Serial Number Prefix	PJD
Estimated Active US Implants	81	Therapy Function Compromised	1	Estimated Longevity	See page 76
Normal Battery Depletions (US)	67	Electrical Interconnect (1 malfunction related to advisory)	1		

Advisories: See page 147 – 2005 Potential Separation of Interconnect Wires



DG

Medtronic CRDM Product Performance Report 65 www.medtronic.com/CRDMProductPerformance

Source: Medtronic Device Registration and Returned Product Analysis Data as of March 12, 2013

Versa DR VEDR01

Product Characteristics

	ket Release	Jul-06	Malfunctions (US)		15				DDDR
	ered US Implants	93,900	Therapy Function No	t Compromised	I 9	Serial N	lumber Prefix		PWH, NWH
Estimat	ted Active US Implants	71,700	Electrical Comp	onent	4	Estimat	ed Longevity		See page 7
Norma	Battery Depletions (US)	164	Electrical Interco	onnect	2				
	nance Note: <u>See page 149</u> –		Other		3				
	nance note on Dual Chamber akers with Measurement Lock-up ERI		Therapy Function Co	mpromised	6				
			Electrical Comp	onent	2				
			Other		4				
100									
90 80									
90 80	0 1 2	3	4 5	5 6	7		8 9	9	10
90 80	0 1 2 Years After Implant	_	4 5				al Battery De		10
90 80		- Excludi	ing Normal Battery D		Inclue				10
90 80	Years After Implant	Excludi	ing Normal Battery D	Depletion -	6 yr	ding Norm			10
90 80 (Years After Implant	Excludi 3 y	ing Normal Battery D vr 4 yr 0.0 100.0	Depletion -	6 yr 100.0	ding Norm at 77 mo			10

Revo MRI SureScan RVDR01

Effective Sample Size

US Market Release	Feb-11	Malfunctions (US)	17	NBG Code	DDDRP
Registered US Implants	52,000	Therapy Function Not Compromised	16	Serial Number Prefix	PTN
Estimated Active US Implants	50,300	Electrical Component	3	Estimated Longevity	See page 76
Normal Battery Depletions (US)	0	Other	13		
Advisories	None	Therapy Function Compromised	1		
		Electrical Component	1		



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Summary (95% Confidence Interval)	
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	Included				E	Malfunctions (US)	ctions ((<l)< th=""><th>I</th><th>Device</th><th></th><th>Device Survival Probability (%)</th><th>0111LY (%)</th><th></th><th></th><th></th><th></th><th></th><th></th><th></th></l)<>	I	Device		Device Survival Probability (%)	0111LY (%)							
١٨		arket ase	stered stnslqn	bəter 2U ə ^y 81ns	al Battery (2U) snoite	qργ tion bsomised	yqe toN noit:	promised		Years /	Years After Implant	olant								
ime7	muN muN	sələЯ M SU			Depl Norn	rom Func moD	r9nc Ther	mo) stoT		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr 8	8 yr 9	9 yr	10 yr	11 yr
Adapta DR	ADDR01, ADDR03, ADDR06, ADDR06,	Jul-06	342,700	281,900	375	22	+ 42	= 64	Excluding Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 at 77 mo				
	<mark>See page</mark> Pacemake	<u>149</u> – Perfi rs with Mea	ormance ne ssurement	<u>See page 149</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	hamber				Including Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.9 +0.0/-0.0	99.8 +0.0/-0.0	99.4 +0.0/-0.1	98.8 +0.1/-0.1	98.8 +0.1/-0.1 at 77 mo				
Adapta DR	ADDRL1	Jul-06	73,900	66,700	23	m	+ 6	= 12	Excluding Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 at 76 mo				
	<mark>See page</mark> Pacemake	149 – Perfi rs with Meč	ormance ne ssurement	<u>See page 149</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	hamber				Including Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.9 +0.0/-0.0	99.8 +0.1/-0.1	99.6 +0.1/-0.1	99.4 +0.2/-0.3	99.4 +0.2/-0.3 at 76 mo				
Adapta DR	ADDRS1	Jul-06	33,300	24,900	274	4	+ v	6	Excluding Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.9 +0.0/-0.1	99.9 +0.0/-0.1 at 74 mo				
	<mark>See page</mark> Pacemake	149 – Perfi rs with Meá	ormance ne ssurement	<u>See page 149</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	hamber				Including Normal Battery Depletion	9.99 +0.0/-0.0	99.8 +0.0/-0.1	99.6 +0.1/-0.1	98.8 +0.2/-0.2	95.6 +0.5/-0.5	83.6 +1.7/-1.9	81.5 +2.5/-2.9 at 74 mo				
Adapta SR	ADSR01, ADSR03, ADSR06	Jul-06	64,600	45,500	151	4	+ 4	∞ ∥	Excluding Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 at 76 mo				
									Including Normal Battery Depletion	100.0 +0.0/-0.0	9.99 +0.0/-0.0	99.8 +0.0/-0.1	99.4 +0.1/-0.1	98.7 +0.2/-0.2	97.4 +0.4/-0.4	97.3 +0.4/-0.5 at 76 mo				
Adapta VDD	ADVDD01 Jul-06	Jul-06	1,000	760	-	0	0 +	0	Excluding Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 at 66 mo					
	<mark>See page</mark> Pacemake	<u>149</u> – Perfi ·rs with Meã	ormance ne asurement	<u>See page 149</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	hamber				Including Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 at 66 mo					
Advisa DR MRI+C82 Ensura	A2DR01, A3DR01, A4DR01, A5DR01, ENDR01	Apr-11	1,120	1,100	0	0	0 +	0	Excluding Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 at 35 mo								
	See page 149 Pacemakers w		ormance ne ssurement	<u>See page 149</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	hamber				Including Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 at 35 mo								
AT500	AT501, 7253	Mar-03	11,100	006	2,808	S	+ 4	6	Excluding Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.9 +0.0/-0.1	99.9 +0.0/-0.1	99.9 +0.0/-0.1	99.9 +0.0/-0.1 at 83 mo				
	<mark>See page</mark> System Fc	<mark>See page 154</mark> – Performanc System Follow-Up Protocol	irmance no otocol	See page 154 – Performance note on AT500 Pacing System Follow-Up Protocol	acing				Including Normal Battery Depletion	99.9 +0.0/-0.1	99.8 +0.1/-0.1	99.4 +0.1/-0.2	97.5 +0.3/-0.3	85.5 +0.8/-0.8	55.2 +1.2/-1.3	1.4 +0.7/-0.5 at 83 mo				

IPG Implantable Pulse Generators, continued

Source: Medtronic Device Registration and Returned Product Analysis Data as of March 12, 2013

Medtronic CRDM Product Performance Report 67 www.medtronic.com/CRDMProductPerformance

continued

continued
Summary
Survival
Device

		yr 11 yr												
		10 yr												
		9 yr	100.0 +0.0/-0.0 at 106 mo	24.4 +2.0/-1.9 at 106 mo			100.0 +0.0/-0.0 at 101 mo	13.0 +3.0/-2.7 at 101 mo			100.0 +0.0/-0.0 at 99 mo	98.4 +0.7/-1.2 at 99 mo	99.9 +0.1/-0.4 at 97 mo	32.0 +4.2/-4.1
		8 yr	100.0 +0.0/-0.0	60.1 +1.7/-1.7			100.0 +0.0/-0.0	70.5 +0.6/-0.6			100.0 +0.0/-0.0	98.4 +0.7/-1.2	100.0 +0.0/-0.0	47.4 +2.5/-2.5
		7 yr	100.0 +0.0/-0.0	86.9 +1.0/-1.1	100.0 +0.0/-0.0 at 80 mo	23.4 +3.8/-3.6 at 80 mo	100.0 +0.0/-0.0	91.5 +0.2/-0.2	100.0 +0.0/-0.0 at 83 mo	21.4 +2.0/-1.9 at 83 mo	100.0 +0.0/-0.0	98.8 +0.5/-0.9	100.0 +0.0/-0.0	85.0 +0.7/-0.7
		6 yr	100.0 +0.0/-0.0	96.6 +0.5/-0.6	100.0 +0.0/-0.0	61.3 +3.2/-3.3	100.0 +0.0/-0.0	97.2 +0.1/-0.1	100.0 +0.0/-0.0	68.1 +1.2/-1.2	100.0 +0.0/-0.0	99.6 +0.2/-0.5	100.0 +0.0/-0.0	94.3 +0.4/-0.4
		5 yr	100.0 +0.0/-0.0	98.1 +0.3/-0.4	100.0 +0.0/-0.0	91.9 +1.4/-1.7	100.0 +0.0/-0.0	98.7 +0.1/-0.1	100.0 +0.0/-0.0	91.0 +0.6/-0.7	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	97.3 +0.2/-0.3
Device Survival Probability (%)		4 yr	100.0 +0.0/-0.0	99.0 +0.2/-0.3	100.0 +0.0/-0.0	96.2 +0.9/-1.2	100.0 +0.0/-0.0	99.4 +0.1/-0.1	100.0 +0.0/-0.0	97.1 +0.3/-0.4	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	98.8 +0.2/-0.2
l Probal	plant	3 yr	100.0 +0.0/-0.0	99.8 +0.1/-0.2	100.0 +0.0/-0.0	98.6 +0.5/-0.8	100.0 +0.0/-0.0	99.8 +0.0/-0.0	100.0 +0.0/-0.0	98.9 +0.2/-0.2	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.4 +0.1/-0.1
e Surviva	Years After Implant	2 yr	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.6 +0.2/-0.5	100.0 +0.0/-0.0	9.9 +0.0/-0.0	100.0 +0.0/-0.0	99.5 +0.1/-0.2	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.8 +0.1/-0.1
Device	Years <i>F</i>	1 yr	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	9.99 +0.0/-0.0	100.0 +0.0/-0.0	99.9 +0.0/-0.1	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.9 +0.0/-0.0
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery
()	Į	stoT	-		0		28		-		0		9	
Malfunctions (US)	besimord		н —		Ш О		22 =		Ш О		Ш 0		5	
unctio	rapy ction Not	əq⊥	+		+		+		+		+		+	
Malf	rapy Function promised	ad 9dT	0		0		Q		-		0		-	
	yatteß len (SU) snoitel		1,095	hamber	373	hamber	5,735	hamber	1,907	hamber	œ	hamber	1,341	
•	bəter VƏ Və SU av	itoA	1,600	n Dual C c-up ERI	160	n Dual C c-up ERI	45,100	n Dual C c-up ERI	2,200	n Dual C c-up ERI	400	n Dual C c-up ERI	7,200	
				e note o ent Lock		e note o ent Lock		e note o ent Lock		e note o ent Lock	7	e note o ent Lock		
	stered stants		6,800	ormance asureme	1,900	ormance asureme	100,800	ormance asureme	12,200	ormance asureme	590	ormance asureme	25,500	
	larket ase	ələЯ V SU	Dec-03	<u>See page 149</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	Dec-03	<u>See page 149</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	Feb-04	<u>See page 149</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	Feb-04	<u>See page 149</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	Feb-04	<u>See page 149</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	Dec-03	
	ıper el	ooM nuV	E1DR01, E1DR03, E1DR06	<mark>See page</mark> Pacemake	E1DR21	<mark>See page</mark> Pacemake	E2DR01, E2DR03, E2DR06, E2DR06, E2D01, E2D03	<mark>See page</mark> Pacemake	E2DR21	<mark>See page</mark> Pacemake	E2DR31, E2DR33	<mark>See page</mark> Pacemake	E2SR01, E2SR03, E2SR06	
			EnPulse DR		En Pulse DR		EnPulse 2 DR		EnPulse 2 DR		EnPulse 2 DR		EnPulse 2 SR	

IPG Implantable Pulse Generators, continued

continued

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continued
Summary
urvival
Device Si

					E	Malfunct	ctions (US)	(NS)		Devic	e Surviv	Device Survival Probability (%)	bility (%							
γlin	del mber	Market ease	jistered Implants	bətemi SU əvi stnelc	rmal Battery (2U) snoitelg	rapy notion besimorqm	stapy toN noitor feasimonam	b92imo1qm ial		Years	Years After Implant	plant								
ns7	oM INV		SU Səß	†2A	ioN I9Ū	Inf	nFur	Tot		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr
EnPulse 2 VDD	E2VDD01	Dec-03	640	190	66	0	0 +	0	Excluding Normal Battery Depletion	100.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0				
	<mark>See page</mark> Pacemake	<u>See page 149</u> – Performance note on Dual Pacemakers with Measurement Lock-up ERI	ormance no surement L	<u>See page 149</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	amber				Including Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.6 +0.3/-0.9	98.5 +0.7/-1.5	90.5 +2.4/-3.2	63.5 +5.5/-6.2				
EnRhythm DR	P1501DR	May-05	110,100	67,300	1,013	23	+ 5,897	7 = 5,950	50 Excluding Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.9 +0.0/-0.0	99.1 +0.1/-0.1	96.2 +0.2/-0.2	89.4 +0.3/-0.3	85.4 +0.4/-0.4	85.0 +0.4/-0.4 at 86 mo			
	See page at Device	<u>See page 140</u> – 2010 Low Battery V at Device Interrogation Advisories:	Low Batter on Advisorie	<u>See page 140</u> – 2010 Low Battery Voltage Displayed at Device Interrogation Advisories:	played	(0) (adviso	+ (217) pry-relate	(0) + (217) = 217 (advisory-related subset)	7 Including Normal Battery Depletion	99.9	99.9 +0.0/-0.0	99.6 +0.0/-0.0	97.9 +0.1/-0.1	91.8 +0.2/-0.2	76.8 +0.4/-0.4	61.1 +0.6/-0.6	54.6 +1.1/-1.1 at 86 mo			
	See page MOSFET II	<u>See page 151</u> – Performance note on ar MOSFET Integrated Circuit Technology	rmance not ircuit Techn	<u>See page 151</u> – Performance note on anomalies in MOSFET Integrated Circuit Technology	ies in															
EnRhythm MRI	EMDR01	N/A	110	80	0	0	و +	9	Excluding Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 at 41 mo							
									Including Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 at 41 mo							
Kappa 400 DR	KDR401, KDR403	Jan-98	46,600	4,200	7,855	12	+ 15	= 27	Excluding Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.9 +0.0/-0.0	9.99 +0.0/-0.0+	9.99 +0.0/-0.0+	99.9 +0.0/-0.0	99.9 +0.0/-0.0 at 107 mo		
	<mark>See page</mark> Pacemake	<u>See page 149</u> – Performance note on Dual (Pacemakers with Measurement Lock-up ERI	ormance no surement L	<u>See page 149</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	amber				Including Normal Battery Depletion	99.9 +0.0/-0.0	99.8 +0.0/-0.0	99.7 +0.0/-0.1	99.4 +0.1/-0.1	98.8 +0.1/-0.1	97.1 +0.2/-0.2	88.1 +0.4/-0.4	58.9 +0.7/-0.7	8.0 +0.7/-0.7 at 107 mo		
Kappa 400 SR	KSR401, KSR403	Feb-98	15,300	1,500	1,512	-	+ 4	Ш С	Excluding Normal Battery Depletion	100.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 at 113 mo		
									Including Normal Battery Depletion	99.9 +0.0/-0.1	99.7 +0.1/-0.1	99.5 +0.1/-0.1	99.0 +0.2/-0.2	98.4 +0.2/-0.3	96.7 +0.4/-0.4	90.4 +0.7/-0.7	66.2 +1.3/-1.4	14.1 +1.9/-1.8 at 113 mo		
Kappa 700 DR	KD701, KD703, KD706	Jan-99	320	67	21	0	0 +	0	Excluding Normal Battery Depletion	100.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 at 98 mo		
	See page Interconn	See page 143 – 2009 f Interconnect Wires	Potential Se	<u>See page 143</u> – 2009 Potential Separation of Interconnect Wires		(0) + (advisory-	<u> </u>	(0) = (0) elated subset)) Including Normal Battery Depletion	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.0 +0.7/-2.7	98.0 +1.2/-3.2	95.8 +2.1/-4.0	94.7 +2.4/-4.3	86.4 +4.5/-6.4	84.8 +4.9/-6.8 at 98 mo		
	<u>See page</u> Pacemake	<u>See page 149</u> – Performance note on Dual Pacemakers with Measurement Lock-up ERI	ormance no surement L	<u>See page 149</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	amber															

Source: Medtronic Device Registration and Returned Product Analysis Data as of March 12, 2013

continued

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IPG Implantable Pulse Generators, continued

Device Survival Summary continued

Control Control <t< th=""><th>ltronic</th><th></th><th></th><th></th><th></th><th>F</th><th>Malfunctions</th><th></th><th>Device</th><th>Survival</th><th>Device Survival Probability (%)</th><th>lity (%)</th><th></th><th></th><th></th><th></th><th></th><th></th></t<>	ltronic					F	Malfunctions		Device	Survival	Device Survival Probability (%)	lity (%)						
$ \frac{5}{6} = 5$		del nber	təxhet 9269	istered stnslqm	SU 9vi	mal Battery اوtions	rapy ction Not bəsimorqu		Years A	fter Imp	lant							
Repart 0 0 RP701, KDR73, Jan-9 CSS 00 3 3 0 / 3 2 / 3 0 3 4 / 3 / 3 / 3 0 3 4 / 3 / 3 0 3 4 / 3 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 4 / 3 0 3 / 3 0 3 / 3 0 3 / 3 0 3 / 3 0 3 / 3 0 3 / 3 0 3 / 3 0 3 / 3 0 3 / 3 0 3 / 3 0 3 / 3 0 3 / 3 0 3 / 3 0 3 / 3 0 3 / 3 0 3 / 3 0 <th></th> <th>nuN</th> <th>aləsi USU</th> <th>I SN ნəუ</th> <th>ţэА</th> <th>noN Dep</th> <th>an nu adT adT</th> <th></th> <th>1 yr</th> <th>2 yr</th> <th>3 yr</th> <th>4 yr</th> <th></th> <th></th> <th>7 yr</th> <th></th> <th></th> <th> 11 yr</th>		nuN	aləsi USU	I SN ნəუ	ţэА	noN Dep	an nu adT adT		1 yr	2 yr	3 yr	4 yr			7 yr			 11 yr
$ \frac{\text{Generative}}{\text{Accessment lock-up Entry}} \frac{\text{Generative}}{\text{Accessment lock-up Entry}} \frac{1271}{10} + (0) = (277)$ $ \frac{\text{Normalisative}}{10} \frac{1000}{10} + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) = (0) + (0) + (0) = (0) + (0) = (0) + (0) + (0) + (0) = (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + (0) + $				205,800	23,800	34,757	+ 63	Excluding Normal Battery Depletion	0.	9.99 +0.0/-0.0+	99.9 +0.0/-0.0	99.9 +0.0/-0.0		-0.0	99.7 +0.0/-0.0	0.0	99.4 +0.1/-0.1	
And the second	nce Re	<u>See page 143</u> – 200	09 Potential S	eparation	of Interconne	ect Wires	= (0) +	Including Normal Battery Denletion		99.8 +0.0/-0.0	99.6 +0.0/-0.0				85.9 +0.2/-0.2		10.9 +0.4/-0.4	
2epage 149 - Performance note on Dual Chamber Participation Parameter sinth Masurement Lock-up EIR Parameter sinth Masurement Lock-up EIR Parameter sinth Masurement Lock-up EIR Parameter sinth Masurement Lock-up BIR Parameter sinth Masurement Lock-up EIR Parameter sinth Parameter sinth Masurement Lock-up EIR Parameter sinth Masurement Lock-up EIR Parameter sinth Parameter sinth Masurement Lock-up EIR Parameter sinth Parame	epor						(advisory-related subset)											
Kapa 70 Kor 71 Feb-9 9.00 7.0 1.346 4 1 5 Keuding to 1000 1000 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0 90.0	t	<u>See page 149</u> – Pt Pacemakers with N	erformance n Measurement	ote on Dua Lock-up EF	ll Chamber 81													
$ \frac{\text{Sepage I43 - 2009 Potential Separation of Intercomed}}{\text{Wires}} \begin{array}{c} (0) \ + \ (0) \ = \ (0) \\ \text{Wires} \end{array} \\ \frac{\text{Sepage I43 - 2009 Potential Separation of Intercomed}}{\text{Wires}} \begin{array}{c} (0) \ + \ (0) \ = \ (0) \\ \text{Wires} \end{array} \\ \frac{\text{Sepage I43 - 2009 Potential Separation of Intercomed}}{\text{Mires}} \end{array} \\ \frac{\text{Sepage I43 - 2009 Potential Separation of Intercomed}}{\text{Rapha 70}} \end{array} \\ \frac{\text{Sepage I43 - 2009 Potential Separation of Intercomed}}{\text{Rapha 70}} \end{array} \\ \frac{\text{Sepage I43 - 2009 Potential Separation of Intercomed}}{\text{Rapha 70}} \end{array} \\ \frac{\text{Sepage I43 - 2009 Potential Separation of Intercomed}}{\text{Kar706} \ \text{Mires} \ \text{Mires} \end{array} \\ \frac{\text{Sepage I43 - 2009 Potential Separation of Intercomed}}{\text{Wires} \ \text{Mires} \ \text{Mires} \ \text{Mires} \end{array} \\ \frac{\text{Sepage I43 - 2009 Potential Separation of Intercomed}}{\text{Wires} \ \text{Mires} \end{array} \\ \frac{\text{Sepage I43 - 2009 Potential Separation of Intercomed}}{\text{Mires} \ \text{Mires} \ \text{Mires}$	Kappa 700 DR		Feb-99	9,800	750	1,346	≡ +	Excluding Normal Battery Depletion	o.	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0		0.1	99.9 +0.1/-0.1	99.9 +0.1/-0.1 at 86 mo		
$ \frac{5 \text{ Berbage 149 - Performance note on Dual Chamber }{\text{Pacemakers with Measurement Lock-up ERI} } \\ \frac{\text{Kappa 700}}{\text{Rappa 700}} \frac{5 \text{Farbage 149 - Performance note on Dual Chamber }{\text{Rappa 700}} \frac{1000}{\text{Rappa 700}} \frac{1000}{\text{ASP704}} \frac{1000}{\text{ASP704}} \frac{1000}{\text{ASP706}} \frac{1000}{\text{ADP}700} \frac{1000}{\text{AD}700} \frac{1000}{\text{AD}700} \frac{1000}{\text{AD}700} \frac{1000}{\text{AD}700} \frac{1000}{\text{AD}700} \frac{1000}{\text{AD}700} \frac{1000}{\text{AD}700} \frac{1000}{\text{AD}700} \frac{1000}{\text{AD}700} \frac{10000}{\text{AD}700} \frac{1000}{\text{AD}700} \frac{1000}{\text{A}7000} 1$		See page 143 – 20 Wires	09 Potential 9	Separation	of Interconn	ect	(0) + (0) = (0) (advisory-related subset)	Including Normal Battery Depletion	0.1	99.5 +0.1/-0.2	98.7 +0.2/-0.3	0.5		1.5	22.2 +2.0/-1.9	12.3 +2.0/-1.9 at 86 mo		
Kapa 700 Kar701, Kar703, Jan-99 55,100 6,000 5,100 6,000 5,100 6,000 5,100 6,000 9,90 9,90 9,00 100,0 100,0 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00 9,00		<u>See page 149</u> – Pt Pacemakers with N	erformance n Measurement	ote on Dua Lock-up EF	ll Chamber 81													
See page 13 - 2009 Potential Separation of Interconnect (17) (10) (17) (10) (17) Normal Battery Nerwal Battery 99.9 97.0 93.5 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6 93.6	Kappa 700 SR		Jan-99	55,100	6,000	5,100	 +	Excluding Normal Battery Depletion	0.	100.0 +0.0/-0.0	100.0 +0.0/-0.0	0	0.	0	9.9 +0.0/-0.0	0.1	99.8 +0.1/-0.1 at 115 mo	
Kappa 800 KDR801, KDR803 Jan-02 4,300 540 736 3 + 0 = 3 + 0 = 3 + 0 = 3 + 0 = 3 + 0 = 3 + 0 = 3 + 0 = 3 + 0 = 3 + 0 = 3 + 0 = 3 + 0 = 3 + 0 = 3 + 0 = 3 + 0 = 3 + 0 = 3 + 0 = 3 + 0 = 3 + 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0	Soi	See page 143 – 200 Wires	09 Potential 5	Separation	of Interconn	ect	= (0) +	Including Normal Battery	-0.0	-0.1		98.5 +0.1/-0.1	-0.2		-0.5		9.1 +1.3/-1.2 at 115 mo	
Kapa 800 KDR801, KDR803 Jan-02 4,300 540 736 3 + 0 = 3 Kulting 100.0 100.0 100.0 100.0 999 999 999 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20 901/20	urce						(advisory-related subset)											
See page 149 Performance note on Dual Chamber Including 100.0 99.6 99.4 98.6 95.5 87.6 64.8 Pacemakers with Measurement Lock-up ERI Depletion +0.0/-0.0 +0.1/-0.2 +0.1/-0.2 +0.3/-0.4 +0.6/-0.7 +1.1/-1.2 +1.9/-1.2			Jan-02	4,300	540	736	" 0 +	Excluding Normal Battery Depletion	0.		100.0 +0.0/-0.0	0	O.	0.	99.9 +0.1/-0.2	0.2	99.9 +0.1/-0.2 at 109 mo	
	nic Devi	See page 149 – Pt Pacemakers with N	erformance n Measurement	Lock-up EF	ll Chamber 81			Including Normal Battery Depletion			99.6 +0.1/-0.2	0.3			87.6 +1.1/-1.2	6.1	23.8 +2.7/-2.6 at 109 mo	

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Device Survival Probability (%)

Malfunctions

Model Zurst Model Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registrered Registre
w ← = ∠ 26,100 19,708 6,200 3,176 n 3,176 n 1,75 n Dual Chamber ~up ERI 81 75 81 75 81 75 81 75 81 75 81 0tential Separation 1,500 1,500 2,779 otential Separation 2,700 n Dual Chamber cup ERI 81
Kappa 900 KSR901, konote Jan-02 125,200 26,100 19, konote SR Kappa 900 KSR901, konote Jan-02 125,200 26,100 19, konote SR Kappa 900 KSR901, konote Jan-02 37,000 6,200 3,1 SR Kappa 900 KSR901, konote Jan-02 37,000 6,200 3,1 Ginterconnect Wires Advisories: See page 143 - 2009 Potential Separati Advisories 8 8 Kappa 900 KVDP901 Jan-02 6,00 3,1 9 9 Kappa 900 KVDP901 Jan-02 6,00 7 8 8 Kappa 900 KVDP901 Jan-02 6,00 7 8 8 Kappa 900 KVDP901 Jan-02 6,00 7 8 8 Kappa 900 KVDP901 Jan-02 16,00 1,00 2,009 1,00 2,000 Kappa 900 KVDP901 Jan-02 1,500 7 8 8 1,000 1,500 2,100 2,100 2,100 2,1 Kappa 920

Device Survival Summary continued

continued

Source: Medtronic Device Registration and Returned Product Analysis Data as of March 12, 2013

Medtronic CRDM Product Performance Report 71 www.medtronic.com/CRDMProductPerformance

		14 yr			99.5 +0.1/-0.2 at 145 mo	42.6 +3.3/-3.4 at 145 mo	99.7 +0.1/-0.2 at 150 mo	59.6 +3.2/-3.4 at 150 mo			99.6 +0.1/-0.1 at 146 mo	58.2 +2.4/-2.5 at 146 mo
		12 yr			99.5 +0.1/-0.2	48.8 +2.6/-2.6	99.7 +0.1/-0.2	65.6 +2.3/-2.4	99.4 +0.1/-0.1 at 143 mo	39.5 +1.9/-1.9 at 143 mo	99.6 +0.1/-0.1	62.7 +1.7/-1.8
		10 yr	100.0 +0.0/-0.0 at 113 mo	82.2 +5.2/-7.0 at 113 mo	99.5 +0.1/-0.2	83.5 +1.0/-1.0	99.7 +0.1/-0.2	86.6 +1.1/-1.2	99.4 +0.1/-0.1	83.6 +0.4/-0.5	99.7 +0.1/-0.1	85.8 +0.7/-0.7
		8 yr	100.0 +0.0/-0.0	93.7 +2.6/-4.3	99.6 +0.1/-0.2	94.3 +0.5/-0.6	99.7 +0.1/-0.2	95.2 +0.6/-0.7	99.6 +0.1/-0.1	95.1 +0.2/-0.2	99.7 +0.1/-0.1	95.6 +0.3/-0.3
		7 yr	100.0 +0.1/-0.1	97.0 +1.5/-3.1	99.8 +0.1/-0.2	97.3 +0.3/-0.4	99.8 +0.1/-0.2	97.2 +0.4/-0.5	99.7 +0.0/-0.0	97.7 +0.1/-0.1	99.8 +0.0/-0.1	97.5 +0.2/-0.2
		6 yr	100.0 +0.0/-0.1	98.8 +0.8/-2.0	99.9 +0.1/-0.2	98.8 +0.2/-0.2	99.9 +0.1/-0.2	98.6 +0.3/-0.3	9.9 +0.0/-0.0	98.8 +0.1/-0.1	9.9 +0.0-/0.0+	98.6 +0.1/-0.1
(9		5 yr	100.0 +0.0/-0.1	98.8 +0.8/-2.0	99.9 +0.0/-0.1	99.4 +0.1/-0.2	99.9 +0.0/-0.1	99.2 +0.2/-0.2	99.9 +0.0/-0.0	99.3 +0.1/-0.1	100.0 +0.0/-0.0	99.2 +0.1/-0.1
ability (9		4 yr	100.0 +0.0/-0.0	99.6 +0.3/-1.3	100.0 +0.0/-0.0	99.7 +0.1/-0.1	100.0 +0.0/-0.0	99.7 +0.2/-0.2	9.99 +0.0/-0.0	99.6 +0.0/-0.0	100.0 +0.0/-0.0	99.5 +0.1/-0.1
al Proba	ıplant	3 yr	100.0 +0.0/-0.0	99.6 +0.3/-1.3	100.0 +0.0/-0.0	99.9 +0.1/-0.1	100.0 +0.0/-0.0	99.8 +0.1/-0.1	100.0 +0.0/-0.0	99.8 +0.0/-0.0	100.0 +0.0/-0.0	99.7 +0.0/-0.1
Device Survival Probability (%)	Years After Implant	2 yr	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	9.99 +0.0/-0.1	100.0 +0.0/-0.0	99.9 +0.1/-0.1	100.0 +0.0/-0.0	9.99 +0.0/-0.0+	100.0 +0.0/-0.0	9.99 +0.0/-0.0
Devic	Years	1 yr	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	9.99 +0.0/-0.1	100.0 +0.0/-0.0	9.99 +0.0/-0.0+	100.0 +0.0/-0.0	9.9 +0.0/-0.0
			Excluding al Battery Depletion	Including al Battery Depletion	Excluding al Battery Depletion	Including Ial Battery Depletion	ding ttery etion	Including al Battery Depletion	ding tery tion	ding tery tion	ding ttery stion	Including Ial Battery Depletion
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
Malfunctions	npromised rtion Not perion Not perionised	an An An	0 + 0 = 0 Excl. NormalBa Depl	(0) + (0) = Incluindlation (advisory-related subset) Depletion	23 + 12 = 35 Exclu Normal Bar Depic	(21)+(1)=(22)Indu(advisory-related subset)Normal Bach	13 + 0 = 13 Exclu Normal Bar Deple	(13)+(0)=Inclu(13)Normal Bar(advisory-related subset)Depleted	187 + 58 = 245 Exclui Normal Bat Deple	(163) + (7) = (170) Indu (advisory-related subset) Deple	+ 11 = 52 Norm	+ (4) = (41) Norm isory-related subset)
Malfunctions	rapy iction Not bəsimorqn	Acti Imp Jor Jor A A Con The The The The The Con	+ 0 = 0	(0) + (0) = (0) Norm (advisory-related subset) 1	828 23 + 12 = 35 Norm	ation (21) + (1) = (22) Norm (advisory-related subset)	397 13 + 0 = 13 Norm	(13) + (0) = (13) Norm (advisory-related subset)	3,874 187 + 58 = 245 Norm	ation (163) + (7) = (170) Norm (advisory-related subset)	1,243 41 + 11 = 52 Norm	tion (37) + (4) = (41) Norm
Malfunctions	ive US shants mal Battery srapy npromised npromised npromised	USI Esti Acti Imp Dep Fun Con Con Fun Con	830 110 26 0 + 0 = 0 Norm	(0) + (0) = (0) Norm (advisory-related subset) 1	15,900 3,300 828 23 + 12 = 35 Norm	ation (21) + (1) = (22) Norm (advisory-related subset)	12,100 1,800 <u>397</u> 13 + 0 = 13 _{Norm}	(13) + (0) = (13) Norm (advisory-related subset)	106,600 30,000 3,874 187 + 58 = 245 Norm	ation (163) + (7) = (170) Norm (advisory-related subset)	54,000 10,800 1,243 41 + 11 = 52 Norm	tion (37) + (4) = (41) Norm
Malfunctions	mplants mated ive US mal Battery mpromised mpromised mpromised	Reid Reg USI Esti The Fun Con The Fun Con	110 26 0 + 0 = 0 Norm	(0) + (0) = (0) Norm (advisory-related subset) 1	3,300 828 23 + 12 = 35 Norm	ation (21) + (1) = (22) Norm (advisory-related subset)	1,800 397 13 + 0 = 13 Norm	(13) + (0) = (13) Norm (advisory-related subset)	Aug-99 106,600 30,000 3,874 187 + 58 = 245 Norm	ation (163) + (7) = (170) Norm (advisory-related subset)	10,800 1,243 41 + 11 = 52 Norm	tion (37) + (4) = (41) Norm
Malfunctions	mber Market mplants mal Battery market mpromised mpromised mpromised mpromised mpromised	US I Reg US I Esti Inp Dep Fun Con The Fun Con	830 110 26 0 + 0 = 0 Norm	Norm	15,900 3,300 828 23 + 12 = 35 Norm	(1) = (22) Norm related subset) 1	12,100 1,800 <u>397</u> 13 + 0 = 13 _{Norm}	(0) = (13) Norm related subset)	106,600 30,000 3,874 187 + 58 = 245 Norm	Norm	54,000 10,800 1,243 41 + 11 = 52 Norm	+ (4) = (41) Norm isory-related subset)

continued

Device Survival Summary continued

		16 yr						
		14 yr						
		12 yr	98.8 +0.7/-2.0 at 124 mo	61.2 +5.3/-5.9 at 124 mo				
		10 yr	98.8 +0.7/-2.0	63.4 +5.1/-5.6				
		8 yr	99.2 +0.5/-1.2	93.2 +1.8/-2.4				
		7 yr	99.8 +0.2/-0.9	96.6 +1.2/-1.8	100.0 +0.0/-0.0 at 77 mo	98.3 98.1 +0.2/-0.2 +0.3/-0.3 at 77 mo		
		6 yr	100.0 +0.0/-0.0	99.1 +0.5/-1.1	100.0 +0.0/-0.0			
()		5 yr	100.0 +0.0/-0.0	99.7 +0.2/-0.9	100.0 +0.0/-0.0	99.2 +0.1/-0.1		
bility (%		4 yr	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.7 +0.0/-0.1		
Device Survival Probability (%)	plant	3 yr	100.0 100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0 +0.0/-0.0	99.9 +0.0/-0.0 +0.0/-0.0	99.9 +0.0/-0.1 at 25 mo	99.8 +0.1/-0.1
e Surviv	Years After Implant	2 yr		100.0 +0.0/-0.0			99.9 +0.0/-0.1	99.8 +0.1/-0.1
Device	Years	1 yr	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.9 +0.0/-0.0
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Doulotion
	le	toT	-	(1)	: 15	lbset)	17	
ions	rapy ction Not npromised		= 0	= 0	=	(advisory-related subset)	16 =	
Malfunction	ction npromised	uoj	+	+	+	isory-re	+	
Ma	(de)	эчт				≥		
L			-	of (1)	9	(ac	-	
	nal Battery Jetions	Dep	67 1		164 6		0	
E	snoitel	Acti Imp Nor Dep	81 67 1				50,300 0 1	
E	ve US lants letions	US I Esti Acti Imp Mor Dep			164			
E	mplants ve US lants lants letions	Rele NSU I SU Acti Imp Imp	81		71,700 164		50,300	
E	nber Market istered mplants ve US lants lants lants	USU Rege Reg USU USU Acti PCP PCP PCP PCP PCP PCP PCP PCP PCP PC	650 81	Advisories: <u>See page 147</u> – 2005 Potential Separation of (1 Interconnect Wires	93,900 71,700 164	See page 149 Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI (ac	52,000 50,300	

Source: Medtronic Device Registration and Returned Product Analysis Data as of March 12, 2013

Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The longevity estimates shown here assume a lower rate of 60 ppm, 100% pacing, and pulse width of 0.4 ms unless noted otherwise. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates. The elective replacement time is indicated via telemetry indication, and rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet), unless noted otherwise.

		Estimated L	ongevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Adapta DR	ADDR01, ADDR03, ADDR06, ADD01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.4 6.0 4.5	8.2 7.4 6.0	**
Adapta DR	ADDRS1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.3 3.2	6.1 5.4 4.4	**
Adapta DR	ADDRL1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.0 7.3 5.4	10.0 8.9 7.2	**
Adapta SR	ADSR01, ADSR03, ADSR06	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.5 5.1	7.9 7.5 6.3	**
Adapta VDD	ADVDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.5 4.4	6.5 6.2 5.4	**
AT500	AT501, 7253	Low 2.0 V (A, RV) Nominal 3.0 V (A, RV) High 5.0 V (A, RV)	7.7 5.8 3.7	8.3 7.0 5.2	Telemetry indication. Pacing mode and rate (magnet and non-magnet) as programmed.
Advisa DR	A4DR01, A5DR01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.3 3.2	6.1 5.4 4.4	**
Advisa DR MRI+C82	A3DR01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**
EnPulse DR	E1DR01, E1DR03, E1DR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**
EnPulse DR	E1DR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**
EnPulse 2 DR	E2DR01, E2DR03, E2DR06, E2D01, E2D03	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**
EnPulse 2 DR	E2DR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**
EnPulse 2 DR	E2DR31, E2DR33	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.0 7.4 5.2	10.1 9.1 7.1	**
EnPulse 2 SR	E2SR01, E2SR03, E2SR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.2 6.3 4.8	7.7 7.3 6.1	**
EnPulse 2 VDD	E2VDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.1 5.5 4.3	6.5 6.2 5.4	**
EnRhythm DR	P1501DR	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.7 7.3 4.9	11.2 9.4 7.1	**
EnRhythm MRI	EMDR01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.1 5.5 4.3	6.5 6.2 5.4	**

**Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).

continued

Reference Chart continued

		Estimated Lo	ongevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Ensura MRI	EN1DR01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.3 3.2	6.1 5.4 4.4	**
Kappa 400 DR	KDR401, KDR403	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.8 6.4 5.1	8.5 7.5 6.5	**
Kappa 400 SR	KSR401, KSR403	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.9 6.9 5.8	8.4 7.7 7.0	**
Kappa 700 D	KD701, KD703, KD706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR701, KDR703, KDR706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR721	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.2	**
Kappa 700 SR	KSR701, KSR703, KSR706	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.5 4.9	7.9 7.5 6.2	**
Kappa 800 DR	KDR801, KDR803	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 900 DR	KDR901, KDR903, KDR906	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 920 DR	KDR921	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.3	**
Kappa 900 SR	KSR901, KSR903, KSR906	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 4.9	7.9 7.4 6.1	**
Kappa 900 VDD	KVDD901	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.4	**
Prodigy SR	8158, 8160, 8161, 8162	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Sensia DR	SEDR01, SED01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.4 6.0 4.5	8.2 7.4 6.0	**
Sensia SR	SESR01, SES01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.5 5.1	7.9 7.5 6.3	**
Sigma 100 S	SS103, SS106	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**

 ** Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).

continued

Reference Chart continued

		Estimated Lo	ongevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Sigma 200 DR	SDR203	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 200 SR	SSR203	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 DR	SDR303, SDR306	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 300 SR	SSR303, SSR306	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 VDD	SVDD303	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	8.9 7.3 5.8	9.7 8.6 7.4	**
Versa DR	VEDR01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.4 6.0 4.5	8.2 7.4 6.0	**
Revo MRI SureScan	RVDR01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.7 7.3 4.9	11.2 9.4 7.1	**

 ** Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).

Method for Estimating Lead Performance

Medtronic CRDM has tracked lead survival for over 29 years with its multicenter, global chronic lead studies.

Leads Performance Analysis

Implanted leads operate in the challenging biochemical environment of the human body and the body's response to foreign objects. Implanted leads are also subject to mechanical stresses associated with heart motion, body motion, and patient anatomy.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. While IPGs and ICDs have a battery that will deplete after a predictable length of time, a lead's longevity cannot be predicted, nor are there simple indicators that a lead is approaching the end of its service life. Therefore, regular monitoring while implanted, and evaluation of lead integrity upon IPG or ICD replacement, is necessary to determine if a lead may be approaching the end of its service life.

Shortfalls of Using Returned Product and Complaints to Estimate Lead Performance

All leads and lead segments returned to Medtronic are analyzed to determine whether or not they meet performance limits established by Medtronic. Although returned product analyses are valuable for gaining insight into lead failure mechanisms, this data cannot be used by itself for determining the survival probability of leads because only a small fraction of leads are explanted and returned for analysis. Additionally, those leads that are returned cannot be assumed to be statistically representative of the performance of the total population for a given lead model. Partial or total lead extraction can result in significant damage to a lead, making a definitive analysis of a suspected failure, and its cause, impossible.

To account for the under reporting inherent with lead survival analysis based solely on returned product, some manufacturers add reported complaints where adverse product performance is evident but the product itself has not been returned. The improvement to the accuracy of survival estimates depends on the degree to which all complaints are actually communicated to the manufacturer. Since not all complaints are communicated to the manufacturer, adding complaints to the survival analysis does not completely solve the under reporting problem.

Thus, lead survival probabilities are more appropriately determined through a clinical surveillance study that includes active follow-up with the patients. Although Medtronic monitors returned product analysis and complaints, these are not used to determine lead survival estimates. Medtronic tracks lead survival through its Product Surveillance Registry. The registry is designed to record clinical observations representative of the total clinical experience. Therefore, the lead survival estimates include both lead hardware failure and lead-related medical complications, and do not differentiate a lead hardware failure from other clinical events such as exit block, perforation, dislodgement, or concurrent pulse generator failure. The lead need not be returned to Medtronic.

Product Surveillance Registry (PSR)

Medtronic has been monitoring the performance of its cardiac therapy products with a multicenter study since 1983 and has evaluated the performance of more than 95,000 leads, with data reported from countries around the world. Throughout this time period, Medtronic has continually worked to adapt systems and processes to more effectively monitor product performance following market release. The following summarizes current registry requirements.

Medtronic's global Product Surveillance Registry has a prospective, non-randomized, observational design. A key purpose of the registry is to provide continuing evaluation and periodic reporting of the long-term reliability and performance of Medtronic marketreleased cardiac therapy products. Product-related adverse events, indicating the status of the product, are collected to measure survival probabilities. The data gathered may also be used to support the design and development of investigational plans for new cardiac therapy products. The registry is designed to continue indefinitely, encompassing new products as they become commercially available.

To ensure a sufficiently large and representative source of data, participating clinical sites must meet pre-specified selection criteria. The number of participants is regularly reviewed to ensure the necessary capacity to meet Medtronic's ongoing prospective post-market surveillance needs is available. Every effort is made to ensure participants are representative of the range of clinical environments in which Medtronic cardiac rhythm products are used. Eligible products for enrollment include Medtronic market-released cardiac rhythm therapy products for which additional information to further characterize product performance following market release is desired. Enrollment may be capped at a product when the number enrolled ensures sufficient precision to effectively characterize product survivability.

continued

The Standard Actuarial Method is used to determine estimates of lead survival.

Enrolled patients are followed in accordance with the standard care practices of their care provider from their implant date until they can no longer be followed (e.g., death, lost to follow-up, etc.). However, to ensure regular patient status assessments are completed, follow-up windows consistent with typical care practices have been established with a minimum annual follow-up requirement. Product-related adverse events, system modifications and changes in patient status (e.g., death and withdrawal from the study) are required to be reported upon occurrence. This active surveillance model ensures a robust dataset for effectively monitoring product performance.

Patients are eligible for enrollment if:

- They are intended to be implanted or are within 30 days post-implant of a Medtronic market-released lead connected to a market-released CRT, ICD, or IPG device, and the lead is used for a pacing, sensing, or defibrillation application, or
- They participated in a qualifying investigational study of a Medtronic cardiac therapy product that is now market-released; complete implant and follow-up data are available; and the data can be appropriately and legally released.

Each site must inform Medtronic whenever a lead complication has occurred or when a patient is no longer participating. Chronic product performance is analyzed as a function of time using the survival analysis method.

Medtronic continually evaluates the quality and integrity of the data through a combination of on-site and centralized monitoring activities.

Lead Complications

The data presented characterizes chronic lead performance by estimating lead-related complicationfree survival probabilities. For analysis purposes, the complication criteria, which align with the AdvaMed 'Industry Guidance for Uniform Reporting of Clinical Performance of Cardiac Rhythm Management Pulse Generators and Leads', are defined below. These criteria do not, however, enable a lead integrity or "hardware" failure to be conclusively differentiated from other clinical events such as an undetected lead dislodgement, exit block, or concurrent pulse generator failure manifested as a sensing or capture problem. All reported lead-related adverse events are classified by the reporting investigator and are adjudicated by an independent event adjudication committee.¹ A leadrelated complication is considered to have occurred if a clinical observation occurs more than 30 days after implant, is adjudicated with at least one of the following event classifications and at least one of the following clinical actions is made. Events with an onset date 30 days or less after the implant are considered procedure-related and therefore not included as chronic lead-related complications.

Event Classifications

- Failure to capture
- Failure to sense/undersensing
- Oversensing
- Abnormal pacing impedance (based on lead model, but normal range is typically 200 2,000 ohms)
- Abnormal defibrillation impedance (based on lead model, but normal range is typically 20 200 ohms)
- Insulation breach
- Conductor fracture, confirmed electrically, visually or radiographically
- Extracardiac stimulation
- Cardiac perforation
- Lead dislodgement

Clinical Actions

- Lead surgically abandoned/capped
- Lead electrically abandoned
- Lead explanted
- Lead replaced
- Lead conductor taken out of service (polarity reprogrammed to remove defective conductor, e.g., bipolar to unipolar)

continued

¹During the evolution of PSR, event adjudication was transitioned from a Medtronic technical review committee to an independent event adjudication committee in 2011. Data analyses include adjudication using both methods.

- Lead use continued based on medical judgment despite a known clinical performance issue
- Other lead-related surgery performed (e.g., lead mechanical alteration or unsuccessful repositioning)

Note: Successful lead repositioning is not a qualifying action.

Data Analysis Methods

The performance of leads is expressed in terms of lead survival estimates, where "survival" refers to the function of the lead, not the survival of the patient. These survival estimates are intended to illustrate the probability that a lead will survive for a given number of years without a chronic lead-related complication.

Survival times are calculated from the implant date to the earliest of the complication date, out-of-service date (for example, subject leaves the study or the lead is no longer being used) or the last follow-up date. If a lead experiences more than one complication, the first is used to calculate survival time; although all complications associated with a lead are included in the summary tables.

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed across the intervals (Cutler-Ederer Method), is used to determine estimates of lead survival.

On the following pages, each graph includes a survival curve where events include qualifying lead-related complications. This survival estimate is a good representation of the probability a lead will survive a period of time without a lead-related complication. For example, if a survival probability is 95% after 5 years of service, then the lead has a 5% chance of experiencing a lead-related complication in the first 5 years following implant.

Although tabular data is provided in 1-year intervals, the curves are actually computed and plotted using 3-month intervals.

The data in the tables is rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have one or more complications. This occurs because even with the complications, the data rounds to 100%. The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way to indicate the degree of certainty of the estimates. Greenwood's formula is used to calculate the standard errors, and the log-log method is used to produce the 2-sided 95% confidence bounds.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the number of leads entering an interval is less than 50 leads. When the number of leads entering an interval reaches 50, the next data point is added to the survival curve. For those lead models that do not have sufficient sample size, a survival curve will not be presented.

Definition of Analysis Dataset

The survival estimates are derived from all device components successfully enrolled as of the data cutoff date. The number of enrollments is listed for each lead model.

This sample is considered to be representative of the worldwide population, and therefore the survival estimates shown should be representative of the performance worldwide of these models.

Criteria for Model Inclusion

Performance information for a model or model family will be published when more than 100 leads have been enrolled and no fewer than 50 leads followed for at least 6 months. Models will continue to be published for at least 20 years as long as Medtronic estimates at least 500 leads remain active in the United States, based on estimated US implants.

Medtronic, at its discretion, may stop providing updated performance information on lead models that received original US market-release approval 20 or more years ago.

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

Returned Product Analysis Results

Every lead or lead portion returned to Medtronic receives an analysis. Although the returned product analysis data is not used to generate the survival estimates, the data provides valuable insight into the causes of lead malfunction.

For reporting returned product analysis results, Medtronic CRDM considers a lead as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction for returned product analysis reporting, the lead must have been returned to Medtronic and analyzed.

The results of the analysis is presented in four categories. The lead reporting categories are:

- Conductor Fracture: Conductor malfunction with complete or intermittent loss of continuity that could interrupt current flow (e.g., fractured conductors), including those associated with clavicle flex fatigue or crush damage.
- Insulation Breach: A malfunction of the insulation allowing inappropriate entry of body fluids or inappropriate current flow between the conductors, or between the conductor and the body. Examples include cuts, tears, depressions, abrasions, and material degradation.
- Crimps/Welds/Bonds: Any malfunction in a conductor or lead body associated with a point of connection.
- Other: Malfunctions of specific lead mechanical attributes, such as sensors, connectors, seal rings, or malfunction modes not included in the three categories above.

A lead subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic.

For leads designed for either ventricular or atrial use, the numbers listed in the Returned Product Analysis tables include both.

The numbers of malfunctions listed in the Returned Product Analysis tables are the actual numbers confirmed in the returned product analysis from the United States. The numbers of complications listed in the complications tables are the actual numbers observed in the PSR centers around the world.

US Reports of Acute Lead Observations (Occurring within First Month of Service)

In the first weeks following lead implantation, physiologic responses and lead performance can vary until longterm lead stability is attained. Acute (defined as the first month after implant) lead performance may be subject to a number of factors, including patient-specific anatomy, clinical conditions and/or varying implant conditions/ techniques. After a period of time, the implant and the lead performance stabilizes. It is for this reason that the Product Surveillance Registry results, which are intended to measure long-term performance, do not include complications that occur within the first 30 days after implant.

Information about the clinical experience in the first month of service is included in this report. The source for this information is Medtronic's complaint handling system database. The information is summarized in tables titled "US Reports of Acute Lead Observations." To be included in this summary of observations, a lead must first be successfully implanted and registered in Medtronic's Device and Registrant Tracking system.

Each Event Report received by Medtronic's complaint handling system is assigned one or more Reason for Report codes based on the information received. The Reason for Report codes have been grouped into Acute Lead Observation categories. The categories used for this product performance report are drawn from the "FDA Guidance for Submission of Research and Marketing Applications for Permanent Pacemaker Leads and for Pacemaker Lead Adapter 510(k) Submissions." The categories are:

- 1. Cardiac Perforation
- 2. Conductor Fracture
- 3. Lead Dislodgement
- 4. Failure to Capture
- 5. Oversensing
- 6. Failure to Sense
- 7. Insulation Breach
- 8. Impedance Abnormal

9. Extracardiac Stimulation

10. Unspecified

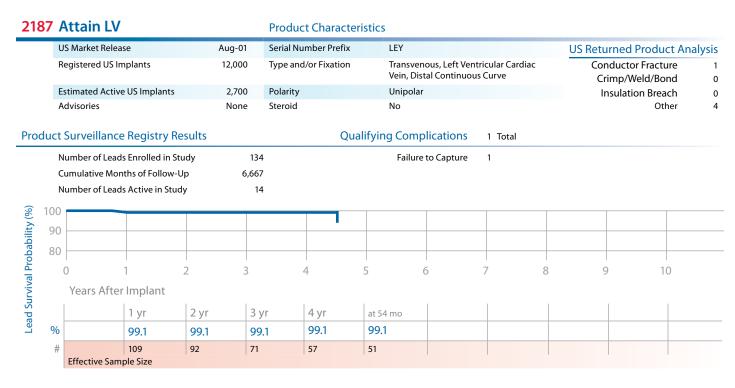
Although multiple observations are possible for any given lead, only one observation is reported per lead. The observation reported is the observation highest on the list. For example, if an Event Report includes observations for both Lead Dislodgement and Failure to Sense, Lead Dislodgement is reported.

The lead event reported to Medtronic may or may not have involved clinical action or product returned to Medtronic. The lead may have remained implanted and in service.

Estimated Number of Implanted and Active Leads in the United States

In addition to providing the number of leads enrolled in the PSR, this report also provides the number of leads registered as implanted and the number remaining active in the United States based on the status recorded in the Medtronic Device and Registrant Tracking system.

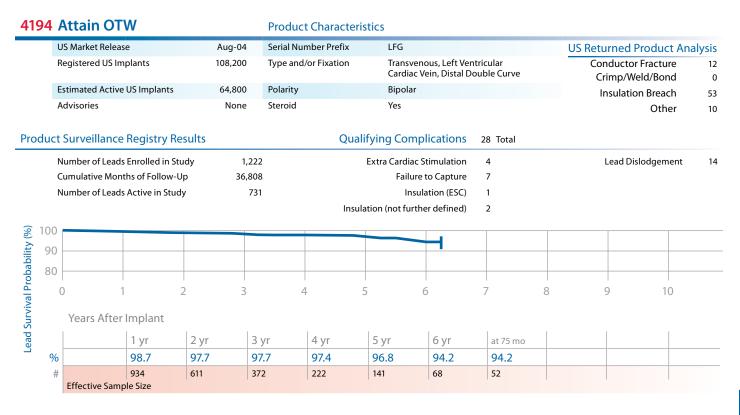
Some lead models do not have a survival curve presented in this report. These lead models do not have a survival curve because they have insufficient sample size in the Product Surveillance Registry. Returned Product Analysis results for these models are included here for reference and comparison.



4193 Attain OTW

U	JS Market Releas	e	м	lay-02	Serial Numb	oer Prefix	BAA			U	S Returned Pro	duct Ana	alysi
R	Registered US Im	plants	10	100,700 Type and/or F		r Fixation		venous, Left Ven Double Curve	ac Vein,	^{n,} Conductor Fracture Crimp/Weld/Bond			
E	stimated Active	US Implants	3	35,000 Polarit			Unipo	olar			Insulation Breach		
A	Advisories			None	Steroid		Yes				(Other	1
oduct	Surveillance	Registry R	esults			Qua	lifying Cor	nplications	38 Total				
N	Number of Leads	Enrolled in St	tudy	675			Cond	uctor Fracture	1		Lead Dislod	gement	1
C	Cumulative Mont	ths of Follow-	Up	30,442			Extra Cardi	ac Stimulation	8		Unspecified Clinica	l Failure	
N	Number of Leads Active in Study			123			Fail	ure to Capture	12				
100													
90													
100 90 80													
	0 1	1	2	3	4		5	б	7	8	9	10	
	Years After	Implant											
		1 yr	2 yr	З у	r 2	1 yr	5 yr	6 yr	7 yr	8 yr	at 99 mo		
%		95.9	95.0	94	.3 9	94.3	93.8	93.3	93.3	92.3	92.3		
#		545	437	358	3 2	275	203	145	99	57	44		
	Effective Samp	ole Size											

Left-Heart Leads



4195 Attain StarFix

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96	5 Attain Ability		Product Characteris	tics					
	US Market Release	May-09	Serial Number Prefix	PVI		US Returned Product Analysis			
	Registered US Implants	48,600	Type and/or Fixation	Transvenous, Left Ven Preformed Body, Dou		Conductor Fracture Crimp/Weld/Bond			
	Estimated Active US Implants	40,500	Polarity	Bipolar		Insulation Breach			
	Advisories	None	Steroid	Yes		Other			
duo	ict Surveillance Registry Results		Quali	fying Complications	38 Total				
	Number of Leads Enrolled in Study	1,876		Conductor Fracture	1	Lead Dislodgement	1		
					12				
	Cumulative Months of Follow-Up	34,965		Extra Cardiac Stimulation	12				
	Cumulative Months of Follow-Up Number of Leads Active in Study	34,965 1,300		Extra Cardiac Stimulation Failure to Capture	12				
10	Number of Leads Active in Study								
10	Number of Leads Active in Study								
9	Number of Leads Active in Study								
9	Number of Leads Active in Study	1,300		Failure to Capture					
9	Number of Leads Active in Study			Failure to Capture		9 10			
9	Number of Leads Active in Study	1,300		Failure to Capture		9 10			
9	Number of Leads Active in Study	1,300	4 5	Failure to Capture		9 10			
91	Number of Leads Active in Study	1,300	4 5	Failure to Capture		9 10			

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	US Market Rele	ase	Apr-11	Serial Number P	refix	RRA		US Returned Product A	nalys	
	Registered US	Implants				Transvenous, Left Ver Distal Double Curve	itricular Cardiac Vein	, Conductor Fracture Crimp/Weld/Bond		
	Estimated Activ	ve US Implants	11,300 Polarity			Bipolar		Insulation Breach		
	Advisories		None	Steroid		Yes		Other		
oduc	t Surveilland	e Registry Results			Qualifyi	ng Complications	2 Total			
	Number of Lea	ds Enrolled in Study	672	2		Lead Dislodgement	2			
	Cumulative Mo	onths of Follow-Up	2,876	i						
	Number of Lea	ds Active in Study	618							
	-									
10(
90	0									
8(0 0									
	0	1 2	3	4	5	6	7 8	9 10		
10(9(8(Vears Afte	er Implant								
	at 9 mo									
	99.5									
;	# 87									

L L	US Market Release	Mar-11	Serial Number Pr	efix	RAE		US Return	US Returned Product Analysi				
F	Registered US Implants	2,800	Type and/or Fixat	tion	Transvenous, Left Ven Tines	tricular Cardiac Vein,	Condu	ictor Fracture p/Weld/Bond	(
E	Estimated Active US Implants	2,600	Polarity		Bipolar			lation Breach	0			
ŀ	Advisories	None	Steroid		Yes			(
duct	t Surveillance Registry Results			Qualifyin	g Complications	0 Total						
١	Number of Leads Enrolled in Study	178	3									
C	Cumulative Months of Follow-Up	1,517	7									
1	Number of Leads Active in Study	161										
100												
100												
90												
80		3	4	5	6	7 8	9	10				
	0 1 2	5										
		5										
	0 1 2 Years After Implant	5	·									
				-								
	Years After Implant											

Lead Survival Summary (95% Confidence Interval)

	ISE		Study		iths of idy	Device	Survival	Probabi	lity (%)						
	t Relea	olled	ive in 9	Qualifying Complications	Cumulative Mor Follow-Up in Stu	Years After Implant									
Family		Leads Enr	Leads Act			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr
Attain LV	Aug-01	134	14	1	6,667	99.1 +0.8/-5.1	99.1 +0.8/-5.1	99.1 +0.8/-5.1	99.1 +0.8/-5.1	99.1 +0.8/-5.1 at 54 mo					
Attain OTW	May-02	675	123	38	30,442	95.9 +1.3/-1.8	95.0 +1.4/-2.1	94.3 +1.6/-2.3	94.3 +1.6/-2.3	93.8 +1.8/-2.4	93.3 +2.0/-2.7	93.3 +2.0/-2.7	92.3 +2.5/-3.7	92.3 +2.5/-3.7 at 99 mo	
Attain OTW	Aug-04	1,222	731	28	36,808	98.7 +0.6/-0.8	97.7 +0.8/-1.2	97.7 +0.8/-1.2	97.4 +0.9/-1.3	96.8 +1.3/-2.1	94.2 +2.6/-4.4	94.2 +2.6/-4.4 at 75mo			
Attain StarFix	Aug-08	1,231	963	12	23,520	99.2 +0.4/-0.9	98.6 +0.7/-1.1	98.3 +0.8/-1.4	98.3 +0.8/-1.4	98.3 +0.8/-1.4 at 57 mo					
Attain Ability	May-09	1,876	1,300	38	34,965	98.3 +0.5/-0.8	97.5 +0.7/-1.0	97.0 +0.9/-1.3							
Attain Ability Plus	Apr-11	672	618	2	2,876	99.5 +0.4/-1.8 at 9 mo									
Attain Ability Straight	Mar-11	178	161	0	1,517	100 .0 at 9 mo									
	Attain LVAttain OTWAttain OTWAttain StarFixAttain AbilityAttain Ability PlusAttain Ability	Attain LVAug-01Attain OTWMay-02Attain OTWAug-04Attain StarFixAug-08Attain AbilityMay-09Attain AbilityApr-11Ability PlusMar-11Attain AbilityMar-11	Attain LVAug-01134Attain OTWMay-02675Attain OTWAug-041,222Attain StarFixAug-081,231Attain AbilityMay-091,876Attain AbilityApr-11672Attain AbilityMar-11178	Attain LVAug-0113414Attain OTWMay-02675123Attain OTWAug-041,222731Attain StarFixAug-081,231963Attain AbilityMay-091,8761,300Attain AbilityApr-11672618Attain AbilityMar-11178161	Attain LV Aug-01 134 14 1 Attain OTW May-02 675 123 38 Attain OTW Aug-04 1,222 731 28 Attain OTW Aug-04 1,222 731 28 Attain StarFix Aug-08 1,231 963 12 Attain Ability May-09 1,876 1,300 38 Attain Ability Plus Apr-11 672 618 2 Attain Ability Mar-11 178 161 0	Attain LV Aug-01 134 14 1 6,667 Attain OTW May-02 675 123 38 30,442 Attain OTW Aug-04 1,222 731 28 36,808 Attain OTW Aug-04 1,222 731 28 36,808 Attain StarFix Aug-08 1,231 963 12 23,520 Attain Ability May-09 1,876 1,300 38 34,965 Attain Ability Plus Apr-11 672 618 2 2,876 Attain Ability Mar-11 178 161 0 1,517	Attain LV Aug-01 134 14 1 6,667 99.1 99.1 +0.8/-5.1 Attain OTW May-02 675 123 38 30,442 95.9 +1.3/-1.8 Attain OTW Aug-04 1,222 731 28 36,808 98.7 +0.6/-0.8 Attain OTW Aug-08 1,231 963 12 23,520 99.2 +0.4/-0.9 Attain Ability May-09 1,876 1,300 38 34,965 98.3 +0.5/-0.8 Attain Ability Plus Apr-11 672 618 2 2,876 99.5 +0.4/-1.8 at 9 mo Attain Ability Mar-11 178 161 0 1,517 100.0 at 9 mo	Attain LV Aug-01 134 14 1 6,667 99.1 99.1 +0.8/-5.1 99.1 99.1 +0.8/-5.1 99.1 90.8/-5.1 99.1 90.8/-5.1 99.1 +0.8/-5.1 91.2 95.0 +1.3/-1.8 91.2 95.0 +1.3/-1.8 97.7 +0.8/-0.8 97.7 +0.8/-1.2 97.7 +0.8/-1.2 97.7 +0.8/-1.2 97.7 +0.8/-1.2 92.2 +0.4/-0.9 98.6 +0.7/-1.1 97.5 +0.7/-1.0 98.3 +0.5/-0.8 97.5 +0.7/-1.0 98.3 +0.5/-0.8 97.5 +0.4/-1.8 at 9 mo 99.5 +0.4/-1.8 at 9 mo 99.5 +0.4/-	Attain LV Aug-01 134 14 1 6,667 99.1 +0.8/-5.1 91.2 +0.8/-1.2 94.3 +1.6/-2.3 Attain Ability Plus Aug-08 1,231 963 12 23,520 99.2 +0.4/-0.9 98.3 +0.5/-0.8 97.5 +0.7/-1.0 97.0 +0.9/-1.3 Attain Ability Plus Apr-11 672 618 2 2,876 99.5 +0.4/-1.8 at 9 mo 97.5 +0.4/-1.8 at 9 mo 97.0 +0.9/-1.3	Attain LV Aug-01 134 14 1 6,667 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 90.1 99.1 90.1 99.1 90.1 99.1 90.1 99.1 90.1 99.1 90.1 99.1 90.1 90.1 99.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 10.8/-5.1 91.1 10.8/-5.1 91.3 91.3 91.3 91.3 91.3 11.6/-2.3 91.3 91.3 91.4 10.8/-1.2 97.7 97.7 97.7 97.7 97.8 10.9/-1.3 98.3 90.5/-0.8 91.4 10.8/-1.4 98.3 10.8/-1.4 90.8/-1.4 10.8/-1.	Attain LV Aug-01 134 14 1 6,667 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 90.8 99.1 90.8 99.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 90.1 10.8/-5.1 90.1 10.8/-5.1 90.1 10.8/-5.1 91.1 16.0.8/-1.2 91.3 91.3 91.3 91.3 91.3 91.3 91.3 91.3 91.4 10.8/-1.2 91.3 91.3 91.3 91.3 91.3 92.3 90.3 90.8/-	Attain LV Aug-01 134 14 1 6,667 99.1 99.1 99.1 99.1 99.1 99.1 99.1 40.8/-5.1 99.1 99.1 40.8/-5.1 99.1 99.1 40.8/-5.1 99.1 99.1 40.8/-5.1 99.1 40.8/-5.1 99.1 40.8/-5.1 99.1 40.8/-5.1 99.1 40.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 at54 mo Attain OTW May-02 675 123 38 30,442 95.9 95.0 94.3 94.3 +1.8/-2.4 93.8 +1.8/-2.4 92.0-2.7 Attain OTW Aug-04 1,222 731 28 36,808 98.7 97.7 97.7 97.4 96.8 +1.3/-2.1 94.2 OTW Aug-08 1,231 963 12 23,520 99.2 98.6 +0.8/-1.2 98.3 +0.8/-1.4 98.3 +0.8/-1.4 at57 mo Attain Ability May-09 1,876 1,300 38 34,965 98.3 97.5 97.0 +0.8/-1.4 at57 mo +0.8/-1.4 at5	Attain LV Aug-01 134 14 1 6,667 99.1 99.1 99.1 99.1 99.1 99.1 99.1 40.8/-5.1 99.1 40.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 10.8/-5.1 11.6/-2.3 11.6/-2.3 11.6/-2.3 11.6/-2.3 11.6/-2.3 11.6/-2.3 11.8/-2.4 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.7 12.0/-2.	Attain LV Aug-01 134 14 1 6,667 99.1 91.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 90.1 31.4 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3 93.3	Attain LV Aug-01 134 14 1 6,667 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1 15.8 99.1 99.1 15.8 99.1 99.1 15.8 99.2 99.3 93.3 92.3 92.3 92.3 92.3 92.3 92.3 92.3 92.3 92.3 92.3 92.3 92.3 92.3 92.3

US Returned Product Analysis Summary

Source: Product Surveillance Registry Data as of February 1, 2013

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
2187	Attain LV	Aug-01	12,000	2,700	1	0	0	4
4193	Attain OTW	May-02	100,700	35,000	52	0	8	51
4194	Attain OTW	Aug-04	108,200	64,800	12	0	53	10
4195	Attain StarFix	Aug-08	14,500	11,500	1	0	1	4
4196	Attain Ability	May-09	48,600	40,500	5	0	0	6
4296	Attain Ability Plus	Apr-11	12,000	11,300	0	0	0	0
4396	Attain Ability Straight	Mar-11	2,800	2,600	0	0	0	0

Source: Returned Product Analysis Data as of February 1, 2013

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure to Sense		Impedance Abnormal	Extracardiac Stimulation	Unspecified
2187	Attain LV	12,000	0	0	9	3	0	1	0	0	1	0
4193	Attain OTW	100,700	0	0	44	11	1	0	0	0	16	2
4194	Attain OTW	108,200	2	2	114	34	2	0	0	6	28	5
4195	Attain StarFix	14,500	0	0	21	11	0	0	0	1	18	1
4196	Attain Ability	48,600	0	1	117	34	1	0	1	5	56	3
4296	Attain Ability Plus	12,000	0	0	35	5	0	0	1	0	8	0
4396	Attain Ability Straight	2,800	0	1	13	2	0	0	0	0	5	0

Report Cutoff Date: February 1, 2013

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
2187	Attain LV	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
4193	Attain OTW	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
4194	Attain OTW	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)/ Silicone (4719)	MP35N	Platinum Alloy	IS-1 BI
4195	Attain StarFix	Transvenous Cardiac Vein Deployable Lobes	Polyurethane (55D)	MP35N	Platinum Alloy	IS-1 UNI
4196	Attain Ability	Transvenous Cardiac Vein Preformed Body	Polyurethane (outer) SI-polyimide (inner)	Ag-core- MP35N	Platinum iridium alloy with titanium nitride coating	IS-1 BI
4296	Attain Ability Plus	Transvenous Cardiac Vein Distal Double Curve	Polyurethane (outer) Silicone (inner)	Ag-core- MP35N	Platinum iridium alloy with titanium nitride coating	IS-1 BI
4396	Attain Ability Straight	Transvenous Cardiac Vein Tines	Polyurethane (outer) Silicone (inner)	Ag-core- MP35N	Platinum iridium alloy with titanium nitride coating	IS-1 BI

Defibrillation Leads

6021 Epicardial Patch

67	21,	6921 Epi	cardial Pa	atch	Product	t Characteri	stics						
	ι	JS Market Relea	se	Feb-93	Serial Nur	nber Prefix	TBH, TBG, TBE	3, TAD, TAC, or	TAB	USI	Returned Pr	oduct Ana	lysis
	F	Registered US Im	nplants	8,800	Type and	or Fixation	Epicardial Def	fib Patch, Sutu	re		Conductor	Fracture	25
	E	stimated Active	US Implants	1,500	Polarity		Defib Electro	de only			Crimp/We	eld/Bond	0
	ŀ	Advisories		None	Steroid		No				Insulatio	n Breach	2
												Other	0
Pro	duct	Surveillance	Registry Re	sults		Qua	alifying Com	olications	47 Total				
	١	Number of Lead	s Enrolled in Stu	ıdy	407		Conduc	tor Fracture	21	Insulat	tion (not furthe	er defined)	2
	(Cumulative Mon	ths of Follow-U	p 23,	303		Failure	e to Capture	8		Ov	versensing	12
	١	Number of Lead	s Active in Stud	у	4		Impedance C	out of Range	4				
(%	100					1		1					
ity (90												
lide	80												
Lead Survival Probability (%)	70										-		
ival		0 1	2	2 3		4	5	6	7	8	9	10	
Surv								0	,	0	-	10	
ad		Years After I	mplant										
Le			1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	9 yr	at 111 m	10
	%		96.5	95.0	92.7	91.9	90.0	85.1	83.7	83.7	83.7	83.7	
	#	Effective Course	330	301	256	209	176	132	95	66	56	50	
		Effective Sam	pie Size										

6930 Sprint Fidelis

Product Characteristics

US Market Release	Sep-04	Serial Number Prefix	LFK	US Returned Product An	alysis
Registered US Implants	400	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture	3
Estimated Active US Implants	200	Polarity	True Bipolar/One Coil	Crimp/Weld/Bond	0
Advisories:		Steroid	Yes	Insulation Breach	0
See page 145 – 2007 Potential Co Wire Fracture	onductor			Other	0

Product Surveillance Registry Results **Qualifying Complications** 0 Total Number of Leads Enrolled in Study 4 174 Cumulative Months of Follow-Up Number of Leads Active in Study 2 Probability (%) 100 Survival estimate not available due to insufficient sample size 90 80 2 3 8 9 10 0 4 5 6 7 1

<i>ival</i>		Years After	r Implant					
Sun		at 0 mo						
ead	%	100.00						
Ľ	#	4						
		Effective Sam	ple Size					



6932 Sprint

Product Characteristics

US Market Release	Aug-96	Serial Number Prefix	ТСА	US Returned Product An	alysis
Registered US Implants	14,900	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture	22
Estimated Active US Implants	4,300	Polarity	True Bipolar/One Coil	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	23
				Other	4

Product Surveillance Registry Results Qualifying Complications 10 Total Number of Leads Enrolled in Study 412 Extra Cardiac Stimulation 1 Impedance Out of Range Cumulative Months of Follow-Up 25,610 Failure to Capture 2 Oversensing Number of Leads Active in Study 41 Failure to Sense 2



1

4

6933, 6937, 6937A, 6963 SVC/CS

Product	Characte	ristics

80 (Years Afte	2 yr	nt 3 yr 97.2	4 yr 96.7	5 yr 95.4	6 yr 94.9	7 yr 93.9	8 yr 93.4	9 yr 92.2	10 yr 91.2	11 yr 91.2	at 138 mo								
(4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	at 138 mo								
(Years Afte	r Impla	nt																	
) 1	2	3 4	4 5	6	7	7 8	9	1	0 1	1 1	2 13	14	15	16	17	18	19	20	21
00																				
90																				
100																				
										Impec	lance Oi	it of Range	3							
			e in ordia	,								re to Sense				Un	specifie		al Failur	
	lumber of Lea				54	13						to Capture				Lead Dislodgement Oversensing				
	lumber of Lea Cumulative Ma				EA	966 1,382						or Fracture itimulation				Insulat			defined	,
	Surveillan								Quai	/ 3				Total						
4	Curveillen	co Dogi	ctru Do	culto					Qual	ifuing	Comp	lications	47	T					ouler	
A	dvisories				None	Ste	eroid			No							In	sulation	Breach Other	
	stimated Act	ve US Im	plants		2,600		larity				e Coil							•	d/Bond	
E	legistered US				14,400		pe and/	or Fixati	on			us CS or SVC	C Defib						racture	
		ease		[Dec-93	Se	rial Nun	nber Pre	fix	TAT	, TBU, T	DB, TAF				USR	etum	ed Pro	duct A	Analy

6935 Sprint Quattro Secure

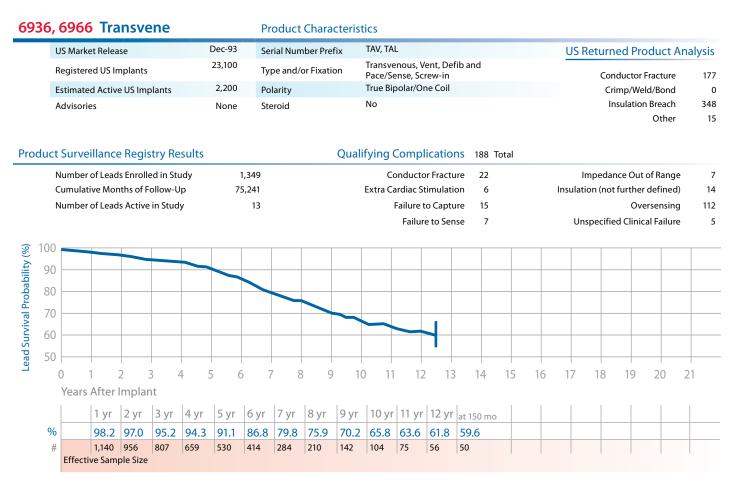
Product Characteristics

US Market Release	Nov-08	Serial Number Prefix	TAU	US Returned Product An	alysis
Registered US Implants	40,200	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture	46
Estimated Active US Implants	36,600	Polarity	True Bipolar/One Coil	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	2
Performance Note: <u>See page 150</u> – Helix Retraction of the Sprint Ouatt	ro Secure			Other	42

S 6935 and Sprint Quattro Secure 6947

Product Surveillance Registry Results		(Qualifying (Complications	8 Total			
Number of Leads Enrolled in Study	1,886		Co	onductor Fracture	e 1			
Cumulative Months of Follow-Up	25,696			Failure to Sense	1			
Number of Leads Active in Study	1,610		Le	ad Dislodgement	: 4			
				Oversensing	2			
a 100								
Š 1								
e 0 1 2	3	4	5	6	7	8	9	10

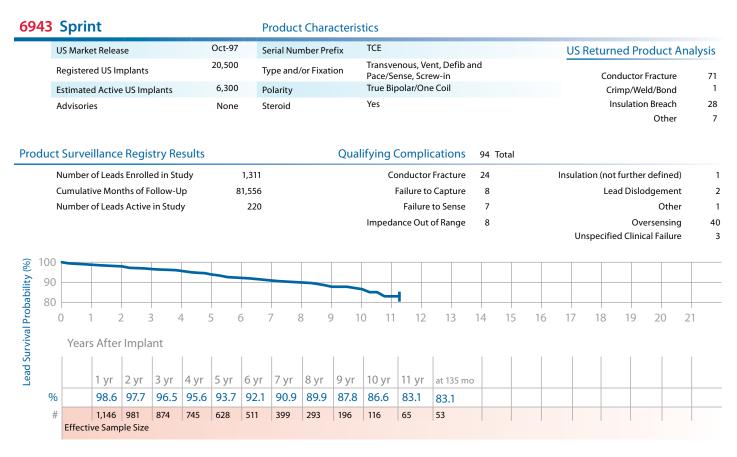
Lead Survival P Years After Implant 1 yr 2 yr 3 yr at 39 mo 99.5 99.2 99.2 % 99.2 # 846 353 81 44 **Effective Sample Size**



6942 Sprint

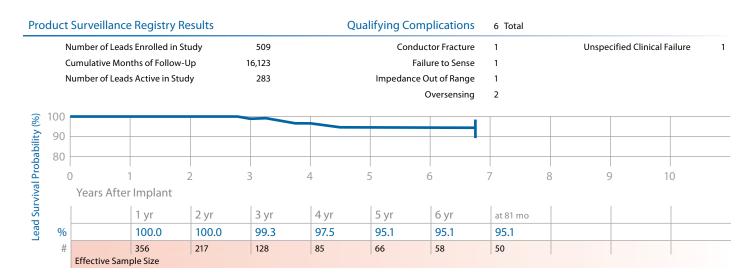
US Market Release	Jul-97	Serial Number Prefix	ТСВ	US Returned Product Ana	alysis
Registered US Implants	17,700	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture	14
Estimated Active US Implants	5,400	Polarity	Integrated Bipolar/Two Coils	Crimp/Weld/Bond	1
Advisories	None	Steroid	Yes	Insulation Breach	22
				Other	7

uutt	Surveillance	e negisti y n			<u> </u>	ualifying Co	inplications	7 Total			
Ν	lumber of Lead	s Enrolled in S	tudy	351		Cond	ductor Fracture	1		Ov	ersensing
C	umulative Mor	ths of Follow-	Up	19,099	Failure to Sense			1	Unspecified Clinical Failure		
Ν	lumber of Lead	s Active in Stu	dy	29		Lead	Dislodgement	1			
100											
90											
80											
C)	1	2	3	4	5	6	7	8	9	10
	Years After	^r Implant									
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	at 111 mo
%		99.1	99.1	98.1	97.5	96.8	96.8	96.8	96.8	96.8	96.8
#		294	231	179	141	118	100	78	67	53	49
	Effective Sam	ple Size									



6944 Sprint Quattro

-				
US Market Release	Dec-00	Serial Number Prefix	TDC	US Returned Product Analysis
Registered US Implants	41,400	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture 93
Estimated Active US Implants	21,800	Polarity	True Bipolar/Two Coils	Crimp/Weld/Bond 1
Advisories	None	Steroid	Yes	Insulation Breach 2
				Other 31





6947M Sprint Quattro Secure

Product Characteristics

Feb-12	Serial Number Prefix	ТДК	US Returned Product Anal	ysis
21,100	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture	1
20,600	Polarity	True Bipolar/Two Coils	Crimp/Weld/Bond	0
None	Steroid	Yes	Insulation Breach	0
)			Other	6
	21,100 20,600	21,100 Type and/or Fixation 20,600 Polarity None Steroid	21,100Type and/or FixationTransvenous, Vent, Defib and Pace/Sense, Screw-in20,600PolarityTrue Bipolar/Two CoilsNoneSteroidYes	21,100 Type and/or Fixation Transvenous, Vent, Defib and Pace/Sense, Screw-in Conductor Fracture 20,600 Polarity True Bipolar/Two Coils Crimp/Weld/Bond None Steroid Yes Insulation Breach

Product Surveillance Registry Results **Qualifying Complications** 2 Total Number of Leads Enrolled in Study 994 Failure to Capture 2 Cumulative Months of Follow-Up 2,540 Number of Leads Active in Study 961 Lead Survival Probability (%) 100 90 80 0 2 4 6 9 10 Years After Implant at 6 mo 99.5 % # 78 Effective Sample Size

6947 Sprint Quattro Secure

Product Characteristics

094/	Sprint Qualtro Secure	:	Product Charac	teristics			
	US Market Release	Nov-01	Serial Number Prefi	x TDG		US Returned Product Anal	lysis
	Registered US Implants	358,900	Type and/or Fixation	n Transvenous, Vent, Defib Pace/Sense, Screw-in	and	Conductor Fracture	436
	Estimated Active US Implants	243,700	Polarity	True Bipolar/Two Coils		Crimp/Weld/Bond	4
	Advisories	None	Steroid	Yes		Insulation Breach	32
	Performance Note: <u>See page 150</u> – Helix Retraction of the Sprint Quattro S 6935and Sprint Quattro Secure 694					Other	272
Produ	ct Surveillance Registry Results			Qualifying Complications	37 Total		
	Number of Leads Enrolled in Study	2,7	'15	Conductor Fracture	7	Lead Dislodgement	4
	Cumulative Months of Follow-Up	115,0	03	Failure to Capture	1	Oversensing	11
	Number of Leads Active in Study	1,1	51	Failure to Sense	2	Unspecified Clinical Failure	2
				Impedance Out of Range	7		
				Insulation (not further defined)	3		

%	100							1				
Ň	00											
iļi	90											
ab	80											
ę	00											
P	()	1	2 3	3 4	1 5	5 (5	7 8	3) 1	0
al												
.2												

Surv		Years After	Implant									
ead			1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	9 yr	at 117 mo
-	%		99.5	99.2	98.9	98.6	98.2	97.8	97.3	96.9	95.8	95.8
	#		2,395	1,900	1,176	745	582	437	327	223	105	48
		Effective Sam	ole Size									

6948 Sprint Fidelis

US Market Release	Sep-04	Serial Number Prefix	LFH	US Returned Product Ana	alysis
Registered US Implants	10,400	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture	141
Estimated Active US Implants	4,900	Polarity	True Bipolar/Two Coils	Crimp/Weld/Bond	0
Advisories		Steroid	Yes	Insulation Breach	2
<mark>See page 146</mark> – 2007 Potential Co Vire Fracture	onductor			Other	5

Pro	duct	Surveillance	e Registry Re	sults		Qua	lifying Com	plications	0 Total			
	Ν	lumber of Lead	s Enrolled in St	udy	30							
	C	Cumulative Mor	ths of Follow-U	Jp	1,413							
	Ν	lumber of Lead	s Active in Stud	У	15							
ity (%)	100 90	Survival estim	ate not availab	le due to insuffi	cient sample siz	e						
obability	80											
l Pro	() ,	1 2	2 .	3 4	4	5 (б	7	8	9 1	0
viva		Years After	Implant									
l Sur		at 0 mo										

2		rears / treef	Implant					
d Sui		at 0 mo						
Leac	%	100.0						
_	#	30						
		Effective Samp	ole Size					

	US Market Release	Sep-04	Serial Nur	mber Prefix	LFJ			US Returned Product A	nalysis
	Registered US Implants	186,700	Type and	/or Fixation	Transvenous, Screw-in	Vent, Defil	and Pace/Sense,	Conductor Fracture	5,977
	Estimated Active US Implants	79,600	Polarity		True Bipolar/T	Two Coils		Crimp/Weld/Bond	3
	Advisories		Steroid		Yes			Insulation Breach	29
	See page 146 – 2007 Potential Cor Wire Fracture	ductor						Other	196
uc	t Surveillance Registry Result	S		Qı	alifying Complic	cations	75 Total		
	Number of Leads Enrolled in Study		795		Conductor		36	Insulation (not further defined	2
	Cumulative Months of Follow-Up	37,3	326		Failure to	o Capture	2	Lead Dislodgemen	
	Number of Leads Active in Study	:	241		Failure	to Sense	4	Oversensing	15
					Impedance Out	of Range	14	Unspecified Clinical Failure	1
~ ~ ~					Impedance Out o	of Range	14	Unspecified Clinical Failure	1
					Impedance Out o	of Range	14	Unspecified Clinical Failure	1
90					Impedance Out o	of Range	14	Unspecified Clinical Failure	1
00 90 80		3		4	Impedance Out of the second se	of Range	14 7 8	Unspecified Clinical Failure	1
90 80		3		4		of Range			1
90 80	0 1 2	-	3 yr	4 4 yr	5 6	of Range			. 1
90 80	0 1 2 Years After Implant	vr 3			5 6 5 yr 6	-	7 8		1

6996 Sub-Q Lead

US Market Release	Jun-01	Serial Number Prefix	TCR	US Returned Product An	alysis
Registered US Implants	3,800	Type and/or Fixation	Subcutaneous Defib Coil, Suture	Conductor Fracture	19
Estimated Active US Implants	2,200	Polarity	One Defib Coil	Crimp/Weld/Bond	0
Advisories	None	Steroid	No	Insulation Breach	0
				Other	0

Pro	duct	Surveillance	e Registry Re	sults		Qua	lifying Com	olications	2 Total			
	Ν	lumber of Lead	s Enrolled in Stu	ıdy	41		Conduc	tor Fracture	1			
	C	umulative Mor	ths of Follow-U	р	1,087		Impedance O	ut of Range	1			
	Ν	lumber of Lead	s Active in Stud	у	20							
ity (%)	100 90	Survival estima	ate not available	due to insuffic	ient sample size	1						
abili	80											
Prob	() .	1 2	2 3	3 4	1 5	5 6	5	7	8	9 1	0
Lead Survival Probability		Years After	Implant									
ad		at 0 mo										
Le	%	100.0										
	#	36										
		Effective Sam	ple Size									

Medtronio			əssələ	рә	γbut2 ni s		vbutδ ni c γbut2 ni c	Device S	Device Survival Probability (%)	robabilit	y (%)									
		J	rket R	Enroll		oitecil	ηU-wo	Years Aft	Years After Implant	'nt										
ləboM	qunN	(lime7	₽W SU	speəŋ	sbsəJ filsuQ	dwoy	llo∃ ło	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr	18 yr
	6721, 6921	Epicardial Patch	Feb-93	407	4	47 2	23,303	96.5 +1.5/-2.4	95.0 +1.8/-2.8	92.7 +2.3/-3.4	91.9 +2.5/-3.5	90 .0 +2.9/-4.0	85.1 +3.9/-5.2	83.7 +4.2/-5.6	83.7 +4.2/-5.6	83.7 +4.2/-5.6 at 111 mo				
	6930	Sprint Fidelis	Sep-04	4	7	0	174 1	100.0 at 0 mo												
		Advisories: See page 146 – 2007 Potential Conductor Wire Fracture	2007 Potenti	ial Conduc	tor Wire Fract	ure														
	6931	Sprint Fidelis	Sep-04	294	119	37	13,106	98.2 +1.0/-2.5	96.2 +1.7/-3.2	93.0 +2.6/-4.1	89.2 89.4.9	83.8 +4.8/-6.4	81.6 +5.3/-7.1							
		Advisories: See page 146 – 2007 Potential Conductor Wire Fracture	2007 Potenti	ial Conduc	tor Wire Fract	ure							at 66 mo							
69	6932	Sprint	Aug-96	412	41	10	25,610	99.2 +0.5/-1.7	98.3 +0.9/-2.0	98.3 +0.9/-2.0	98.3 +0.9/-2.0	97.8 +1.2/-2.5	97.8 +1.2/-2.5	97.8 +1.2/-2.5	96.8 +1.8/-3.7	96.8 +1.8/-3.7	93.6 +3.5/-7.5 at 138 mo			
69 69 69 69 69	6933, 6937, 6937A, 6963	svc/cs	Dec-93	966	13	47 5	54,382	98.4 +0.7/-1.0	97.5 + +0.9/-1.3	97.2 +0.9/-1.4	96.7 +1.0/-1.6	95.4 +1.4/-2.0	94.9 +1.5/-2.1	93.9 +1.7/-2.5	93.4 +1.9/-2.7	91.2 +2.8/-4.1	91.2 +2.8/-4.1 at 138 mo			
69	6935	Sprint Quattro Secure Nov-08 1,886 1,610 8 See page 150 – Performance note on Helix Retraction 6935 and 6947	Nov-08 e note on He	1,886 elix Retracti	1,610 ion 6935 and 6		25,696	99.5 +0.3/-0.6	99.2 +0.4/-0.8	99.2 +0.4/-0.8	99.2 +0.4/-0.8 at 39 mo									
	6936, 6966	Transvene	Dec-93	1,349	13	188	75,241	98.2 +0.6/-1.0	97.0 +0.8/-1.2 +	95.2 +1.2/-1.4	94.3 +1.3/-1.6	91.1 +1.8/-2.1	86.8 +2.3/-2.8	79.8 +3.1/-3.6	75.9 +3.5/-4.0	65.8 +4.9/-5.5	61.8 +5.6/-6.2	59.6 +6.1/-6.9 at 150 mo		
	6942	Sprint	Jul-97	351	29	7	19,099	99.1 +0.6/-1.9 +	99.1 +0.6/-1.9 +	98.1 +1.1/-2.7	97.5 +1.4/-3.1	96.8 +1.7/-3.8	96.8 +1.7/-3.8	96.8 +1.7/-3.8	96.8 +1.7/-3.8	96.8 +1.7/-3.8 at 111 mo				
	6943	Sprint	Oct-97	1,311	220	94 8	81,556	98.6 +0.5/-0.9 +	97.7 +0.7/-1.1	96.5 +1.0/-1.2 +	95.6 +1.1/-1.5	93.7 +1.4/-1.8	92.1 +1.6/-2.0	90.9 +1.9/-2.2	89.9 +2.1/-2.4	86.6 +2.8/-3.6	83.1 +4.0/-5.2 at 135 mo			
	6944	Sprint Quattro	Dec-00	509	283	v	16,123	100.0	100.0	99.3 +0.6/-4.1	97.5 +1.7/-5.1	95.1 +2.9/-6.6	95.1 +2.9/-6.6	95.1 +2.9/-6.6 at 81 mo						
	6945	Sprint	Sep-97	1,155	125	38	67,487	99.4 +0.4/-0.6	98.7 +0.5/-1.0	98.2 +0.7/-1.1	97.6 +0.8/-1.3	96.8 +1.1/-1.6	96.1 +1.3/-1.8	95.6 +1.4/-2.0	94.5 +1.7/-2.4	92.7 +2.2/-3.2	91.7 +2.7/-3.9 at 141 mo			
	6947	Sprint Quattro Secure Nov-01 2,715 1,151 37 See page 150 - Performance note on Helix Retraction 6935 and 6947	Nov-01 e note on He	2,715 elix Retracti	1,151 ion 6935 and 6		115,003	99.5 +0.2/-0.4 +	99.2 +0.3/-0.4 +	98.9 +0.4/-0.5	98.6 +0.5/-0.7	98.2 +0.6/-1.0	97.8 +0.7/-1.1	97.3 +0.9/-1.5	96.9 +1.1/-1.7	95.8 +1.6/-2.5 at 117 mo				
	6947M	Sprint Quattro Secure Feb-12 994 961 2 See page 150 - Performance note on Helix Retraction 6935 and 6947	Feb-12 e note on He	994 elix Retracti	961 ion 6935 and i		2,540	99.5 +0.4/-1.7 at 6 mo												
	6948	Sprint Fidelis Sep-04 30 15 0 Advisories: See page 146 – 2007 Potential Conductor Wire Fracture	Sep-04 2007 Potenti	30 ial Conduct	15 tor Wire Fract	0	1,413	100.0 at 0 mo												
6 uct Ana	6949	Sep-04 795 241 75 Advisories: See page 146 – 2007 Potential Conductor Wire Fracture	Sep-04 2007 Potenti	795 ial Conduct	241 tor Wire Fracti		37,326	98.7 +0.6/-1.2	96.9 +1.1/-1.6	94.2 +1.6/-2.1	92.4 +1.8/-2.5	89.4 +2.4/-3	84.3 +3.3/-4.2	81.0 +4.3/-5.4 at 81 mo						
	9669	Sub-Q Lead	Jun-01	41	50	7	1,087	100.0 at 0 mo												
								-	-	-			1			1		-		

Lead Survival Summary (95% Confidence Interval)

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Insulation Breach	Crimp/ Weld/Bond	Other
6721, 6921	Epicardial Patch	Feb-93	8,800	1,500	25	2	0	0
6930	Sprint Fidelis	Sep-04	400	200	3	0	0	0
6931	Sprint Fidelis	Sep-04	8,100	3,600	504	1	0	8
6932	Sprint	Aug-96	14,900	4,300	22	23	0	4
6933, 6937, 6937A, 6963	SVC/CS	Dec-93	14,400	2,600	170	32	0	4
6935	Sprint Quattro Secure	Nov-08	40,200	36,600	46	2	0	42
6936, 6966	Transvene	Dec-93	23,100	2,200	177	348	0	15
6942	Sprint	Jul-97	17,700	5,400	14	22	1	7
6943	Sprint	Oct-97	20,500	6,300	71	28	1	7
6944	Sprint Quattro	Dec-00	41,400	21,800	93	2	1	31
6945	Sprint	Sep-97	42,700	12,800	121	35	1	13
6947	Sprint Quattro Secure	Nov-01	358,900	243,700	436	32	4	272
6947M	Sprint Quattro Secure	Feb-12	21,100	20,600	1	0	0	6
6948	Sprint Fidelis	Sep-04	10,400	4,900	141	2	0	5
6949	Sprint Fidelis	Sep-04	186,700	79,600	5,977	29	3	196
6996	Sub-Q Lead	Jun-01	3,800	2,200	19	0	0	0

Source: Returned Product Analysis Data as of February 1, 2013

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure to Sense		•	Extracardiac Stimulation	Unspecified
6721, 6921	Epicardial Patch	8,800	1	2	0	0	1	1	0	3	0	0
6930	Sprint Fidelis	400	0	0	0	0	0	0	0	0	0	1
6931	Sprint Fidelis	8,100	1	2	1	1	3	1	0	0	0	1
6932	Sprint	14,900	0	0	4	2	0	2	0	1	0	2
6933, 6937, 6937A, 6963	SVC/CS	14,400	0	0	1	2	0	0	1	0	0	6
6935	Sprint Quattro Secure	40,200	10	0	26	15	23	5	1	10	0	5
6936, 6966	Transvene	23,100	5	2	1	5	3	2	1	1	0	4
6942	Sprint	17,700	0	1	1	4	0	0	0	2	0	1
6943	Sprint	20,500	1	0	0	1	1	1	1	2	0	0
6944	Sprint Quattro	41,400	0	2	16	11	11	3	0	8	0	6
6945	Sprint	42,700	1	1	4	6	7	2	2	0	1	2
6947	Sprint Quattro Secure	358,900	22	18	99	66	109	28	4	45	2	22
6947M	Sprint Quattro Secure	21,100	2	1	22	12	3	1	0	2	0	0
6948	Sprint Fidelis	10,400	0	2	7	6	1	0	0	0	0	3
6949	Sprint Fidelis	186,700	10	40	23	32	30	19	6	17	0	25
6996	SubQ	3,800	0	0	1	1	0	0	0	2	0	0
									-			

Report Cutoff Date: February 1, 2013

Reference Chart

			Pin Cont	figuration			
Model Number	Family	Туре	Pace/Sense	High Voltage	Lead Body Diameter	Insulation, Lead Body	Fixation, Steroid
6721	Epicardial Patch	Epi Patch	_	DF-1	S, M, L	Silicone, Single Lumen	Suture
6921	Epicardial Patch	Epi Patch	_	6.5 mm	S, M, L	Silicone, Single Lumen	Suture
6930	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6931	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6932	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid
6933	SVC/CS	Endo SVC/CS Coil	_	DF-1	7 Fr	Silicone, Single Lumen	Passive
6935	Sprint Quattro Secure	Endo RV True Bipolar Sensing	IS-1	DF-1	8.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6937	SVC/CS	Endo SVC Coil	_	DF-1	5.5 Fr	Silicone, Single Lumen	Passive
6937A	SVC/CS	Endo SVC Coil	—	DF-1	7.5 Fr	Silicone with Polyurethane Overlay, Single Lumen	Passive
6942	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid
6943	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid
6944	Sprint Quattro	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6945	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid
6947	Sprint Quattro Secure	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6947M	Sprint Quattro Secure	Endo RV/SVC True Bipolar Sensing	DF4	DF4	8.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6948	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6949	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6963	SVC/CS	Endo SVC/CS Coil	_	6.5 mm	7 Fr	Silicone, Single Lumen	Passive
6966	Transvene	Endo RV True Bipolar Sensing	3.2 mm L.P.	6.5 mm	10 Fr	Polyurethane, Coaxial	Active
6996	Sub-Q Lead	SQ Coil	_	DF-1	7.5 Fr	Silicone, Single Lumen	Passive

Pacing Leads

	US Market Release	Aug-05	Serial Number	r Prefix	LFF			U	S Returned P	roduct Anal	vsis
	Registered US Implants	20,900	Type and/or Fi	ixation	Transvenou	is, V or A, Scre	w-in	_		or Fracture	
	Estimated Active US Implants	15,900	Polarity		Bipolar				Crimp/V	Veld/Bond	(
	Advisories	None	Steroid		Yes				Insulation Breach		
										Other	
	l Placement			Qualify		liestiene	6 7 . 1				
oau	ict Surveillance Registry Resul			Quality	ying Comp		6 Total				
	Number of Leads Enrolled in Study		769	-		Perforation	1			ure to Sense	
	Cumulative Months of Follow-Up Number of Leads Active in Study	22,0	198 109	itimulation to Capture	1		Lead Di	slodgement			
			09		Tanure	to capture	I				
10											
0	00										
9											
	0										
9 8	0 1 2	3	4	5	6		7	8	9	10	
8		3	4	5	6		7	8	9	10	
	0 1 2	-		-	6 5 yr	at 63 mo	7	8	9	10	
8	0 1 2 Years After Implant	yr 3	yr 4	yr 5	_		 7 	8	9	10	

Ventricular Placement

Number of	Leads Enrolled in Study	475		Impe	dance Out of Rang	ge 1						
Cumulative	e Months of Follow-Up	15,455		Lead Dislodgement								
Number of	Leads Active in Study	290	290									
100												
100												
90												
80												
	1 2	3	4	5	6	7	8	9	10			
0		5	-	5	0	/	0	2	10			

ead			1 yr	2 yr	3 yr	4 yr	5 yr	at 69 mo		
Ľ	%		99.5	99.5	99.5	99.5	99.5	99.5		
	#		388	229	142	90	63	49		
		Effective Samp	ole Size							

Pacing Leads continued

	US Market Release	Oct-91	Serial Nu	mber Prefix	LAJ			LIS R	eturned Pro	duct Ana	lysi
	Registered US Implants	217,500		/or Fixation	Transver	nous, Vent, Tines		0511	Conductor F		119 51
	Estimated Active US Implants	41,100	Polarity	, or i mation	Bipolar				Crimp/Wel		
	Advisories	None	Steroid		Yes			Insulation Breach			1
										Other	
luc	ct Surveillance Registry Resul	ts		Qu	alifying Cor	nplications	4 Total				
	Number of Leads Enrolled in Study	1	215		Epile	ure to Capture	3				
	Number of Leaus Emolieu in Sludy		215		ганс	le lo caplule					
	Cumulative Months of Follow-Up	50,9		Ins	sulation (not fu	•	1				
	•			Ins		•					
100	Cumulative Months of Follow-Up Number of Leads Active in Study		928	Ins		•					
10(9(Cumulative Months of Follow-Up Number of Leads Active in Study		928	Ins		•				1	
	Cumulative Months of Follow-Up Number of Leads Active in Study		928	Ins		•				1	
9(Cumulative Months of Follow-Up Number of Leads Active in Study		928	4		•		8	9	10	
9(Cumulative Months of Follow-Up Number of Leads Active in Study	50,5	928		sulation (not fu	rther defined)	1	8	9	10	
9(Cumulative Months of Follow-Up Number of Leads Active in Study	3	928		sulation (not fu	rther defined)	1	8 8 8 yr	9 9 yr	10 at 117	mo
9(Cumulative Months of Follow-Up Number of Leads Active in Study	50,5 3 yr 3	928 13	4	sulation (not fur	rther defined)	1	-			

Pacing Leads continued

Tansvenous, Vor A. Screw-in Conductor Fracture Extimated Active US Implants 30,300 Polarity Bipolar Conductor Fracture Advisories None Steroid Yes Conductor Fracture Conductor Fracture Advisories None Steroid Yes Conductor Fracture Insulation (BSC) Number of Leads Enrolled in Study 2,413 Conductor Fracture Conductor Fracture Insulation (MO) Number of Leads Active in Study 2,413 Conductor Fracture 3 Insulation (MO) Number of Leads Active in Study 2,66 Failure to Capture 22 Insulation (MO) Number of Leads Active in Study 2.66 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21 Vears After Implant Users After Implant Vears After Implant Qualifying Compli	R	JS WIAIK	et Relea	se			Mar-96	Ser	ial Num	ber Pref	fix	LCE							US R	eturne	ed Pro	duct	Anal	ys
Advisories None Steroid Yes Insulation Breach Other Advisories Pacement Burde Conductor Fracture 3 Insulation Breach Other Aurisories Qualifying Complications 77 Total Mumber of Leads Enrolled in Study 2,413 Conductor Fracture 3 Insulation (BCC) Cumulative Months of Follow-Up 133,591 Extra Cardia c Stimulation 2 Insulation (MOO) Number of Leads Active in Study 2,66 Failure to Capture 2 Insulation for further defined) Failure to Capture 2 Insulation for further defined) Ead Disiodgement Impedance Out of Range 9 Oversensing 00 1 2 3 4 5 6 7 8 9 11 12 13 14 15 16 17 18 19 20 21 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1		legister	ed US In	nplants		1	23,800	Тур	oe and/o	or Fixatio	on	Trar	nsvenou	is, V or A	, Screv	v-in								
During the order of leads Enrolled in Study 2,413 Conductor Fracture 3 Insulation (ESC) Cumulative Months of Follow-Up 133,591 Extra Cardiac Stimulation 2 Insulation (MIQ) Number of Leads Enrolled in Study 266 Failure to Capture 22 Insulation (MIQ) Number of Leads Active in Study 266 Failure to Capture 22 Insulation (MIQ) Number of Leads Active in Study 266 Failure to Capture 29 Oversensing Unspecified Clinical Failure 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 1000 100				e US Im	olants								olar								•			
Al Placement buct Surveillance Registry Results Qualifying Complications 7.7 Total Number of Leads Enrolled in Study 2,413 Conductor Fracture 3 Insulation (ESC) Number of Leads Follow-Up 133,591 Extra Cardiac Stimulation 2 Insulation (MOI) Number of Leads Active in Study 266 Extra Cardiac Stimulation 2 Insulation (not further defined) Failure to Sense 13 Lead Dislodgement Oversensing Unspecified Clinical Failure 0 Insulation (not further defined) Insulation (not further defined) 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0	A	dvisori	es				None	Ste	roid			Yes								Ins	ulation			
Curculative Months of Follow-Up 133,591 Conductor Fracture 3 Insulation (ESC) Number of Leads Enrolled in Study 2,413 Conductor Fracture 3 Insulation (ESC) Number of Leads Active in Study 2,66 Failure to Capture 22 Insulation (not further defined) Failure to Sense 13 Extra Cardiac Stimulation 2 Insulation (not further defined) Impedance Out of Range 9 Oversensing Oversensing 00 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21 Years After Implant Qualifying Complications 51 Total Years After Implant Years After Implant Qualifying Complications 51 Total String Complications 51 Total																						Othe	r	
Number of Leads Enrolled in Study 2,413 Conductor Fracture 3 Insulation (ESC) Cumulative Months of Follow-Up 133,591 Extra Cardiac Stimulation 2 Insulation (MIQ) Number of Leads Active in Study 266 Failure to Capture 22 Insulation (not further defined) Failure to Sense 13 Extra Cardiac Stimulation 2 Insulation (not further defined) Impedance Out of Range 9 Unspecified Clinical Failure 0 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21 Years After Implant 96 98.9 98.7 98.2 98.0 97.4 97.2 96.5 91.4 89.9 86.2 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	ial P	lacen	nent																					
Cumulative Months of Follow-Up 133,591 Number of Leads Active in Study 266 Failure to Capture 22 Failure to Cap											Qual						otal							
Number of Leads Active in Study 26 Failure to Capture 22 Insulation (not further defined) Builty to Sense 13 Failure to Sense 13 Lead Dislodgement Oversensing Oversensing Oversensing Oversensing Out of Range 9 10 11 12 13 14 15 16 17 18 19 20 21 Years After Implant Verse Sample Size Out of Sample Size Out of Sample Size Out of Sample Size 10 11 12 13 14 15 16 17 18 19 20 21 Mumber of Leads Enrolled in Study 1/79 Conductor Fracture 3 Impedance Out of Range 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 <td< th=""><td></td><td></td><td></td><td></td><td></td><td>-</td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td>,</td><td></td></td<>						-																	,	
Failure to Sene 13 Lead Dislodgement Impedance Out of Range 9 Oversensing Unspecified Clinical Failure Impedance Out of Range 9 Impedance Out of Range 1 Impedance Out of Range						-	13					Extra C							1					
Impedance Out of Range 9 Oversensing Unspecified Clinical Failure 00 0 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21 Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 9 yr 10 yr 11 yr 12 yr 13 yr at 165 mo 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 <th1< th=""> 1 1 <th1< th=""></th1<></th1<>	N	umber	of Lead	s Active	in Stud	у		266											Insulat					
Unspecified Clinical Failure $Unspecified Clinical Failure$ $V = V = V = V = V = V = V = V = V = V =$												Impod								Lea				
$I = \frac{100}{90} = \frac{1}{90} = 1$												imped	anceO	at ur ndf	ige	7			Un	specifia			-	
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$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	90																							
Years After Implant % 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 9 yr 10 yr 11 yr 12 yr 13 yr at 165 mo Implant % 98.9 98.7 98.2 98.0 97.4 97.2 96.7 95.3 94.6 93.7 92.5 91.4 89.9 86.2 Implant Implant # 1,907 1,637 1,370 1,116 897 737 577 472 358 256 189 135 84 43 Implant tricular Placement uct Surveillance Registry Results Qualifying Complications 51 Total Mumber of Leads Enrolled in Study 1,799 Conductor Fracture 3 Impedance Out of Range Cumulative Months of Follow-Up 95,888 Extra Cardiac Stimulation 2 Insulation (not further defined) Number of Leads Active in Study 162 Failure to Capture 22 Oversensing	80														-		_							
9% 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 9 yr 10 yr 11 yr 12 yr 13 yr at 165 mo	(0	I .	2	3 .	4	5 (с ,	/ 2	5 5		0 1		2 1.	3	14	15	16	17	18	19	20	2	
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duct Surveillance Registry ResultsQualifying Complications51TotalNumber of Leads Enrolled in Study1,799Conductor Fracture3Impedance Out of RangeCumulative Months of Follow-Up95,888Extra Cardiac Stimulation2Insulation (not further defined)Number of Leads Active in Study162Failure to Capture22Oversensing			1,907	1,637								_		-	-									
		Effecti	1,907	1,637								_		-	-									
	# duct N C	ular F Surve Jumber	1,907 ive Samp Placer illance of Lead	1,637 ole Size ment e Regis s Enroll	1,370 stry Re ed in Stu	1,116 esults udy	897	737 1,799 5,888			358	256 ifying	189 Comp Conduct Cardiac S Failure	135 licatio or Fract Stimulat to Capt	84 ons ure ion ure	4 51 3 2 22	3		Insulat	ion (not	furthei Ove	r define ersensi	ed) ng	
	# htric duct N C N	ular F Surve Jumber	1,907 ive Samp Placer illance of Lead	1,637 ole Size ment e Regis s Enroll	1,370 stry Re ed in Stu	1,116 esults udy	897	737 1,799 5,888			358	256 ifying	189 Comp Conduct Cardiac S Failure	135 licatio or Fract Stimulat to Capt	84 ons ure ion ure	4 51 3 2 22	3		Insulat	ion (not	furthei Ove	r define ersensi	ed) ng	
90	# htric duct N C N N 100 90	ular F Surve Jumber	1,907 ive Samp Placer illance of Lead	1,637 ole Size ment e Regis s Enroll	1,370 stry Re ed in Stu	1,116 esults udy	897	737 1,799 5,888			358	256 ifying	189 Comp Conduct Cardiac S Failure	135 licatio or Fract Stimulat to Capt	84 ons ure ion ure	4 51 3 2 22	3		Insulat	ion (not	furthei Ove	r define ersensi	ed) ng	
90 80	# htric duct N C N 100 90 80	ular F Surve Jumber Jumber	1,907 ive Samp Placer illance of Lead ive Mor of Lead	1,637 ole Size Regis s Enroll aths of F s Active	1,370 stry Re ed in Stu ollow-U in Stud	1,116 esults Jdy Jp y	9	737 1,799 5,888 162	577	472	Qual	256 ifying C Extra C	189 Comp Conduct Cardiac Failure Failu	135 or Fract to Capt re to Se	84 ns ure ion ure nse	51 · · · · · · · · · · · · · · · · · · ·	3 Fotal	16	Unsulat Un	specifie	further	r define ersensi cal Failu	ed) ng ure	1
90 80	# tric luct N c N 100 90 80	ular F Surve Jumber Jumulat Jumber	1,907 ive Samp Placer eillance of Lead of Lead	1,637 ole Size Regis s Enroll aths of F s Active	1,370 stry Re ed in Stu ollow-L in Stud	1,116 esults Jdy Jp y	9	737 1,799 5,888 162	577	472	Qual	256 ifying C Extra C	189 Comp Conduct Cardiac Failure Failu	135 or Fract to Capt re to Se	84 ns ure ion ure nse	51 · · · · · · · · · · · · · · · · · · ·	3 Fotal	16	Unsulat Un	specifie	further	r define ersensi cal Failu	ed) ng ure	1
90 80 90 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21	# htric duct N c N 100 90 80	ular F Surve Jumber Jumulat Jumber	1,907 ive Samp Placer eillance of Lead of Lead of Lead	1,637 ole Size Regis s Enroll aths of F s Active	1,370 stry Re ed in Stu ollow-L in Stud	1,116 esults Jdy Jp y	9	737 1,799 5,888 162	577 7 8	472	Qual	256 ifying C Extra C	Comp Conduct Cardiac S Failure Failure	135 or Fract to Capt re to Se	84 ure ion ure nse	4 51 3 22 3	3 Fotal	16	Unsulat Un	specifie	further	r define ersensi cal Failu	ed) ng ure	1

49

52

1.427 1,219 1,032 832

Effective Sample Size

685

539

405

300

213

133

77

#

Pacing Leads continued

4074 CapSure Sense **Product Characteristics** Jun-02 BBD US Market Release Serial Number Prefix US Returned Product Analysis **Registered US Implants** 91,300 **Conductor Fracture** Type and/or Fixation Transvenous, Vent, Tines 2 **Estimated Active US Implants** 57,100 Polarity Bipolar Crimp/Weld/Bond 0 Advisories Steroid Yes Insulation Breach 20 None Other 1 **Atrial Placement** Product Surveillance Registry Results **Qualifying Complications** 2 Total Number of Leads Enrolled in Study 214 Failure to Sense 1 Cumulative Months of Follow-Up 14,960 Lead Dislodgement 1 Number of Leads Active in Study 137 100 Lead Survival Probability (%) 90 80 2 3 4 5 6 7 8 9 10 0 Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr at 90 mo % 99.1 99.1 99.1 99.1 99.1 99.1 99.1 99.1

146

112

73

52

Ventricular Placement

200

Effective Sample Size

189

183

171

#

Produ	ict	Surveillance	e Registry R	esults		Q	ualifying Co	mplications	3 Total			
	(Number of Lead Cumulative Mor Number of Lead	nths of Follow-	Up	956 30,769 691		Fai Impedano Leac	1 1 1				
<u> </u>	00 90									1		
Lead Survival Probability	30	0	1	2	3	4	5	6	7	8	9	10
urviv		Years After	Implant									
ad S			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	at 93 mo		
Le	%		99.7	99.5	99.5	99.5	99.5	99.5	99.5	99.5		
	#	Effective Sam	541 ple Size	388	329	304	242	154	85	47		

	JS Market Release		Feb-04	Serial N	umber Prefix	BBL			US Returned	d Product Ana	lysi
F	Registered US Impla	ants	432,000	Type an	d/or Fixation	Transven	ous, V or A, Scre	v-in	Condu	ictor Fracture	
	stimated Active US	5 Implants	332,400	Polarity		Bipolar				p/Weld/Bond	
A	Advisories		None	Steroid		Yes			Insu	lation Breach Other	
	Placement Surveillance Re	egistry Resi	ults		Qua	lifying Con	nplications	8 Total			
	Number of Leads Er	<u> </u>		,662		, ,	ictor Fracture	1	Leac	Dislodgement	
	Cumulative Months		-	,076			re to Capture	2			
	Number of Leads Ad	-		,017			ilure to Sense	1			
					Insu	lation (not fur	ther defined)	1			
100							_				
90											
80											
	0 1	2	3		4	5	6	7 8	9	10	
	Years After In		_			-	-	-	-		
	1	yr	2 yr	3 yr	4 yr	5 yr	бyr	at 75 mo			
%			99.6	99.5	99.5	99.5	98.9	98.9			
#			1,112	642	370	208	68	48			
	Effective Sample	Size									
duct	ular Placeme Surveillance R	egistry Resi		220	Qua	lifying Con		5 Total			
duct N	Surveillance Re Number of Leads Er	egistry Resu	ly 1	,229	Qua	Extra Cardia	c Stimulation	1			
duct N	Surveillance Re Number of Leads Er Cumulative Months	egistry Resu nrolled in Stud of Follow-Up	ly 1	,434	Qua	Extra Cardia Failu	c Stimulation re to Capture	1 3			
duct N C	Surveillance Re Number of Leads Er Cumulative Months Number of Leads Ac	egistry Resu nrolled in Stud of Follow-Up	ly 1		Qua	Extra Cardia Failu	c Stimulation	1			
duct r c 100	Surveillance Re Number of Leads Er Cumulative Months Number of Leads Ac	egistry Resu nrolled in Stud of Follow-Up	ly 1	,434	Qua	Extra Cardia Failu	c Stimulation re to Capture	1 3			
duct N C N 100 90	Surveillance Re Number of Leads Er Cumulative Months Number of Leads Ac	egistry Resu nrolled in Stud of Follow-Up	ly 1	,434	Qua	Extra Cardia Failu	c Stimulation re to Capture	1 3			
duct r c 100	Surveillance Re Number of Leads Er Cumulative Months Number of Leads Ac	egistry Resi nrolled in Stud of Follow-Up ctive in Study	ly 1 46	,434	Qua	Extra Cardia Failu Impedance	c Stimulation re to Capture	1 3 1			
duct N C N 100 90	Surveillance Re Number of Leads Er Cumulative Months Number of Leads Ac 0 1	egistry Resu rolled in Stud of Follow-Up ctive in Study	ly 1 46	,434	Qua	Extra Cardia Failu	c Stimulation re to Capture	1 3 1	8 9	10	
duct N C N 100 90	Surveillance Re Number of Leads Er Cumulative Months Number of Leads Ac	egistry Resu rolled in Stud of Follow-Up ctive in Study	ly 1 46	,434 744		Extra Cardia Failu Impedance	c Stimulation re to Capture Out of Range		8 9	10	
duct N C N 100 90	Surveillance Re Number of Leads Er Cumulative Months Number of Leads Ac 0 1 0 1 Years After Im	egistry Resi rolled in Stud of Follow-Up ctive in Study 2 nplant	ly 1 46	,434 744		Extra Cardia Failu Impedance	c Stimulation re to Capture Out of Range		8 9	10	
<mark>duct</mark> ۲ ۲ ۱00 90	Surveillance Re Number of Leads Er Cumulative Months Number of Leads Ac O 1 Years After Im	egistry Resi nrolled in Stud of Follow-Up ctive in Study 2 nplant 1 yr	ly 1 46	,434 744	4	Extra Cardia Failu Impedance	c Stimulation rre to Capture Out of Range 6	1 3 1 7	8 9	10	

4092 CapSure SP Novus

Product Characteristics

US Market Release	Sep-98	Serial Number Prefix	LEP	US Returned Product An	alysis
Registered US Implants	177,000	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture	9
Estimated Active US Implants	80,400	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	48
				Other	3

Proc	luc	t Surveillance	e Registry Re	esults		C	Qualifying Co	mplications	19 Total					
	Number of Leads Enrolled in Study Cumulative Months of Follow-Up Number of Leads Active in Study				1,147 65,701 293		Extra Carc	ductor Fracture liac Stimulation ilure to Capture	 Impedance Out of Range Lead Dislodgement 					
Survival Probability (%)	10(9(8()	1	2	3	4	5	6	7	8	9	10		
rvival		Years After	r Implant	_										
l Su			1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	9 yr	at 117 mo		
Lead	%	6	98.9	98.8	98.7	98.4	98.1	97.7	97.7	97.7	97.7	97.7		
	1	# Effective Sam	929 ple Size	831	734	637	553	449	320	206	117	47		

4524 CapSure SP

Product Characteristics

US Market Release	Oct-91	Serial Number Prefix	LAR	US Returned Product Ana	lysis
Registered US Implants	99,500	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture	1
Estimated Active US Implants	23,400	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	64
				Other	6

Proc	duct	Surveillance	Registry Re	sults		(Qualifying (Complicatio	ons 6	Total			
	N	lumber of Leads	Enrolled in Stu	ıdy	911		l	Failure to Capt	ture 3				
	C	umulative Mon	ths of Follow-U	р	40,725			Failure to Se	ense 2				
	N	lumber of Leads	Active in Study	у	35		Le	ad Dislodgem	ient 1				
(%) (X	100												
oilit	90												
bba	80												
l Pro	(0 1		2	3	4	5	6	7	8	()	10
Lead Survival Probability		Years After	Implant										
ad Si			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	at 126 mo
Lea	%		99.6	99.3	99.3	99.0	99.0	99.0	99.0	99.0	99.0	99.0	99.0
	#		682	537	427	329	251	182	133	87	65	55	51

Effective Sample Size

	US Market Release	Nov-94	Serial Nun	nber Prefix	LDC			US Re	eturned Prod	duct Anal	ysis
	Registered US Implants	19,400	Type and/	or Fixation	Transvenou	us, Atrial-J, Scr	ew-in		Conductor Fr		
	Estimated Active US Implants	3,800	Polarity		Bipolar				Crimp/Weld	l/Bond	
	Advisories	None	Steroid		No				Insulation	Breach	
										Other	
luc	t Surveillance Registry Resu	ts		Qua	lifying Comp	olications	12 Total				
	Number of Leads Enrolled in Study		539		Electrical Aba	andonment	1	Ir	mpedance Out	of Range	
	Cumulative Months of Follow-Up	23,2	3,289 Failure to Capture 3			3	Insulation (not further defined)				
	Number of Leads Active in Study		6 Failure to Capture 3			2	Oversensing				
	Number of Leads Active in Study		0		Fallu	ire to Sense	2		Oversensing		
	-		0		Failu	ire to Sense	2		Ove	isensing	
100			0		Fairc	ire to Sense	2				
100 90			0		Failu		2				
100											
100 90		3	0	4		fre to sense	7	8	9	10	
100 90		3		4				8			
100 90	0 1 2 Years After Implant		3 yr	4 4				8 8 8 yr			
100 90	0 1 2 Years After Implant	yr i			5 (6	7	-	9		

4568 CapSureFix **Product Characteristics** US Market Release Jan-97 Serial Number Prefix LDD **US Returned Product Analysis** Registered US Implants 69,100 Transvenous, Atrial-J, Screw-in **Conductor Fracture** Type and/or Fixation 3 Estimated Active US Implants 21,500 Polarity Bipolar Crimp/Weld/Bond 0 Advisories Steroid Yes Insulation Breach 81 None 53 Other Product Surveillance Registry Results **Qualifying Complications** 35 Total 656 Lead Dislodgement Number of Leads Enrolled in Study Failure to Capture 18 9 Cumulative Months of Follow-Up 32,177 4 Medical Judgment Failure to Sense 1 Number of Leads Active in Study 133 3 Impedance Out of Range Lead Survival Probability (%) 100 90 80 0 2 3 4 5 6 7 8 9 10 Years After Implant 6 yr 1 yr 2 yr 3 yr 4 yr 5 yr 7 yr 8 yr 9 yr 94.7 94.0 94.0 92.8 92.1 90.5 % 96.8 96.4 95.3 # 495 431 350 292 242 187 80 51 134 **Effective Sample Size**

4574 CapSure Sense

Product Characteristics

0	JS Market Release	Jun-02	Serial Num	ber Prefix	BBE		US Retur	ned Product Ana	alysis
R	Registered US Implants	61,000	Type and/o	r Fixation	Transvenous, Atrial-J, Tir	nes	Co	onductor Fracture	
E	Estimated Active US Implants	41,100	Polarity		Bipolar		(Crimp/Weld/Bond	
A	Advisories	None	Steroid		Yes			Insulation Breach	
								Other	
uct	Surveillance Registry Result	S		Qual	ifying Complications	2 Total			
N	Number of Leads Enrolled in Study		490		Lead Dislodgment	2			
c	Cumulative Months of Follow-Up	-	F14						
C	Lumulative Months of Follow-Op	Э,	514						
			382						
	Number of Leads Active in Study								
N									
N 100 90	Number of Leads Active in Study								
N 100	Number of Leads Active in Study								
N 100 90	Number of Leads Active in Study								
N 100 90	Number of Leads Active in Study								
N 100 90	Years After Implant 1 yr 2 y	r							
N 100 90 80	Number of Leads Active in Study	r							

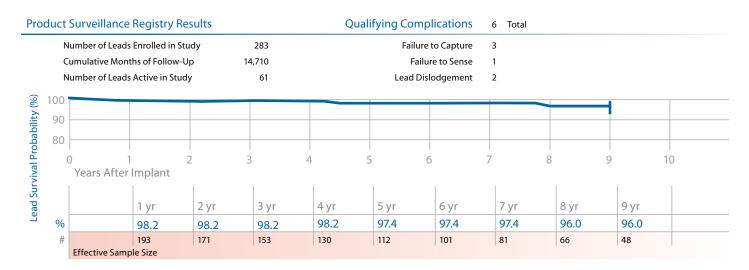
106 Medtronic CRDM Product Performance Report www.medtronic.com/CRDMProductPerformance

4592 CapSure SP Novus

Product Characteristics

Product Characteristics

US Market Release	Oct-98	Serial Number Prefix	LER	US Returned Product Analysi	s
Registered US Implants	85,400	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture	7
Estimated Active US Implants	40,800	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	17
				Other	1

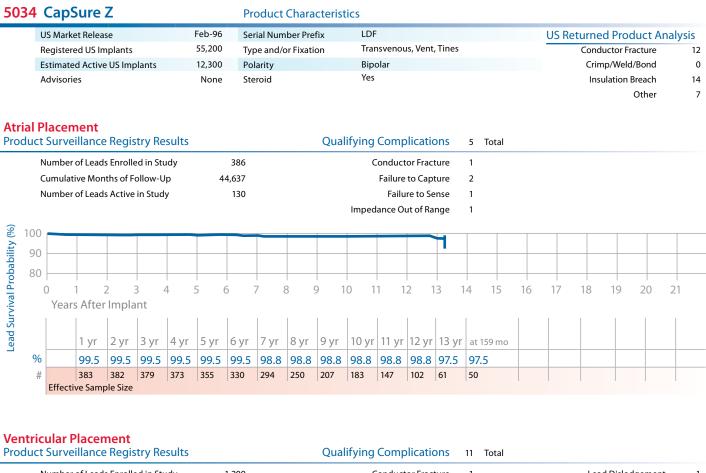


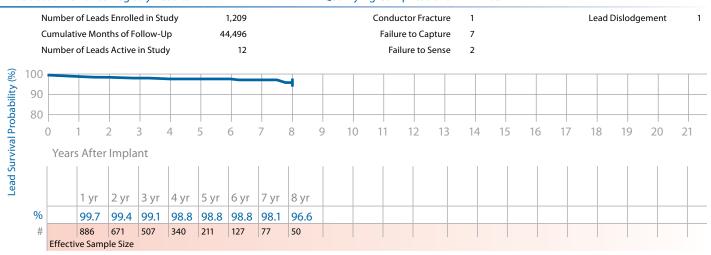
5024, 5024M CapSure SP

L L	JS Marke	t Relea	se			Mar-90	Ser	ial Num	ber Pref	ix	SY or	LAT					US R	eturne	d Prod	uct A	naly	/S
F	Registere	d US Im	plants		1	97,800	Тур	e and/c	or Fixatio	on	Trans	venous	Vent, Ti	ines				Condu	uctor Fra	octure		
E	stimated	d Active	US Imp	olants		42,400	Pola	arity			Bipol	ar						Crim	p/Weld/	/Bond		
A	Advisorie	s				None	Ste	roid			Yes							Insu	ulation B	reach		
																			(Other		
duct	Survei	llance	Regis	try Re	sults					Quali	fying (Compli	cation	1 <mark>5</mark> 5	7 Tota	ıl						
١	Number c	of Leads	s Enrolle	ed in Stu	ıdy	8	8,153				Co	nducto	r Fractui	re	3		Insula	tion (not	further	define	ed)	
C						444	1,024				Extra Ca	rdiac St	imulatio	n	2			Lea	ad Dislo	dgeme	ent	
٢	Number c	of Leads	s Active	in Stud	у		262				F	ailure to	o Captui	re 2	7		Other					
												Failure	to Sens	se	2		Other Oversensing				ng	
											Impeda	nce Out	of Rang	je	3		U	nspecifie				
												Insula	tion (ESC	C)	1			·				
100																						
90																						
80																						
	0 1		2 3	3 4	4 !	5 6	5 7	7 8	3 9) 10	0 11	12	13	14	15	16	17	18	19	20	21	
	Years	After	Impla	int																		
				2	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	16 yr	17 yr	at 207	mo		
		1 yr	2 yr	3 yr	T yı																	
%		1 yr 99.6	2 yr 99.6	3 yr 99.5	99.4	99.3	99.3	99.1	99.0	98.9		98.5	98.5	98.3	97.9	97.1	97.1	95.6	95.6			Ť

Leads

	C Marchard					eb-96	C i	- I. N.I I			LDK								-L D.	-l + . A	a a b
	S Market F				F				oer Prefi				Veet T			<u>(</u>	J2 Ke			duct A	naly
	egistered					2,300			r Fixatio	n		venous,	, vent, i	ines					uctor F		
E	stimated A	Active	US Imp	lants		500	Pola				Unip	olar							np/Weld		
A	dvisories					None	Ster	oid			Yes							Ins	ulation	Breach	
																				Other	
luct	Surveilla	ance	Regist	try Re	sults					Qualif	fying C	Compli	icatior	1 <mark>5</mark> 29	Total						
Ν	umber of	Leads	Enrolle	d in Stu	ıdy	1	,899				Ca	irdiac Pe	erforatio	on 1			Ir	npedan	ice Out	of Rang	e
C	umulative	Mont	hs of Fc	llow-U	р	100	,842				Co	nducto	r Fractu	re 8		In	sulati	on (not	further	defined	I)
Ν	umber of	Leads	Active	in Study	y		148				F	ailure to	o Captu	re 13				Lea	d Dislo	dgemer	t
																				5	
100																					
90																	_				
80					4 5		7			10	11	12	12	1.4	10	10	17	10	10	20	21
80		2		3 4	4 5	6	/	8	9	10) []	12	13	14	15	16	17	18	19	20	21
) 1	2	3																		
) 1 Years A	2 fter l		nt																	
	-	2 (fter		nt 																	
	Years A		Implai		4 vr	5 vr	6 vr	7 vr	8 vr	9 vr	10 vr	 11 vr	12 yr	13 yr	14 yr	at 177 mo					
	Years A	yr	Implai 2 yr	3 yr	4 yr	5 yr	б уг 98 3	7 yr	8 yr	9 yr		11 yr			14 yr	at 177 mo					
	Years A		Implai		4 yr 99.0 795	5 yr 98.8 658	6 yr 98.3 527	7 yr 97.7 416	8 yr 96.9 347			11 yr 95.6 188	12 yr 95.6	13 yr 94.9	14 yr 93.9 78	at 177 mo 93.9 45					





5054 CapSure Z Novus

Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEH	US Returned Product An	alysis
Registered US Implants	95,900	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture	10
Estimated Active US Implants	41,100	Polarity	Bipolar	Crimp/Weld/Bond	1
Advisories	None	Steroid	Yes	Insulation Breach	24
				Other	6

Atrial Placement

Product Surveillance Registry Results **Qualifying Complications** 2 Total Number of Leads Enrolled in Study 424 Failure to Capture 1 Cumulative Months of Follow-Up 33,362 Lead Dislodgement 1 Number of Leads Active in Study 156 100 bability (%) 90 80

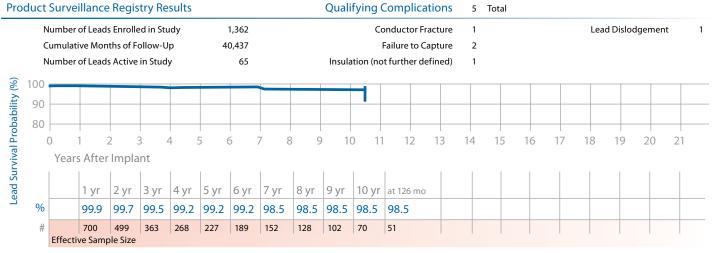
Pro	() 1		2	3	4	5	6	7	8	3	9	10
ival		Years After I	Implant										
NN													
ad S			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	
Lea	%		99.5	99.5	99.5	99.5	99.5	99.5	99.5	99.5	99.5	99.5	
	#		408	385	357	322	284	246	208	155	93	50	
		Effective Samp	le Size										

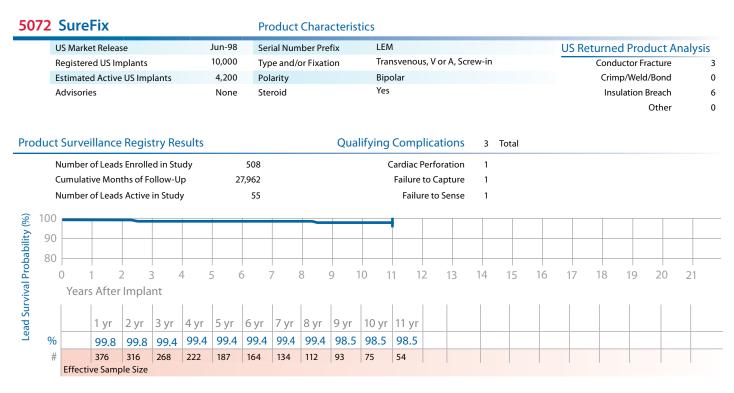
Ventricular Placement

roduc	t Surveillance	e Registry R	esults		Qı	ualifying Co	mplications	9 Total			
	Number of Lead Cumulative Mon Number of Lead	ths of Follow-	Up	967 39,207 92		F	ure to Capture ailure to Sense e Out of Range	6 1 1		Lead Dislo	odgement
100											-
90)										
90 80)										
	0 Years After		2	3	4	5	6	7	8	9	10
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	at 117 mo
%	5	99.5	99.4	99.4	99.1	99.1	97.9	97.9	97.9	97.9	97.9
#	ŧ	656	513	387	318	274	202	157	116	76	49
	Effective Sam	ple Size									

l	JS Marke	t Releas	e			Jan-97	Ser	ial Num	ber Pref	ix	LDJ						US R	eturne	d Pro	duct A	nalysi
F	Registere	d US Im	plants		1	02,400	Тур	e and/o	or Fixatic	on	Trans	venous, V	or A, Scr	ew-in					luctor F		
E	stimate	d Active	US Imp	olants		29,300	Pol	arity			Bipo	ar						Crin	np/Weld	l/Bond	
A	Advisorie	S				None	Ste	roid			Yes							Ins	ulation	Breach	
																				Other	
	lacem																				
luct	Survei	llance	Regis	try Re	sults					Quali	fying (Complica	tions	6	Total						
1	Number	of Leads	Enrolle	ed in Stu	ıdy		968				I	ailure to C	apture	2				Lea	d Dislo	dgemer	t
(Cumulati	ve Mont	ths of Fo	ollow-U	р	34	1,032				Impeda	nce Out of	Range	1					Ove	rsensin	g
1	Number	of Leads	Active	in Study	у		31			Insula	ition (no	t further de	efined)	1							
100																					
90																					
			1											1.4	15	16	17			20	21
80) 3	2	1 1			7 0) 1(11	10	12					10			
80	0	2	-	3 4	4 5	5 6) ,	7 8	3 9) 1() 11	12	13	14	15	10	17	18	19	20	21
80	•	I 2 After	-	-	1 1 <u>5</u>	5 6)) ,	, 7 8	3 9) 1(. 11	12	13	14	15	10	17	18	19	20	21
80	•		Impla	nt							10			14	15			18	19	20	21
80	•	1 yr	Impla 2 yr	nt 3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr) 11 10 yr	at 126 mo		14	15			18	19	20	21
80	Years	1 yr 99.6	Impla	nt) 11 10 yr 97.6 62			14				18	19	20	

Ventricular Placement





Registered US Implants 1,511,200 Type and/or Fixation Transvenous, V or A, Screw-in Estimated Active US Implants 956,100 Polarity Bipolar Advisories None Steroid Yes trial Placement Qualifying Complications 26 Total roduct Surveillance Registry Results Qualifying Complications 26 Total Number of Leads Enrolled in Study 2,744 Cardiac Perforation 1 Im Cumulative Months of Follow-Up 139,060 Conductor Fracture 2 Insulation Number of Leads Active in Study 648 Extra Cardiac Stimulation 2 Failure to Capture 6 Failure to Sense 2 Unsp 0 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 Years After Implant Up and the second Years After Implant Years After Implant Years Ye		US	5 Mar	rket Relea	se		ļ	Aug-00	Sei	ial Num	ber Pref	ix	PJN						US Re	turne	d Produc	ct Ana	lysi
Advisories None Steroid Yes trial Placement oduct Surveillance Registry Results Qualifying Complications 26 Total Number of Leads Enrolled in Study 2,744 Cardiac Perforation 1 Im Cumulative Months of Follow-Up 139,060 Conductor Fracture 2 Insulation Number of Leads Active in Study 648 Extra Cardiac Stimulation 2 Failure to Capture 6 Failure to Sense 2 Unsp		Re	egiste	ered US In	nplants		1,5	511,200	Тур	oe and/o	r Fixatic	n	Tran	svenous, V	or A, Scr	ew-in					ictor Fract		4
Indice Second trial Placement Qualifying Complications 26 Total Number of Leads Enrolled in Study 2,744 Cardiac Perforation 1 Im Cumulative Months of Follow-Up 139,060 Conductor Fracture 2 Insulation Number of Leads Active in Study 648 Extra Cardiac Stimulation 2 Failure to Capture 6 Failure to Sense 2 Unsp					e US Imp	olants	ç							lar							p/Weld/Bo		
Deduct Surveillance Registry Results Qualifying Complications 26 Total Number of Leads Enrolled in Study 2,744 Cardiac Perforation 1 Im Cumulative Months of Follow-Up 139,060 Conductor Fracture 2 Insulation Number of Leads Active in Study 648 Extra Cardiac Stimulation 2 Insulation Number of Leads Active in Study 648 Extra Cardiac Stimulation 2 Unsulative to Capture 6 Failure to Sense 2 Unsulative to Sense 2 Unsulative to Sense 2 Unsulative to Sense 0 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 Years After Implant Image: Sense Sense 1 Image: Sense Sense 10 Image: Sense Sense 10 11 12 13 14 15 16 17		Ac	dviso	ories				None	Ste	roid			Yes							Insu	lation Brea Otl	ach her	:
Number of Leads Enrolled in Study 2,744 Cardiac Perforation 1 Im Cumulative Months of Follow-Up 139,060 Conductor Fracture 2 Insulation Number of Leads Active in Study 648 Extra Cardiac Stimulation 2 Failure to Capture 6 6 Failure to Sense 2 Unsp	ial	Pla	ace	ment																			
Cumulative Months of Follow-Up Number of Leads Active in Study 648 Extra Cardiac Stimulation Failure to Capture 6 Failure to Sense 2 Unsp 0 0 1 2 Unsp 0 0 1 2 Unsp 0 0 0 1 2 0 1 1 1 1 1 1 1 1 1 1 1 1 1	du											Quali		-			Total						
Number of Leads Active in Study 648 Extra Cardiac Stimulation 2 Failure to Capture 6 Failure to Sense 2 Unsp 0 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 Years After Implant							-													-	e Out of R	-	
Failure to Capture 6 Failure to Sense 2 Unsp							•	13										I	nsulatio	•			
Failure to Sense 2 Unsp Po Po Po Po Po Po Po Po Po Po		INU	umbe	er of Lead	s Active	in Stud	У		048											Lead	Dislodge Oversei		
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80 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 Years After Implant													-										
0 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 Years After Implant	9	90																					_
Years After Implant	C	2n L																					
	C	50																					
	C	0				-	4	5	6	7	8 9	9 1	0 1	1 12	13	14	15	16	17	18	19	20	2
$1 \sqrt{r}$ $2 \sqrt{r}$ $3 \sqrt{r}$ $4 \sqrt{r}$ $5 \sqrt{r}$ $6 \sqrt{r}$ $7 \sqrt{r}$ $8 \sqrt{r}$ $9 \sqrt{r}$ $10 \sqrt{r}$ $2 + 122 m_0$	C	0				-	4	5	6	7	8 9	9 1	0 1	1 12	13	14	15	16	17	18	19	20	2
	C	0		ars After	- Impla	nt										14	15	16	17	18	19	20	2
		0		ars After	⁻ Impla 2 yr	ant 3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	at 123mc		14	15	16	17	18	19	20	2
Effective Sample Size		%		ars After 1 yr 99.6	⁻ Impla 2 yr 99.6	3 yr 99.3	4 yr 99.0	5 yr 98.8	6 yr 98.6	7 yr 98.6	8 yr 98.5	9 yr 98.5	10 yr 97.8	at 123mc 97.8		14	15	16	17	18	19	20	2
nont	0 1 Years After 1 yr % 99.6 # 2,084	Years After 1 yr 99.6 2,084	1 yr 99.6 2,084		⁻ Impla 2 yr 99.6 1,784	3 yr 99.3	4 yr	5 yr 98.8	6 yr	7 yr	8 yr	9 yr	10 yr	at 123mc		14	15	16	17	18	19	20	21
	tr	% #	Yea Effec	1 yr 99.6 2,084 ttive Samp	2 yr 99.6 1,784 ble Size	3 yr 99.3 1,527	4 yr 99.0 1,314	5 yr 98.8	6 yr 98.6	7 yr 98.6	8 yr 98.5	9 yr 98.5 215	10 yr 97.8 82	at 123mc 97.8 53)			16	17	18	19	20	21
Qualifying Complications 12 Total Number of Leads Enrolled in Study 1,539 Cardiac Perforation 1	htr	% # :icu	Yea Effec	1 yr 99.6 2,084 Placer Yeillance	2 yr 99.6 1,784 bole Size	3 yr 99.3 1,527	4 yr 99.0 1,314	5 yr 98.8 1,112	6 yr 98.6 902	7 yr 98.6	8 yr 98.5	9 yr 98.5 215	10 yr 97.8 82	at 123mo 97.8 53	tions	12		16			Failure to S	Sense	21
duct Surveillance Registry Results Qualifying Complications 12 Total Number of Leads Enrolled in Study 1,539 Cardiac Perforation 1	ntr	% # ricu ct S	Yea Effec	1 yr 99.6 2,084 tive Samp Placer (eillance er of Lead	2 yr 99.6 1,784 pole Size nent e Regis	3 yr 99.3 1,527	4 yr 99.0 1,314 esults	5 yr 98.8 1,112	6 yr 98.6 902	7 yr 98.6	8 yr 98.5	9 yr 98.5 215	10 yr 97.8 82 fying (at 123mc 97.8 53 Complica ardiac Perfo	tions	12		16				Sense	2
duct Surveillance Registry Results Qualifying Complications 12 Total Number of Leads Enrolled in Study 1,539 Cardiac Perforation 1	ntr	% # Cct S Nu Cu	Yea Effec	ars After 1 yr 99.6 2,084 tive Samp Placer veillance er of Lead ative Mon	2 yr 99.6 1,784 ole Size e Regis s Enrolle	3 yr 99.3 1,527	4 yr 99.0 1,314 esults udy	5 yr 98.8 1,112	6 yr 98.6 902	7 yr 98.6	8 yr 98.5	9 yr 98.5 215	10 yr 97.8 82 fying (at 123mc 97.8 53 Complica ardiac Perfc onductor Fr	tions pration acture	12		16		npedano	Failure to S	Gense	2
Number of Leads Enrolled in Study 1,539 Cardiac Perforation 1 Cumulative Months of Follow-Up 67,711 Conductor Fracture 1 Im	n t r du	% # ct S Nu Cu Nu	Yea Effec	ars After 1 yr 99.6 2,084 tive Samp Placer veillance er of Lead ative Mon	2 yr 99.6 1,784 ole Size e Regis s Enrolle	3 yr 99.3 1,527	4 yr 99.0 1,314 esults udy	5 yr 98.8 1,112	6 yr 98.6 902	7 yr 98.6	8 yr 98.5	9 yr 98.5 215	10 yr 97.8 82 fying (at 123mc 97.8 53 Complica ardiac Perfc onductor Fr	tions pration acture	12		16		npedano	Failure to Stee Out of R	Gense	2
duct Surveillance Registry Results Qualifying Complications 12 Total Number of Leads Enrolled in Study 1,539 Cardiac Perforation 1 Cumulative Months of Follow-Up 67,711 Conductor Fracture 1 Im Number of Leads Active in Study 276 Failure to Capture 5	ntr du 10	% # Nu Ct S Nu Nu	Yea Effec	ars After 1 yr 99.6 2,084 tive Samp Placer veillance er of Lead ative Mon	2 yr 99.6 1,784 ole Size e Regis s Enrolle	3 yr 99.3 1,527	4 yr 99.0 1,314 esults udy	5 yr 98.8 1,112	6 yr 98.6 902	7 yr 98.6	8 yr 98.5	9 yr 98.5 215	10 yr 97.8 82 fying (at 123mc 97.8 53 Complica ardiac Perfc onductor Fr	tions pration acture	12		16		npedano	Failure to Stee Out of R	Gense	2
duct Surveillance Registry ResultsQualifying Complications12TotalNumber of Leads Enrolled in Study1,539Cardiac Perforation1Cumulative Months of Follow-Up67,711Conductor Fracture1ImNumber of Leads Active in Study276Failure to Capture5	ntr du 10	0 % # Ct 2 Nu Cu Nu 00	Yea Effec	ars After 1 yr 99.6 2,084 tive Samp Placer veillance er of Lead ative Mon	2 yr 99.6 1,784 ole Size e Regis s Enrolle	3 yr 99.3 1,527	4 yr 99.0 1,314 esults udy	5 yr 98.8 1,112	6 yr 98.6 902	7 yr 98.6	8 yr 98.5	9 yr 98.5 215	10 yr 97.8 82 fying (at 123mc 97.8 53 Complica ardiac Perfc onductor Fr	tions pration acture	12		16		npedano	Failure to Stee Out of R	Gense	2

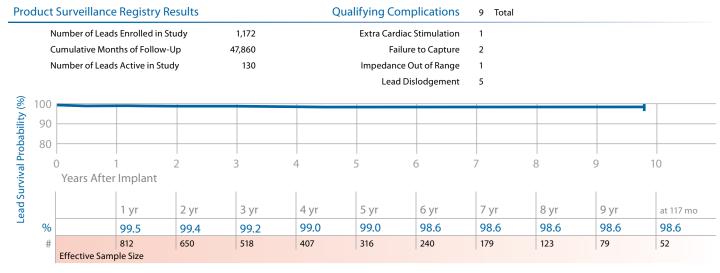
5086MRI CapSureFix Novus **Product Characteristics** US Market Release Feb-11 Serial Number Prefix LFP **US Returned Product Analysis** 102,900 Transvenous, A or V, Screw-in **Registered US Implants Conductor Fracture** 3 Type and/or Fixation 99,700 **Estimated Active US Implants** Polarity Bipolar Crimp/Weld/Bond 0 Yes Advisories None Steroid Insulation Breach 3 Other 12 Product Surveillance Registry Results **Qualifying Complications** 1 Total Number of Leads Enrolled in Study 2,406 Lead Dislodgement 1 13,080 Cumulative Months of Follow-Up Number of Leads Active in Study 2,225 Lead Survival Probability (%) 100 90 80 0 2 3 4 5 6 8 9 10 Years After Implant 1 yr at 15 mo % 99.9 99.9 182 56 # **Effective Sample Size Ventricular Placement** Product Surveillance Registry Results **Qualifying Complications** 2 Total Number of Leads Enrolled in Study 2,397 Failure to Capture 1 Cumulative Months of Follow-Up Lead Dislodgement 13,008 1 Number of Leads Active in Study 2,220

90										
30										
	1	2	2	4	5	6	7	8	9	10
0		2	2	-	0					
0 Years	After Implant	2	S	-	9					
0 Years	After Implant	2	5							
0 Years	After Implant	2 at 15 mo	5							
Vears		2 at 15 mo 99.9								

5092 CapSure SP Novus

Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LET	US Returned Product Ana	lysis
Registered US Implants	132,700	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture	10
Estimated Active US Implants	60,800	Polarity	Bipolar	Crimp/Weld/Bond	0
dvisories	None	Steroid	Yes	Insulation Breach	38
				Other	5



5524, 5524M CapSure SP

Number of Leads Active in Study

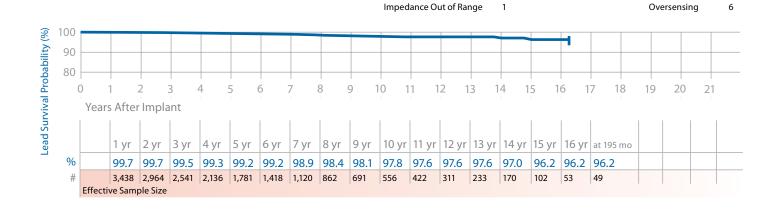
Product Characteristics

233

US Market Release	Mar-90	Serial Number	Prefix	XV or LAV		US Returned Prod	uct Anal	ysis
Registered US Implants	59,400	Type and/or Fix	xation	Transvenous, Atrial-J, Ti	nes	Conductor Fra	cture	11
Estimated Active US Implants	15,800	Polarity		Bipolar		Crimp/Weld/	Bond	2
Advisories	None	Steroid		Yes		Insulation B	each	11
						C	Other	3
oduct Surveillance Registry Resu	ılts		Quali	fying Complications	41 Total			
Number of Leads Enrolled in Study	/ 4,4	496		Conductor Fracture	1	Insulation (not further d	efined)	1
Cumulative Months of Follow-Up	255,3	338		Failure to Capture	23	Lead Dislodg	ement	4

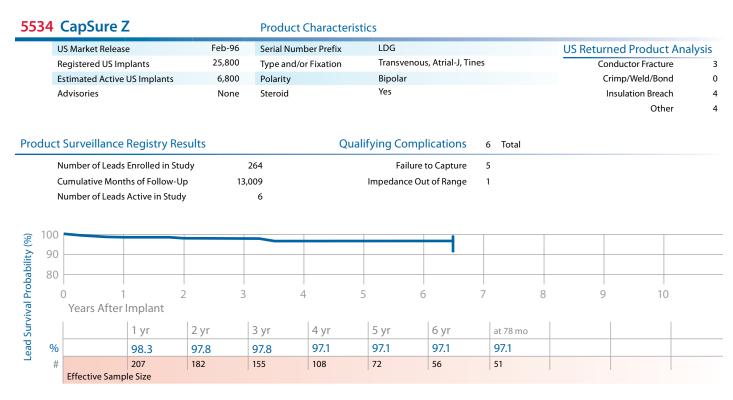
Failure to Sense

4

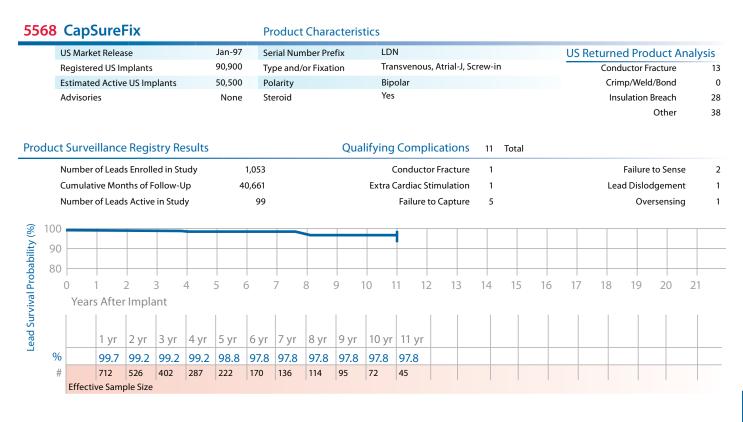


Other

1



ι	JS Market Relea	e	Jun-98	Serial Nu	mber Prefix	LEJ			US R	eturned P	roduct Ana	lysis
F	Registered US Im	plants	62,000	Type and	l/or Fixation	Transve	enous, Atrial-J, Tir	ies		Conducto		ç
E	Estimated Active	US Implants	29,200	Polarity		Bipolar				Crimp/W	/eld/Bond	0
/	Advisories		None	Steroid		Yes				Insulation	on Breach	18
											Other	1
duct	Surveillance	Registry Re	esults		Qu	alifying Co	mplications	4 Total				
1	Number of Leads	Enrolled in St	udy	344		Fai	lure to Capture	1		C	Oversensing	1
(Cumulative Mon	ths of Follow-L	Jp 1:	5,784		Impedanc	e Out of Range	1				
1	Number of Leads	Active in Stud	ly	35		Lead	l Dislodgement	1				
100												
90												
80												
	0 '		2 3	3	4	5	6	7	8	9	10	
	Years After		<u> </u>	, ,	I	5	0	7	0	2	10	
		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	at 78 mo				
				00.7	98.2	98.2	98.2	98.2				
%		100.0	99.2	98.7	50.2	20.2	20.2	20.2				
% #		100.0 273	99.2 227	182	159	137	80	49				



5592	2 CapSure	SP Novus	5	Produc	t Characteris	stics					
	US Market Relea	ase	Jun-98	Serial Nu	mber Prefix	LEU			US Re	turned Product Ar	nalysis
	Registered US Ir	mplants	34,500	Type and	l/or Fixation	Transvenc	ous, Atrial-J, Tin	es		Conductor Fracture	4
	Estimated Activ	e US Implants	18,900	Polarity		Bipolar				Crimp/Weld/Bond	0
	Advisories		None	Steroid		Yes				Insulation Breach	4
										Other	0
Produ	ct Surveillance	e Registry Re	esults		Qua	alifying Com	plications	5 Total			
	Number of Lead	ds Enrolled in Stu	udy	672		Failur	e to Capture	3			
	Cumulative Mor	nths of Follow-L	Jp 31	,062		Lead Di	slodgement	2			
	Cumulative Months of Follow-Up Number of Leads Active in Study			112							
8 10	0										
	90										
ilide											
jobi	30										
al Pi	0	1	2 3		4	5	6	7	8	9 10	
viv	Years Afte	r Implant									
Sun											
Lead Survival Probability (%)		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	at 105 mo	
	%	99.7	99.3	99.3	98.9	98.9	98.9	98.9	98.9	98.9	
	#	517	434	347	283	219	153	111	81	54	
	Effective Sam	nple Size									

5594 CapSure SP Novus

Product Characteristics

US Market Release	Jun-01	Serial Number Prefix	LFD	US Returned Product Analysis
Registered US Implants	15,800	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 5
Estimated Active US Implants	10,300	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 7
				Other 1

Product Surveillance Registry Results

Qualifying Complications 0 Total

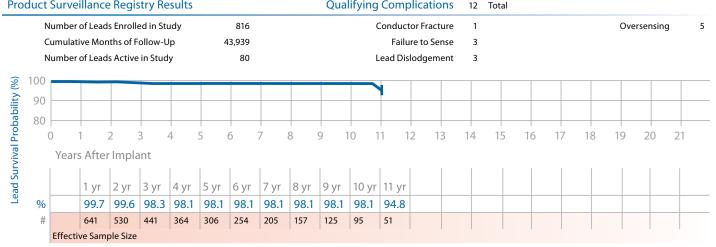
Number of Leads Enrolled in Study	20
Cumulative Months of Follow-Up	1,515
Number of Leads Active in Study	10

90	Surritures			insufficient sar							
80											
	0	1	2	3	4	5	6	7	8	9	10
	Years Aft	er Implar	nt								
	Years Aft	er Implar	nt								
%		er Implar	nt								

6940 CapSureFix

Product Characteristics

•					
US Market Release	Oct-98	Serial Number Prefix	ТСР	US Returned Product Ana	lysis
Registered US Implants	25,400	Type and/or Fixation	Transvenous, Atrial-J , Screw-in	Conductor Fracture	12
Estimated Active US Implants	7,200	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	17
				Other	15
duct Surveillance Registry Results		Qualify	ving Complications 12 Total		



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Pacing Leads continued	Pacing	Leads	continued
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	3							I				
	-	20 yr										
		18 yr										
		16 yr										
	-	14 yr				86.2 +4.4/-6.3 at 165 mo	89.7 +3.7/-5.6 at 147 mo					
	-	12 yr				91.4 +2.3/-3.2	89.7 +3.7/-5.6					
	-	10 yr			98.8 +1/-5.0 at 117 mo	93.7 +1.6/-2.1	93.1 +2.0/-2.8					97.7 +0.8/-1.3 at 117 mo
		8 yr			99.8 +0.1/-0.7	95.3 +1.2/-1.6	95.0 +1.4/-2.0	99.1 +0.7/-2.8 at 90 mo	99.5 +0.3/-1.1 at 93 mo			97.7 +0.8/-1.3
		7 yr			99.8 +0.1/-0.7	96.7 +0.9/-1.2	95.8 +1.2/-1.7	99.1 +0.7/-2.8	99.5 +0.3/-1.1	98.9 +0.7/-2.3 at 75 mo	99.0 +0.7/-1.6 at 78 mo	97.7 +0.8/-1.3
	_	6 yr	99.2 +0.4/-1.1 at 63 mo	99.5 +0.4/-1.3 at 69 mo	99.8 +0.1/-0.7	97.2 +0.7/-1.0	97.2 +0.8/-1.3	99.1 +0.7/-2.8	99.5 +0.3/-1.1	98.9 +0.7/-2.3	99.0 +0.7/-1.6	97.7 +0.8/-1.3
	-	5 yr	99.2 +0.4/-1.1	99.5 +0.4/-1.3	99.8 +0.1/-0.7	97.4 +0.7/-0.9	97.8 +0.7/-1.1	99.1 +0.7/-2.8	99.5 +0.3/-1.1	99.5 +0.3/-0.6	99.0 +0.7/-1.6	98.1 +0.7/-1.2
ity (%)		4 yr	99.2 +0.4/-1.1	99.5 +0.4/-1.3	99.8 +0.1/-0.7	98.0 +0.5/-0.8	98.2 +0.6/-1.0	99.1 +0.7/-2.8	99.5 +0.3/-1.1	99.5 +0.3/-0.6	99.7 +0.2/-0.7	98.4 +0.6/-1.1
ice Survival Probability (%)	ant	3 yr	99.2 +0.4/-1.1	99.5 +0.4/-1.3	99.8 +0.1/-0.7	98.2 +0.5/-0.7	98.7 +0.5/-0.7	99.1 +0.7/-2.8	99.5 +0.3/-1.1	99.5 +0.3/-0.6	99.7 +0.2/-0.7	98.7 +0.5/-1.0
Survival	Years After Implant	2 yr	99.2 +0.4/-1.1	99.5 +0.4/-1.3	99.8 +0.1/-0.7	98.7 +0.4/-0.6	98.7 +0.5/-0.7	99.1 +0.7/-2.8	99.5 +0.3/-1.1	99.6 +0.2/-0.5	99.8 +0.2/-0.5	98.8 +0.5/-0.9
Device	Years A	1 yr	99.2 +0.4/-1.1	99.5 +0.4/-1.3	99.9 +0.1/-0.5	98.9 +0.4/-0.5	99.3 +0.3/-0.6	99.1 +0.7/-2.8	99.7 +0.2/-0.8	99.8 +0.1/-0.5	99.8 +0.2/-0.5	98.9 +0.5/-0.9
sdtnoM γbut2 ni q			22,098	15,455	50,928	133,591	95,888	14,960	30,769	59,076	46,434	65,701
sue		filenØ qmoጋ	9	m	4	77	51	2	m	8	5	19
γbut2 ni e			509	290	13	266	162	137	691	1,017	744	293
pəj	Enrol	speəJ	769	475	1,215	2,413	1,799	214	956	1,662	1,229	1,147
əseələ	nket R	₽W SN	Aug-05	Aug-05	Oct-91	Mar-96	Mar-96	Jun-02	Jun-02	Feb-04 1,662	Feb-04	Sep-98
	þer	medD	Atrial	Vent	Vent	Atrial	Vent	Atrial	Vent	Atrial	Vent	Vent
	M	(lims7	SelectSecure	SelectSecure	CapSure SP	CapSureFix	CapSureFix	CapSure Sense	CapSure Sense	CapSureFix Novus	CapSureFix Novus	CapSure SP Novus
		əboM dmuV	3830	3830	4024	4068	4068	4074	4074	4076	4076	4092

Lead Survival Summary (95% Confidence Interval)

ing				nunue	9								
		20 yr											
		18 yr						95.6 +2.3/-4.6 at 207 mo					
		16 yr						97.1 +1.2/-2.1	93.9 +2.4/-3.7 at 177 mo				
		14 yr						97.9 +0.8/-1.2	93.9 +2.4/-3.7	97.5 +1.7/-5.4 at 159 mo			
		12 yr	99.0 +0.6/-1.2 at 126 mo					98.5 +0.5/-0.7	95.6 +1.5/-2.4	98.8 +0.8/-1.9			
		10 yr	99.0 +0.6/-1.2	91.8 +4.3/-8.8 at 9 yr	90.5 +3.5/-5.4 at 9 yr		96.0 +2.4/-5.7 at 9 yr	98.8 +0.3/-0.6	96.0 +1.4/-2.1	98.8 +0.8/-1.9		99.5 +0.4/-1.4	97.9 +1.1/-2.4 at 117 mo
		8 yr	99.0 +0.6/-1.2	96.5 +2.1/-5.2	92.1 +2.5/-3.6		96.0 +2.4/-5.7	99.0 +0.3/-0.4	96.9 +1.1/-1.7	98.8 +0.8/-1.9	96.6 +2.1/-5.7	99.5 +0.4/-1.4	97.9 +1.1/-2.4
		7 yr	99.0 +0.6/-1.2	96.5 +2.1/-5.2	92.8 +2.3/-3.2		97.4 +1.5/-3.8	99.1 +0.3/-0.3	97.7 +0.9/-1.3	98.8 +0.8/-1.9	98.1 +1.1/-2.8	99.5 +0.4/-1.4	97.9 +1.1/-2.4
		6 yr	99.0 +0.6/-1.2	97.6 +1.6/-4.2	94.0 +1.8/-2.6		97.4 +1.5/-3.8	99.3 +0.2/-0.3	98.3 +0.7/-1.2	99.5 +0.4/-1.6	98.8 +0.6/-1.1	99.5 +0.4/-1.4	97.9 +1.1/-2.4
		5 yr	99.0 +0.6/-1.2	99.3 +0.5/-1.4	94.0 +1.8/-2.6		97.4 +1.5/-3.8	99.3 +0.2/-0.2	98.8 +0.5/-0.9	99.5 +0.4/-1.6	98.8 +0.6/-1.1	99.5 +0.4/-1.4	99.1 +0.5/-1.2
lity (%)		4 yr	99.0 +0.6/-1.2	99.3 +0.5/-1.4	94.7 +1.6/-2.5		98.2 +1.1/-3.0	99.4 +0.2/-0.2	99.0 +0.5/-0.7	99.5 +0.4/-1.6	98.8 +0.6/-1.1	99.5 +0.4/-1.4	99.1 +0.5/-1.2
evice Survival Probability (%)	lant	3 yr	99.3 +0.4/-1.0	99.3 +0.5/-1.4	95.3 +1.5/-2.2		98.2 +1.1/-3.0	99.5 +0.1/-0.3	99.1 +0.4/-0.7	99.5 +0.4/-1.6	99.1 +0.4/-1.0	99.5 +0.4/-1.4	99.4 +0.3/-0.9
Surviva	Years After Implant	2 yr	99.3 +0.4/-1.0	99.3 +0.5/-1.4	96.4 +1.3/-1.9	99.5 +0.4/-1.5	98.2 +1.1/-3.0	99.6 +0.1/-0.2	99.6 +0.2/-0.4	99.5 +0.4/-1.6	99.4 +0.3/-0.8	99.5 +0.4/-1.4	99.4 +0.3/-0.9
Device	Years A	1 yr	99.6 +0.3/-0.7	99.3 +0.5/-1.4	96.8 +1.2/-1.8	99.5 +0.4/-1.5	98.2 +1.1/-3.0	99.6 +0.1/-0.2	99.7 +0.2/-0.4	99.5 +0.4/-1.6	99.7 +0.2/-0.6	99.5 +0.4/-1.4	99.5 +0.3/-0.8
stin Study Months			40,725	23,289	32,177	5,514	14,710	444,024	100,842	44,637	44,496	33,362	39,207
su	pniy vitsci	Qualifi IqmoD	9	12	35	7	9	57	29	5	11	2	6
۲put2 ni ه	əvitəA	sbeəJ	35	9	133	382	61	262	148	130	12	156	92
pə	Enroll	sbeəJ	911	539	656	490	283	8,153	1,899	386	1,209	424	967
əscələ	rket R	₽W SU	Oct-91	Nov-94	Jan-97	Jun-02	Oct-98	Mar-90	Feb-96	Feb-96	Feb-96	Jun-98	Jun-98
)êr	վաթվշ	Atrial	Atrial	Atrial	Atrial	Atrial	Vent	Vent	Atrial	Vent	Atrial	Vent
		۷lime٦	CapSure SP	Screw-In	CapSureFix	CapSure Sense	CapSure SP Novus	CapSure SP	CapSure Z	CapSure Z	CapSure Z	CapSure Z Novus	CapSure Z Novus
		ləboM dmuN	4524	4558M	4568	4574	4592	5024, 5024M	5033	5034	5034	5054	5054

Lead Survival Summary continued

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		20 yr															
		18 yr									96.2 +1.6/-2.7 at 195 mo						
		16 yr									96.2 +1.6/-2.7						
		14 yr									97.0 +1.1/-1.7						
	-	12 yr	97.6 +1.6/-4.2 at 126 mo	98.5 +1/.0-2.5 at 126 mo	98.5 +1.1/-4 at 11 yr	97.8 +1.1/-1.9 at 123 mo					97.6 +0.7/-1.2			97.8 +1.2/-2.6 at 11 yr			94.8 +3.1/-7.5 at 11 yr
		10 yr	97.6 +1.6/-4.2	98.5 +1.0/-2.5	98.5 +1.1/-4	97.8 +1.1/-1.9	98.0 +1.2/-2.5 at 117 mo			98.6 +0.7/-1.6 at 117 mo	97.8 +0.7/-1.1			97.8 +1.2/-2.6	98.9 +0.7/-1.6 at 105 mo		98.1 +0.9/-1.6
	-	8 yr	97.6 +1.6/-4.2	98.5 +1.0/-2.5	99.4 +0.5/-1.7	98.5 +0.5/-0.9	98.8 +0.6/-1.1			98.6 +0.7/-1.6	98.4 +0.5/-0.7			97.8 +1.2/-2.6	98.9 +0.7/-1.6		98.1 +0.9/-1.6
		7 yr	99.3 +0.5/-1.2	98.5 +1.0/-2.5	99.4 +0.5/-1.7	98.6 +0.5/-0.7	98.8 +0.6/-1.1			98.6 +0.7/-1.6	98.9 +0.4/-0.5	97.1 +1.6/-3.5 at 78 mo	98.2 +1.1/-3.0 at 78 mo	97.8 +1.2/-2.6	98.9 +0.7/-1.6		98.1 +0.9/-1.6
		6 yr	99.3 +0.5/-1.2	99.2 +0.5/-1.6	99.4 +0.5/-1.7	98.6 +0.5/-0.7	98.8 +0.6/-1.1			98.6 +0.7/-1.6	99.2 +0.2/-0.5	97.1 +1.6/-3.5	98.2 +1.1/-3.0	97.8 +1.2/-2.6	98.9 +0.7/-1.6		98.1 +0.9/-1.6
		5 yr	99.3 +0.5/-1.2	99.2 +0.5/-1.6	99.4 +0.5/-1.7	98.8 +0.4/-0.6	99.0 +0.5/-0.9			99.0 +0.5/-1.2	99.2 +0.3/-0.4	97.1 +1.6/-3.5	98.2 +1.1/-3.0	98.8 +0.7/-1.6	98.9 +0.7/-1.6		98.1 +0.9/-1.6
ity (%)		4 yr	99.3 +0.5/-1.2	99.2 +0.5/-1.6	99.4 +0.5/-1.7	99.0 +0.4/-0.6	99.0 +0.5/-0.9			99.0 +0.5/-1.2	99.3 +0.3/-0.4	97.1 +1.6/-3.5	98.2 +1.1/-3.0	99.2 +0.4/-1.0	98.9 +0.7/-1.6		98.1 +0.9/-1.6
Probabil	ant	3 yr	99.3 +0.5/-1.2	99.5 +0.3/-1.2	99.4 +0.5/-1.7	99.3 +0.3/-0.4	99.3 +0.4/-0.7			99.2 +0.4/-0.9	99.5 +0.2/-0.3	97.8 +1.3/-3.0	98.7 +0.9/-2.6	99.2 +0.4/-1.0	99.3 +0.4/-1.3		98.3 +0.8/-1.5
Device Survival Probability (%)	Years After Implant	2 yr	99.6 +0.3/-0.9	99.7 +0.2/-0.9	99.8 +0.2/-1.4	99.6 +0.2/-0.4	99.4 +0.3/-0.6	99.9 +0.1/-0.4 at 15 mo	99.9 +0.1/-0.3 at 15 mo	99.4 +0.3/-0.8	99.7 +0.1/-0.2	97.8 +1.3/-3.0	99.2 +0.6/-2.4	99.2 +0.4/-1.0	99.3 +0.4/-1.3		99.6 +0.3/-1.0
Device	Years A	1 yr	99.6 +0.3/-0.9	99.9 +0.1/-0.8	99.8 +0.2/-1.4	99.6 +0.2/-0.3	99.6 +0.2/-0.5	99.9 +0.1/-0.4	99.9 +0.1/-0.3	99.5 +0.3/-0.7	99.7 +0.2/-0.2	98.3 +1.1/-2.7	100.0	99.7 +0.2/-0.7	99.7 +0.2/-1.1	100.0 at 0 mo	99.7 +0.2/-0.8
sdtnoM γbut2 ni q			34,032	40,437	27,962	139,060	67,711	13,080	13,008	47,860	255,338	13,009	15,784	40,661	31,062	1,515	43,939
sue	ying oitecil	tileuQ qmoD	9	Ś	m	26	12	-	2	6	4	9	4	11	Ω	0	12
ې nt Study	evitoA	speəŋ	31	65	55	648	276	2,225	2,220	130	233	9	35	66	112	10	80
pə	Enroll	speəJ	968	1,362	508	2,744	1,539	2,406	2,397	1,172	4,496	264	344	1,053	672	20	816
əseələ	rket B	eM 2U	Jan-97	Jan-97	96-unſ	Aug-00	Aug-00	Feb-11	Feb-11	Jun-98	Mar-90	Feb-96	Jun-98	Jan-97	Jun-98	Jun-01	Oct-98
	þer	medD	Atrial	Vent	A or V	Atrial	Vent	Atrial	Vent	Vent	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial
	,	(lime7	CapSureFix	CapSureFix	SureFix	CapSureFix Novus	CapSureFix Novus	CapSureFix Novus	CapSureFix Novus	CapSure SP Novus	CapSure SP	CapSure Z	CapSure Z Novus	CapSureFix	CapSure SP Novus	CapSure SP Novus	CapSureFix
e: Medtroi	I	ləboM dmuN	5068	5068	5072	5076	5076	5086MRI	5086MRI	5092	5524, 5524M	5534	5554	5568	5592	2207 Product	6940

Source: Medtronic Device Registration and Returned Product Analysis Data as of February 1, 2013

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Insulation Breach	Crimp/ Weld/Bond	Other
3830	SelectSecure	Aug-05	20,900	15,900	4	12	0	4
4024	CapSure SP	Oct-91	217,500	41,100	27	178	0	16
4068	CapSureFix	Mar-96	123,800	30,300	50	163	0	95
4074	CapSure Sense	Jun-02	91,300	57,100	2	20	0	1
4076	CapSureFix Novus	Feb-04	432,000	332,400	33	33	1	24
4092	CapSure SP Novus	Sep-98	177,000	80,400	9	48	0	3
4524	CapSure SP	Oct-91	99,500	23,400	1	64	0	6
4558M	Screw-in	Nov-94	19,400	3,800	1	18	0	20
4568	CapSureFix	Jan-97	69,100	21,500	3	81	0	53
4574	CapSure Sense	Jun-02	61,000	41,100	5	3	0	0
4592	CapSure SP Novus	Oct-98	85,400	40,800	7	17	0	1
5024, 5024M	CapSure SP	Mar-90	197,800	42,400	53	56	1	17
5033	CapSure Z	Feb-96	2,300	500	1	0	0	3
5034	CapSure Z	Feb-96	55,200	12,300	12	14	0	7
5054	CapSure Z Novus	Jun-98	95,900	41,100	10	24	1	6
5068	CapSureFix	Jan-97	102,400	29,300	40	56	2	83
5072	SureFix	Jun-98	10,000	4,200	3	6	0	0
5076	CapSureFix Novus	Aug-00	1,511,200	956,100	404	422	0	204
5086MRI	CapSureFix Novus MRI	Feb-11	102,900	99,700	3	3	0	12
5092	CapSure SP Novus	Jun-98	132,700	60,800	10	38	0	5
5524, 5524M	CapSure SP	Mar-90	59,400	15,800	11	11	2	3
5534	CapSure Z	Feb-96	25,800	6,800	3	4	0	4
5554	CapSure Z Novus	Jun-98	62,000	29,200	9	18	0	1
5568	CapSureFix	Jan-97	90,900	50,500	13	28	0	38
5592	CapSure SP Novus	Jun-98	34,500	18,900	4	4	0	0
5594	CapSure SP Novus	Jun-01	15,800	10,300	5	7	0	1
6940	CapSureFix	Oct-98	25,400	7,200	12	17	0	15

Source: Returned Product Analysis Data as of February 1, 2013

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure to Sense		Extracardiac Stimulation	Impedance Abnormal	Unspecified
3830	SelectSecure	20,900	5	1	27	14	3	1	1	0	0	2
4024	CapSure SP	217,500	12	11	48	103	1	15	1	2	6	20
4068	CapSureFix	123,800	5	3	31	23	0	5	1	1	2	4
4074	CapSure Sense	91,300	10	1	24	28	0	1	0	0	2	0
4076	CapSureFix Novus	432,000	46	4	116	63	б	14	1	8	11	12
4092	CapSure SP Novus	177,000	1	4	21	28	0	0	1	0	2	2
4524	CapSure SP	99,500	2	2	23	15	0	4	2	0	1	12
4558M	Screw-in	19,400	2	0	2	2	0	1	0	1	1	1
4568	CapSureFix	69,100	3	1	4	6	1	1	0	0	2	1
4574	CapSure Sense	61,000	0	1	33	14	1	8	0	0	0	4
4592	CapSure SP Novus	85,400	0	0	26	8	1	1	1	0	0	2
5024, 5024M	CapSure SP	197,800	9	8	30	49	1	9	6	3	3	16
5033	CapSure Z	2,300	0	0	0	0	0	0	0	0	0	1
5034	CapSure Z	55,200	2	2	14	28	0	3	3	0	0	12
5054	CapSure Z Novus	95,900	1	1	22	22	0	0	1	0	2	9
5068	CapSureFix	102,400	16	4	20	31	1	5	1	0	1	6
5072	SureFix	10,000	0	0	2	2	0	0	0	0	0	0
5076	CapSureFix Novus	1,511,200	150	11	470	227	27	35	8	13	12	31
5086MRI	CapsureFix Novus	102,900	99	2	112	55	13	11	1	9	2	0
5092	CapSure SP Novus	132,700	4	1	43	30	1	6	3	3	0	9
5524, 5524M	CapSure SP	59,400	0	0	0	0	0	0	0	0	0	0
5534	CapSure Z	25,800	0	0	6	3	0	1	0	1	0	4
5554	CapSure Z Novus	62,000	0	1	29	25	0	2	0	0	0	3
5568	CapSureFix	90,900	7	0	30	19	2	2	1	2	2	4
5592	CapSure SP Novus	34,500	1	0	24	4	0	2	0	0	0	1
5594	CapSure SP Novus	15,800	0	0	8	0	0	0	0	0	0	2
6940	CapSureFix	25,400	0	1	6	1	0	0	0	0	1	0

Report Cutoff Date: February 1, 2013

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
3830	SelectSecure	Transvenous V or A Screw-In	Polyurethane/Silicone (55D,4719)	MP35N 5 Filars/ Cable	1.8 mm Helix/Steroid	IS-1 BI
4024	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4068	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A/55D)	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4074	CapSure Sense	Transvenous Ventricular Tines	Polyurethane/Silicone (55D, 4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium/ Steroid	IS-1 BI
4076	CapSureFix Novus	Transvenous V or A Screw-In	Polyurethane/Silicone (55D, 4719)	MP35N 4/6 Filars	TiN Coated Platinum Alloy/Steroid	IS-1 BI
4092	CapSure SP Novus	Transvenous Ventricular Tines	Polyurethane/Silicone (55D/4719)	MP35N 6/4 Filars	Porous Platinized/ Steroid	IS-1 BI
4524	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4558M	Screw-In	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4568	CapSureFix	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4574	CapSure Sense	Transvenous Atrial -J Tines	Polyurethane/Silicone (55D,4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium	IS-1 BI
4592	CapSure SP Novus	Transvenous Atrial-J Tines	Polyurethane/Silicone (55D/4719)	MP35N 6/3 Filars	Porous Platinized/ Steroid	IS-1 BI
5024, 5024M	CapSure SP	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5024) IS-1 Bl (5024M)
5033	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
5034	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	CapSure Z Platinized/Steroid	IS-1 BI
5054	CapSure Z Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	CapSure Z Porous/Platinized/ Steroid	IS-1 BI
5068	CapSureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
5072	SureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/5 Filars	1.8 mm Helix/Steroid	IS-1 BI
5076	CapSureFix Novus	Transvenous V or A Screw-In	Silicone (4719)	MP35N 4/6 Filars	Porous Platinized/ Steroid	IS-1 BI
5086MRI	CapsureFix Novus	Transvenous A or V Screw-in	Silicone	MP35N	Titanium nitride coated platinum alloy	IS-1 BI
5092	CapSure SP Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5524, 5524M	CapSure SP	Transvenous Atrial-J Tines	Silicone	MP35N 6/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5524) IS-1 Bl (5524M)
5534	CapSure Z	Transvenous Atrial-J Tines	Silicone	MP35N 4/5 Filars	CapSure Z Platinized/Steroid	IS-1 BI
5554	CapSure Z Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	CapSure Z Porous Platinized/ Steroid	IS-1 BI
5568	CapSureFix	Transvenous Atrial-J Screw-In	Silicone	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
5592	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5594	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Platinized Platinum/ Steroid	IS-1 BI
6940	CapSureFix	Transvenous Atrial-J Screw-In	Silicone	MP35N 3/6 Filars	Platinum Alloy	IS-1 BI

Epi/Myocardial Pacing Leads

4951, 4951M Spectraflex

Product Characteristics

 -					
US Market Release	Oct-81	Serial Number Prefix	TF or LBJ	US Returned Product An	alysis
Registered US Implants	11,600	Type and/or Fixation	Myocardial Stab-in, V or A, Peds	Conductor Fracture	36
Estimated Active US Implants	2,500	Polarity	Unipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	No	Insulation Breach	9
				Other	5

Prod	uct	Surveillance	Registry Re	sults		C	Qualifying Com	plications	14	Total				
	C	lumber of Leads Cumulative Mont lumber of Leads	ths of Follow-U	p	179 5,953 4		Failur	tor Fracture e to Capture ure to Sense	1 7 3			edance Out of R Insulation not further def	(ESC)	1 1 1
ead Survival Probability (%)	100 90 80	0 1		2	3	4	5	6	7	8	} 5	2 1	0	
ad Surviv		Years After	1 yr	2 yr	3 yr	4 yr								
Le	% #		97.7 89	96.5 75	93.8 61	90.5 51								

Effective Sample Size

4965	CapSure E	pi		Produc	t Character	istics						
	US Market Release	e	Sep-96	Serial Nu	mber Prefix	LBT			US	Returned F	Product Ana	lysis
	Registered US Imp	olants	20,900	Type and	/or Fixation	Epicardia	l Suture-On V o	r A			or Fracture	163
	Estimated Active	US Implants	9,400	Polarity		Unipolar				Crimp/\	Weld/Bond	1
	Advisories		None	Steroid		Yes				Insulat	ion Breach	34
											Other	2
roduo	t Surveillance	Registry Res	ults		Qu	alifying Con	nplications	12 Tota	al			
	Number of Leads	Enrolled in Stud	у	219		Condu	ictor Fracture	5	Insu	lation (not furt	ther defined)	1
	Cumulative Montl	hs of Follow-Up	7,	617		Failu	re to Capture	3			Oversensing	2
	Number of Leads	Active in Study		25		Fa	ilure to Sense	1				
@ 10	0											
Lead Survival Probability (%)	0				-							
oabili 8					1 ·							
교	0 1	2	3		4	5	6	7	8	9	10	
N.	Years After I	Implant										
l Su		1 yr	2 yr	3 yr	4 yr	at 51 mo						
ead %	6	99.0	98.2	97.2	92.7	91.3						
	#	140	117	92	63	55						
	Effective Sampl	le Size										

Epi/Myocardial Pacing Leads continued

68 CapSu										
US Market Re	elease	Sep-99	Serial Nu	mber Prefix	LEN			US Re	turned Prod	uct Analysis
Registered U	JS Implants	27,800	Type and	/or Fixation	Epicardial	Suture-On V o	r A		Conductor Fra	cture
Estimated Ac	ctive US Implants	17,200	Polarity		Bipolar				Crimp/Weld/	Bond
Advisories		None	Steroid		Yes				Insulation B	reach
									(Other
duct Surveilla	nce Registry Resu	ults		Qua	alifying Com	plications	61 Total			
Number of L	eads Enrolled in Stud	y	816		Conduc	tor Fracture	12	Im	pedance Out o	f Range
Cumulative l	Months of Follow-Up	39,	078		Extra Cardiac	Stimulation	2	Insulatio	n (not further d	lefined)
Number of L	ande Active in Ctudy					-				0.1
	eads Active in Study		334		Failur	e to Capture	20			Other
	leads Active III study		334			e to Capture ure to Sense	20 4		Over	other sensing
			334						Over	
100			334						Over	
			334						Over	
100			334						Over	
100 90 80			334	4	Fail	ure to Sense	4	8		sensing
100 90 80 0	1 2 fter Implant	3	334	4	Fail			8	Over:	
100 90 80 0	1 2 fter Implant	3	334 3 yr	4 4 yr	Fail	ure to Sense	4	8 8 8 yr		sensing
100 90 80 0	1 2 fter Implant	3 2 yr			Fail	ure to Sense	4		9	sensing

5071 Screw-in

Product Characteristics

US Market Release	Dec-92	Serial Number Prefix	LAQ	US Returned Product A	nalysis
Registered US Implants	44,300	Type and/or Fixation	Myocardial Screw-in Vent.	Conductor Fracture	13
Estimated Active US Implants	15,200	Polarity	Unipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	No	Insulation Breach	2
				Other	0

Pro	duct	Surveillance	e Registry Res	sults		Qual	ifying Com	plications	14 Total			
	Ν	lumber of Lead	s Enrolled in Stu	dy	295		Failur	e to Capture	11			
			ths of Follow-U		8,171		Impedance C		1			
	N	lumber of Lead	s Active in Study	/	60		(Oversensing	2			
(%)	100											
Probability (%)	90											
babi	80											
Pro	(0	1 2		3	4 5	5	6	7	8	9	10
vival		Years After	Implant									
Lead Survival			1 yr	2 yr	3 yr	4 yr	5 yr					
-ead	%		97.3	94.2	92.0	92.0	90.3					
	#		147	102	75	64	49					
		Effective Sam	ple Size									

Epi/Myocardial Pacing Leads continued

Lead Survival Summary (95% Confidence Interval)

		əse		ζtndy		ζtnqλ utps			-	ŝ								
		ələ	pəl	ui a	su		Device S	urvival F	Device Survival Probability (%)	ty (%)								
		rket R	Enroll		ying vitsoi		Years After Implant	ter Impla	ant									
dmuN dmuN	γlime٦	₽W SU	speəl		filenØ IqmoD	lumu) Iloi fo	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr
4951, 4951M	Spectraflex	Oct-81	179	4	14	5,953	97.7 +1.6/-4.8	96.5 +2.2/-5.8	93.8 +3.5/-7.5	90.5 +4.8/-9.1								
4965	CapSure Epi	Sep-96	219	25	12	7,617	99.0 +0.7/-3.0	98.2 +1.2/-4.0	97.2 +1.8/-4.7	92.7 +3.7/-7.1	91.3 +4.2/-8.0 at 51 mo							
4968	CapSure Epi	Sep-99	816	334	61 3	39,078	39,078 98.6 +0.6/-1.2	96.7 +1.1/-1.7	95.1 +1.5/-2.1	93.0 +1.9/-2.5	92.1 +2.0/-2.8	91.2 +2.3/-3.0	89.2 +2.8/-3.8	89.2 +2.8/-3.8	84.7 +4.6/-6.3 at 117 mo			
5071	Screw -in	Dec-92	295	60	14	8,171	97.3 +1.5/-3.2	94.2 +2.8/-4.9	92.0 +3.6/-6.2	92.0 +3.6/-6.2	90.3 +4.3/-7.5							

Epi/Myocardial Pacing Leads continued

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Insulation Breach	Crimp/ Weld/Bond	Other
4951, 4951M	Spectraflex	Oct-81	11,600	2,500	36	9	0	5
4965	CapSure Epi	Sep-96	20,900	9,400	163	34	1	2
4968	CapSure Epi	Sep-99	27,800	17,200	33	12	0	2
5071	Screw-in	Dec-92	44,300	15,200	13	2	0	0

Source: Returned Product Analysis Data as of February 1, 2013

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure To Sense	Impedance Abnormal	Extracardiac Stimulation
4951, 4951M	Spectraflex	11,600	0	1	0	8	0	0	0	0
4965	CapSure Epi	20,900	0	1	0	4	1	4	3	0
4968	CapSure Epi	27,800	0	0	3	11	2	0	2	0
5071	Screw-in	44,300	1	0	0	32	0	2	2	3

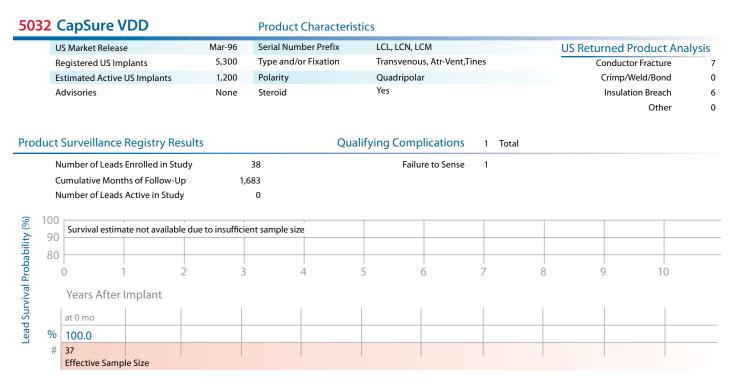
Model Number	Family	Estimated US Implants	Insulation Breach	Unspecified
4951, 4951M	Spectraflex	11,600	0	1
4965	CapSure Epi	20,900	0	3
4968	CapSure Epi	27,800	1	0
5071	Screw-in	44,300	0	1

Report Cutoff Date: Data as of February 1, 2013

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
4951, 4951M	Spectraflex	Myocardial Stab-In V or A/Peds	Polyurethane (80A)	MP35N 4 Filars	Barb	5 mm (4951) IS-1 UNI (4951M)
4965	CapSure Epi	Epicardial Suture V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 UNI
4968	CapSure Epi	Epicardial Suture V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 B1
5071	Screw-in	Myocardial Screw-In Ventricular	Silicone	MP35N Multifilars	2-Turn Helix	IS-1 UNI

VDD Single Pass Pacing Leads

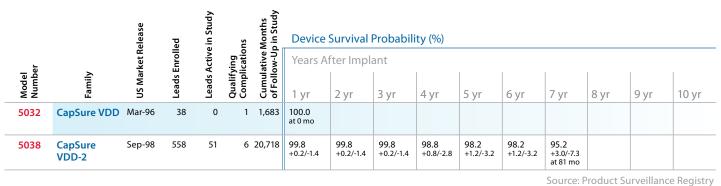


5038	CapSure VDD-2		Product Charae	cteristics						
	US Market Release	Sep-98	Serial Number Pref	fix LEE, LEG, or LEF			US Retu	rned Produ	ct Analy	/sis
	Registered US Implants	9,100	Type and/or Fixation	on Transvenous, Atr-Vent.,T	ines		C	onductor Fract	ure	4
	Estimated Active US Implants	3,500	Polarity	Quadripolar				Crimp/Weld/Bo	ond	0
	Advisories	None	Steroid	Yes				Insulation Brea	ach	1
								Ot	her	0
Produ	ct Surveillance Registry Results Number of Leads Enrolled in Study Cumulative Months of Follow-Up		58	Qualifying Complications Conductor Fracture Failure to Capture	6 3 1	Total				
	Number of Leads Active in Study		51	Failure to Sense	2					
bility (9	00 00 00 0 0 1 2 Years After Implant	3	4	5 6	7	8	(9 1	0	

l Survi			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 81 mo		
-ead	%		99.8	99.8	99.8	98.8	98.2	98.2	95.2		
	#		420	308	220	176	135	83	52		
		Effective Samp	ole Size								

VDD Single Pass Pacing Leads

Lead Survival Summary (95% Confidence Interval)



Data as of February 1, 2013

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
5032	CapSure VDD	Mar-96	5,300	1,200	7	0	6	0
5038	CapSure VDD-2	Sep-98	9,100	3,500	4	0	1	0

Source: Returned Product Analysis Data as of February 1, 2013

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Lead Dislodgement	Failure to Capture	Failure to Sense	Extracardiac Stimulation	Unspecified
5032	CapSure VDD	5,400	1	1	1	0	1
5038	CapSure VDD-2	9,000	2	1	1	1	0

Report Cutoff Date: February 1, 2013

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5032	CapSure VDD	Transvenous V and A Tines	Silicone	MP35N 5/6/1 Filars	Porous Platinized/ Steroid	Atr. IS-1 Bl, Vent. IS-1 Bl
5038	CapSure VDD-2	Transvenous V and A Tines	Silicone	MP35N	Porous Platinized/ Steroid	Atr. IS-1 Bl, Vent. IS-1 Bl

ICD and CRT-D Charge Time Performance

Medtronic continues its commitment to providing updated information on charge time performance.

Introduction

Information on charge time performance of Medtronic products is presented in this section of the CRDM Product Performance Report. Medtronic implemented the collection of charge time data on July 1, 1999. The data are collected via our ongoing active clinical study of long-term system performance called the Product Surveillance Registry. The study protocol requests device data be routinely taken and sent to Medtronic at no more than 6-month intervals.

In our analysis performed for this report, only charge times resulting from full energy charges are considered. To ensure consistent reporting across devices, the charge time reported at implant represents the last charge time available from date of implant. When more than one charge time is available in a 6-month interval, a conservative approach has been adopted whereby only the maximum charge time in each 6-month interval is reported. As charge time is directly proportional to the time elapsed since the last capacitor reformation, charges occurring within 15 days of a previous charge are excluded. This precludes the reporting of overly optimistic results.

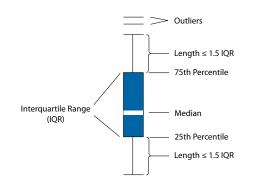
Data from over 20,000 devices contribute to the charge time data in this report. By tracking and reporting this charge time data, Medtronic is able to ascertain the actual performance of its charging circuitry. The insight gained through this information is applied to Medtronic's ongoing efforts to provide charge times that are short and consistent over the life of the product.

Data Presentation

Charge time data for ICD and CRT-D models are presented using boxplots at 6-month intervals. The shaded box on the plots represents the middle half of the data – the Interquartile Range (IQR). The white line in the middle of each box is the median charge time. The top of the box representing the IQR is the third quartile or the 75th percentile (i.e., 75% of all charge times fall below this line), whereas the bottom of the box represents the first quartile or the 25th percentile. Vertical lines are drawn from the quartiles to the farthest value not more than 1.5 times the interquartile range. Any values more extreme than the vertical lines are considered outliers.

Results

The graph below shows the overall maximums, minimums, and medians for Medtronic ICD and CRT-D products, beginning with the 7271 GEM DR.



40 35																			_																	
30 25 20 15 10	Ţ	I	I	I	Ţ	Ŧ	Ŧ	Ţ	Ŧ	Ŧ		Ŧ	I	Ŧ	Ŧ	Ŧ		Ŧ		Ŧ	Ŧ	ļ	Ŧ	Ŧ	Ŧ	Ţ	Ţ		Ŧ	-	-	_	_	-	Ŧ	_
5	7271 GEM DR	7231 GEM III VR	7276 GEM III AT	7230 Marquis VR	7274 Marquis DR	7232 Maximo VR	7278 Maximo DR	7288 Intrinsic	7290 Onyx	7298 In Sync Sentry	7299 In Sync Sentry	7304 InSync Maximo	D153ATG/DRG EnTrust	D154ATG/DRG EnTrust	D154/D153VRC EnTrust	AWK, C174AWK Concerto	54/D164AWG Virtuoso	154/D164VWC Virtuoso	4TRK, D204DRM Consulta	4DRG,D214DRM Secura DR	C, D214VRM Secura VR	D284DRG Maximo II DR	34TRK Maximo II CRT-D	D284VRC Maximo II VR	274DRG Virtuoso II DR	294TRK Concerto II CRT-D	D274VRC Virtuoso II VR	G/DRM Protecta XT DR	/DRM Protecta XT CRT-D	KG/VRM Protecta XT VR	4DRG/DRM Protecta DR	G/TRM Protecta CRT-D	4VRG/VRM Protecta VR	G/DRM Protecta XT DR	TRM Protecta XT CRT-D	RG/VRM Protecta XT VR
idel Vate s of	1998	2000	2001	2002	2002	2003	2003	2004	2004	2004	2004	2005	2005			C154DWK, C164	2006	2006	D224/D23	8002 D224/D234DR	8002 D224/D234VRC,		87 0 2008	2008	2009	D274/D		D314DRG	D334DRG	D314VRG	D33	D334TRG	2011	D354DRG	D354TRG	D354VRG
Up	132	114		108	96	108	90	90	84	78	72	72	66	84	84	60	72	72	48	48	48	48	48	48	36	36	36	18	18	18	18	18	12	30	30	24
r of oles	3,098				2,794						1,333	442	49				2,876			2,429			1,245			2,409		585	1,303	166	138	157	44	167	239	140

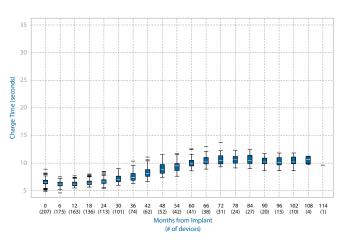
Medtronic CRT-D and ICD Charge Time Performance

Source: Product Surveillance Registry Data as of February 1, 2013

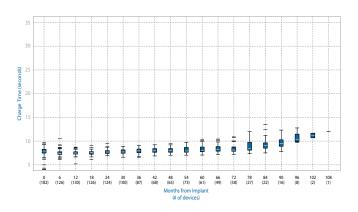
ds) ine. Charge İ 10 Ĩ ŧ Ē ŧ Ī Ē Ē Ŧ 0 6 12 18 24 30 36 (188) (144) (135) (93) (87) (81) (66) 42 48 54 60 66 72 78 84 90 96 102 108 (72) (66) (70) (54) (49) (45) (38) (39) (28) (19) (13) (3) Months from Implant (# of devices)

7230 Marquis VR Charge Time

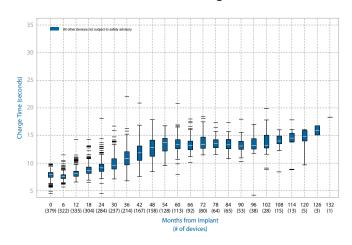
7231 GEM III VR Charge Time



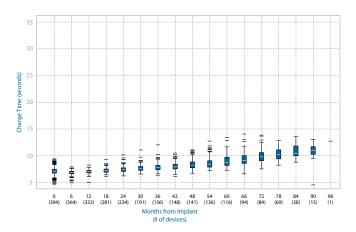
7232 Maximo VR Charge Time



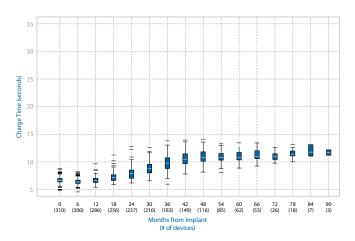
7271 GEM DR Charge Time



7274 Marquis DR Charge Time

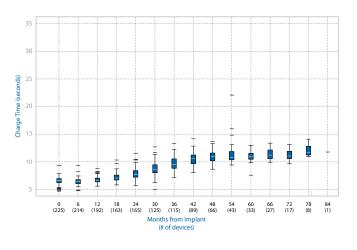


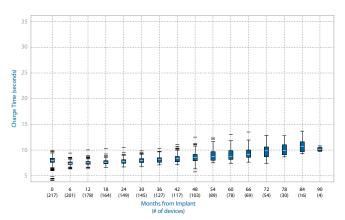
7275 GEM III DR Charge Time



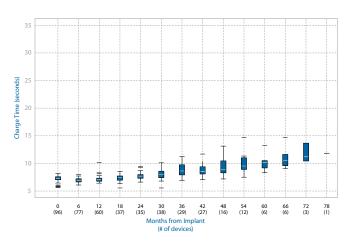
132 Medtronic CRDM Product Performance Report www.medtronic.com/CRDMProductPerformance Source: System Longevity Study Data as of February 1, 2013

7276 GEM III AT Charge Time

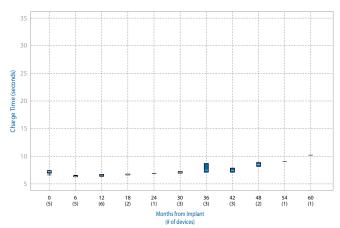




7279 InSync III Marquis Charge Time

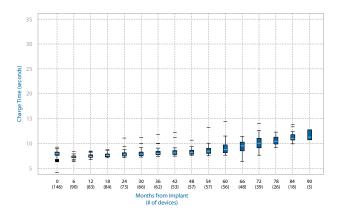


7285 InSync III Protect Charge Time

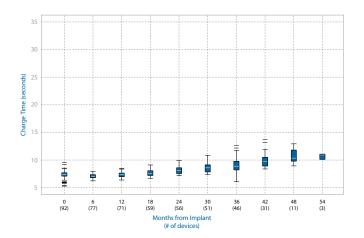


ICD Charge Times

7288 Intrinsic Charge Time



7289 InSync II Marquis Charge Time



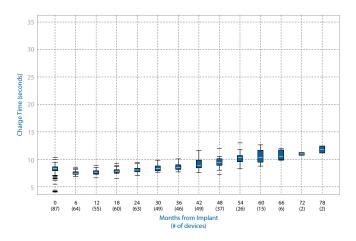
7278 Maximo DR Charge Time

Source: Product Surveillance Registry Data as of February 1, 2013

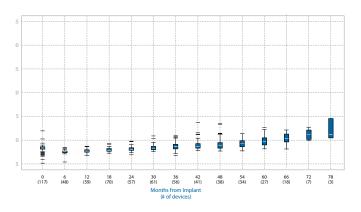
(sp Time (Charge È Ė İ İ 0 (9) 12 (6) 18 (8) 24 (5) 42 (10) 54 (7) 72 (6) 78 (3) 84 (2) 6 (5) 30 (7) 36 (9) 48 (9) 60 (8) 66 (6) ths from Implant (# of devices)

7290 Onyx Charge Time

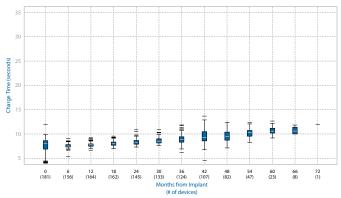




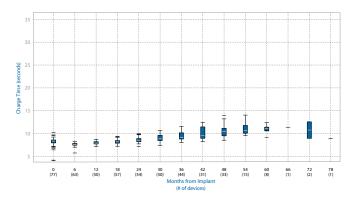
7298 InSync Sentry Charge Time



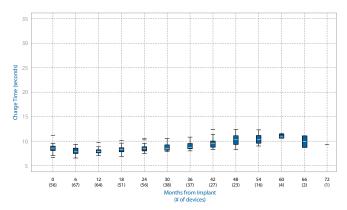
7299 InSync Sentry Charge Time

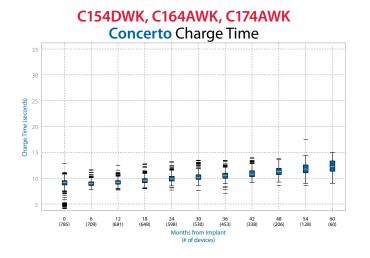


7303 InSync Maximo Charge Time



7304 InSync Maximo Charge Time



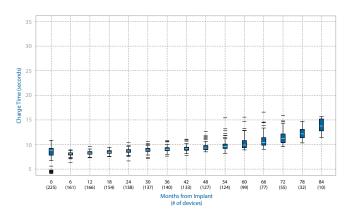


E. Charge F 0 (7) 12 (6) 18 (6) 24 (6) 30 (7) 42 (1) 54 (2) 66 (1) 6 (7) 36 (3) 48 (2) 60 (1) Months from Implant

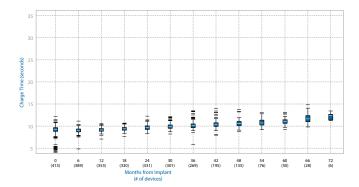
(# of devices

D153ATG/DRG EnTrust Charge Time

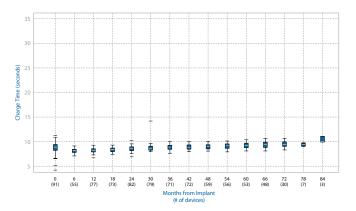
D154ATG/DRG EnTrust Charge Time



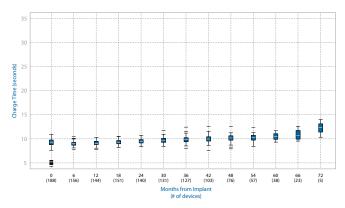
D154AWG/164 Virtuoso Charge Time



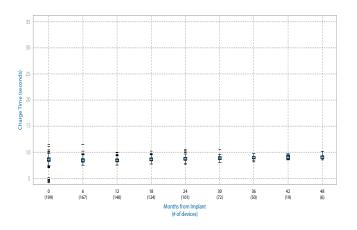
D154VRC EnTrust Charge Time



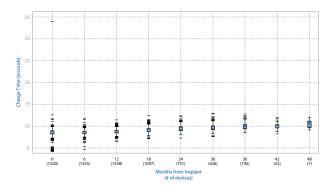
D154VWC/164 Virtuoso Charge Time



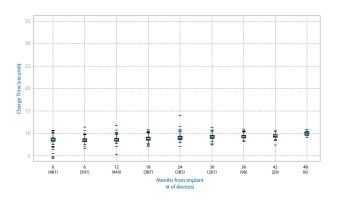
D224VRC/234 Secura VR Charge Time



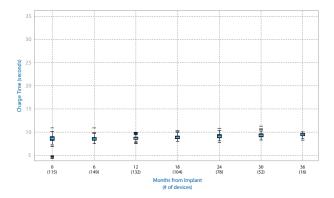
D224TRK/234 Consulta Charge Time



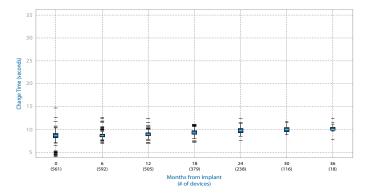
D224DRG/234 Secura DR Charge Time



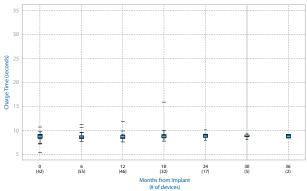
D274DRG Virtuoso II DR Charge Time



D274TRK/294 Concerto II CRT-D Charge Time

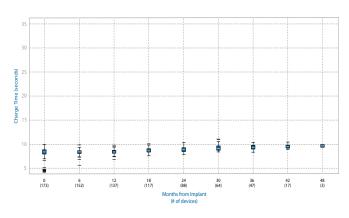


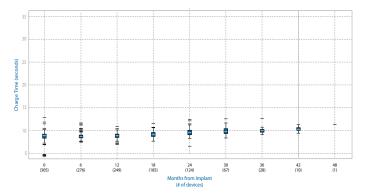
D274VRC Virtuoso II VR Charge Time



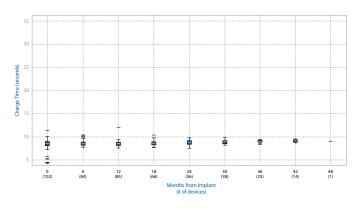
D284DRG Maximo II DR Charge Time

D284TRK Maximo II CRT-D Charge Time

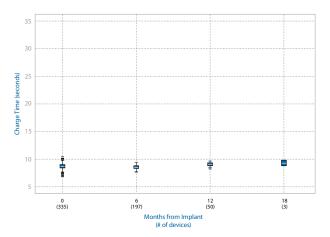




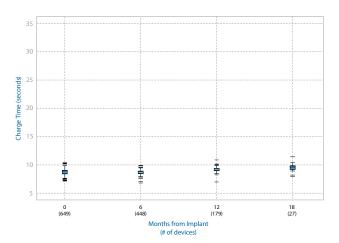
D284VRC Maximo II VR Charge Time



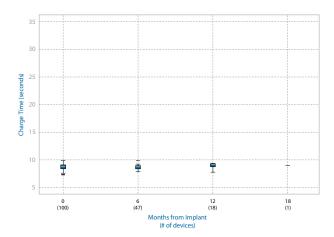
D314DRG/DRM Protecta XT DR Charge Time



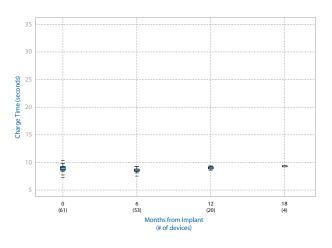
D314TRG/TRM Protecta XT CRT-D Charge Time

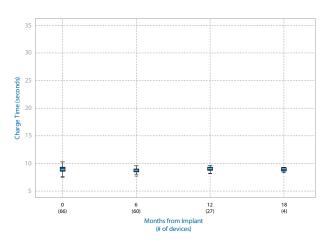


D314VRG/VRM Protecta XT VR Charge Time

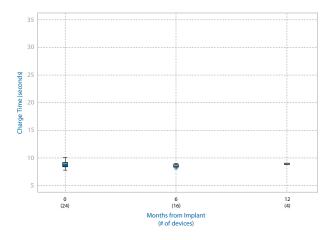


D334DRG/DRM Protecta DR Charge Time

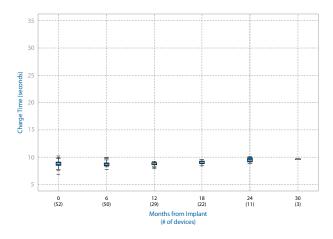




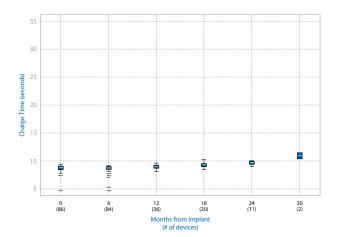
D334VRG/VRM Protecta VR Charge Time



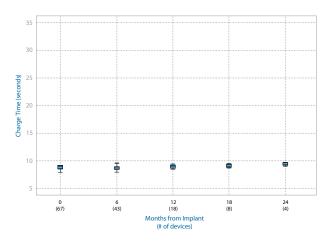
D354DRG/DRM Protecta XT DR Charge Time



D354TRG/TRM Protecta XT CRT-D Charge Time



D354VRG/VRM Protecta XT VR Charge Time



Source: System Longevity Study Data as of February 1, 2013

D334TRG/TRM Protecta CRT-D Charge Time

Advisories

EnTrust ICDs

Original Date of Advisory: March 2012

Potential Rapid Battery Depletion

Product

All EnTrust ICDs.

Advisory

A small percentage of EnTrust ICDs may not meet expected longevity or provide at least three months of device operation between the Elective Replacement Indicator (ERI) and End of Life (EOL) due to a morerapid-than-expected drop in battery voltage. An estimated 39,000 EnTrust ICDs are currently implanted worldwide. No patient deaths or serious injuries have been reported as a result of this issue.

The reported events have involved a drop in battery voltage from ~3.0 V to ERI (2.61 V) over a time period ranging from approximately one week to six months. All reported events have occurred at least 30 months after implant.

Medtronic has identified the cause of these occurrences to be an internal battery short that develops as the battery capacity is consumed. The exact sequence of events and use conditions that lead to the battery short is still being investigated.

Patient Management Recommendations (As of March 2012)

After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following patient management recommendations:

- Physicians should continue routine follow-up sessions at least every three months in accordance with product labeling.
- Physicians should program the audible patient alerts for "Low Battery Voltage ERI" and "Excessive Charge Time EOL" to ON.
- Physicians should replace devices promptly after they reach ERI if the decline in voltage is more rapid than expected.
- Prophylactic replacement of EnTrust ICDs is not recommended.

Status Update

As of February 11, 2013, there have been 74 confirmed events. No patient deaths have been reported due to this issue. No reports have been made of a failure to deliver high voltage therapy.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)
69,000 Worldwide	74 Worldwide	30,600 Worldwide	0.10% Worldwide
(43,200 United States)	(56 United States)	(19,400 United States)	(0.12% United States)

EnRhythm Pacemakers Original Date of Advisory: February 2010

Low Battery Voltage Displayed at Device Interrogation

Product

All EnRhythm pacemakers.

Advisory

Two specific battery issues with EnRhythm pacemakers have been identified and both are addressed by a Medtronic software update.

First Issue

As of February 2010, Medtronic had received 62 reports (out of approximately 110,000 devices worldwide) indicating that the battery voltage at device interrogation was lower than the battery voltage that is tracked by the device to provide data for the elective replacement indicator (ERI) notification. The lower voltage measurement caused confusion and occasionally resulted in unnecessary explants.

Medtronic's investigation has shown that none of these reports resulted in loss of therapy. Importantly, the ERI notification, which uses the nightly battery measurement, is unaffected and accurate. Medtronic has identified the root cause as higher than expected battery resistance.

Medtronic's internal testing has shown that there is no current risk for compromised therapy delivery. If the software update referenced above is not implemented, there will be a potential risk of loss of device functionality in a small percent (less than 0.08% 6 years post-implant) of devices. The software update eliminates this risk.

Second Issue

Through internal accelerated testing, Medtronic has identified a second issue that projects battery voltage could decrease sooner than expected due to a slightly increased rate of lithium depletion. This issue has not been clinically observed and is not expected to occur until approximately 9 years post-implant. If the software update referenced above is not implemented, there may be a potential risk for loss of therapy at or near ERI in a small number of devices. The software will eliminate this issue by changing ERI criteria.

Software Update (As of October 2010)

The battery issues described above and subsequent software update are summarized in the table below. When a device receives the software update, if battery impedance is greater than the new ERI threshold, ERI will be triggered shortly thereafter. Therefore, clinicians may observe an ERI/EOL indicator at the next patient follow-up. When ERI is triggered by battery impedance, additional battery capacity remains and can support device function at ERI parameters for at least one year. Medtronic is not aware of any reports of loss of therapy due to this issue.

As a reminder, when ERI is triggered, EnRhythm devices revert to VVI pacing at 65 ppm at the programmed output settings. EOL is declared 90 days after ERI or at a battery voltage of 2.69 V, whichever comes sooner.

Battery Issue	Software Update
Battery voltage could decrease sooner than expected due to a slightly increased rate of lithium depletion	Changed ERI battery voltage threshold from 2.59 V to 2.81 V to ensure 90 days of therapy from ERI to EOL
Higher than expected battery impedance	Added a secondary ERI trigger based on battery impedance. This new criteria will identify devices with increased battery impedance before device performance is impacted. If triggered, displayed battery voltage is reset to 2.81 V to ensure alignment with ERI battery voltage threshold.

Updated Performance Information (as of August 2011)

We now have access to battery impedance and ERI performance on more than 5,000 EnRhythm devices that have received the EnRhythm software update. Our modeling based on these data shows that approximately 6-10% of devices will reach ERI within 5 years post-implant. Consistent with our previous communications, we continue to expect average device longevity to be reduced by approximately 10-15%, with the expected average longevity remaining at 8.5 to 10.5 years, depending on device settings.¹

Updated Patient Management Recommendations (as of August 2011)

After consultation with Medtronic's Independent Physician Quality Panel, we recommend:

Performing a device follow-up within 90 days after the software download to identify devices that triggered ERI shortly after the software update. Subsequent follow-up can be performed per standard practice. During programmer interrogation of a device at ERI, there is a slight possibility a transient drop in pacing amplitude could occur. If this is noted, either remove the programmer head or temporarily program to a higher output voltage.

continued

EnRhythm Pacemakers

Original Date of Advisory: February 2010

Low Battery Voltage Displayed at Device Interrogation, continued

If an unanticipated ERI/EOL is declared, it is likely due to battery impedance. In such cases, additional battery capacity remains and can support device function at ERI parameters for at least one year. However, when ERI or EOL (typically 90 days after ERI) declaration is seen, schedule device replacement.

¹ The 8.5 year estimate represents a high use scenario (DDD, 100% pacing in atrium and ventricle with 3.0 V output in both chambers). The 10.5 year estimate represents a typical use scenario for a sinus node dysfunction patient with the MVP function ON (AAI(R) <=> DDD(R), 50% pacing in atrium and 5% pacing in ventricle with 3.0 V output in both chambers). Projections are based on modeling and not actual field returns, due to limited availability of implant experience beyond 6 years. Field performance will continue to be monitored and modeling updated to reflect actual data.

Status Update

As of February 25, 2013, 364 devices out of approximately 146,500 devices worldwide have been confirmed as having exhibited an advisory event related to the original advisory, in which higher than expected battery impedance caused a drop in battery voltage at interrogation. Approximately 96,100 remain implanted.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (confirmed malfunctions over total population)	The software update eliminates any potential future risk of the two battery issues described above by changing the ERI criteria.
All EnRhythm pacemakers (146,500 Worldwide)	364 Worldwide	88,800 Worldwide	0.25%	

Included in the August 2011 Performance Update was information about the projected percentage of devices that would encounter an early ERI due to unexpected high battery impedance. As of February 25, 2013, percentage of devices that have encountered ERI due to battery impedance has not exceeded the rate of 6-10% within 5 years post-implant as communicated with our August 2011 Performance Update.

Initial Affected	Number of Confirmed	Estimated Remaining	Only devices using the updated software can trigger ERI due to impedance.
Population	Advisory Related Events	Active Population	
All EnRhythm pacemakers (146,500 Worldwide)	6,698 Worldwide	88,800 Worldwide	

Potential Reduced Device Longevity

Product

A subset of Concerto CRT-D and Virtuoso ICD devices may not meet expected device longevity. Go to <u>www.medtronic.</u> <u>com/CRDMProductPerformance</u> to determine if a specific device is affected.

Advisory

A subset of Concerto CRT-D and Virtuoso ICD devices may not meet expected device longevity due to gradually increasing current drain caused by low voltage capacitor degradation. This issue may present in the affected devices as reaching the Recommended Replacement Time (RRT) earlier than projected. This issue does not compromise device functionality or affect therapy delivery.

Based on information from returned devices, Medtronic expects that affected devices will continue to provide at least 3 months of normal device function between RRT and End of Service (EOS) as described in device labeling.

A total of 8,900 devices worldwide are affected by this advisory. An estimated 6,300 of these devices were active at the time of the original advisory communication.

Concerto and Virtuoso devices in the affected subset were manufactured primarily in 2006 and can be traced to a specific subset of low voltage capacitors.

Patient Management Recommendations

After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following recommendations for patients with devices in the affected subset:

Physicians should continue routine follow-up sessions at least every 3 months in accordance with product labeling. Physicians should verify that the Low Battery Voltage RRT alert is programmed to "On-High." This provides an audible, alternating tone when the device reaches RRT. These devices are shipped with this alert programmed nominally to "On-High."

Physicians may consider monitoring patients through CareLink. The CareLink home monitor can be used to automatically notify the clinician when the device reaches RRT.

Status Update

As of February 11, 2013, 3,681 devices out of approximately 8,900 devices in this subset worldwide have been confirmed as having exhibited this capacitor degradation. Out of the initial advisory population of 8,900 worldwide, less than 500 remain implanted worldwide.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)
8,900 Implanted Worldwide (7,000 United States)	3,681 Worldwide (3,165 United States)	< 500 Worldwide (< 500 United States)	41% Worldwide (45% United States)

Concerto CRT-D and Virtuoso ICD Original Date of Advisory: September 2009

Kappa 600/700/900 Pacemakers Sigma 100/200/300 Pacemakers Original Date of Advisory: May 2009

Potential Separation of Interconnect Wires (2009)

Product

A specific subset of Kappa and Sigma series pacemakers may fail due to separation of interconnect wires from the hybrid circuit. Go to <u>www.medtronic.com/CRDMProductPerformance</u> to determine if a specific device is affected.

Advisory Population

Specific subsets of Kappa and Sigma series pacemakers may fail at a higher than expected rate due to separation of wires that connect the electronic circuit to other pacemaker components (e.g., battery, connector). This may present clinically as loss of rate response, premature battery depletion, loss of telemetry, or no output.

Some patients, whose devices experience a wire separation resulting in a loss of pacing output, will experience a return of bradycardia symptoms (e.g., fainting or lightheadedness). In rare cases involving pacemaker dependent patients, loss of pacing output may result in death or serious injury.

Since 1997, there have been over 1.7 million Kappa and Sigma devices implanted worldwide. At the time of the original advisory communication, an estimated 15,200 Kappa and 6,100 Sigma devices affected by the advisory remained implanted and active. These devices were manufactured primarily between November 2000 and November 2002. Most of these devices have been implanted in patients for five years or longer and may be nearing normal elective replacement time.

There is no provocative testing that can predict which specific devices may fail, and no device programming can mitigate this issue if it occurs.

Patient Management Recommendations

We realize that each patient requires unique clinical consideration and we support your judgment in caring for your patients. After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following recommendations for patients:

- Physicians should advise their patients to seek medical attention immediately if they experience symptoms (e.g., fainting or lightheadedness).
- Physicians should consider device replacement for patients who are both pacemaker dependent and who have been implanted with a device in the affected subsets. Medtronic will offer a supplemental device warranty if the device is not already at elective replacement time.
- Physicians should continue routine follow-up in accordance with standard practice for those patients who are not pacemaker dependent.

Status Update

Advisory Population

Patient management recommendations remain

unchanged. As of February 25, 2013, Medtronic has observed 458 Kappa devices and 294 Sigma devices with this failure mechanism from the Kappa and new Sigma device subsets. This represents 0.79% (Kappa) and 1.97% (Sigma) of the original affected implant population.

Four hundred twenty-one (421) of the Kappa devices (0.72%) and 229 of the Sigma devices (1.53%) were returned with information indicating a problem with the patient's pacing system prior to explant. The remaining 37 Kappa devices (0.06%) and 65 Sigma devices (0.44%) were returned with no information indicating a potential malfunction while implanted or with insufficient information to determine the state of the device at explant. Lacking definite information indicating proper operation until explant, these remaining devices are conservatively categorized as having experienced interconnect wire separation while implanted.

As of May 2009, our modeling predicts failure rates due to this issue of 1.1% (Kappa) and 4.8% (Sigma) over the remaining lifetime of those pacemakers still in service at that time.

Out of the initial advisory population of 58,300 Kappa devices and 14,900 Sigma devices worldwide, less than 500 Kappa devices remain implanted worldwide and 2,400 Sigma devices remain implanted worldwide. Of these, 600 Sigma devices are in the United States.

Continued Vigilance

Included in the advisory communication was information about an additional subset of Kappa devices where we have observed a much lower rate of occurrence of this issue. Approximately 17,000 devices of this subset remain active. We have observed a failure rate of approximately 0.096% in this subset and our May 2009 modeling predicts a failure rate of 0.12% over the remaining device life of those pacemakers still in service at that time. After review with our Independent Physician Quality Panel, we do not recommend any specific actions for this group of devices. We will continue to monitor performance and inform you if any specific patient management recommendations are warranted.

continued

Kappa 600/700/900 Pacemakers

Sigma 100/200/300 Pacemakers Original Date of Advisory: May 2009

Potential Separation of Interconnect Wires, continued

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed and Unconfirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still Implanted Population
Kappa Pacemakers 58,300 Implanted Worldwide (est.) (17,600 United States)	421 Worldwide (221 United States) with information indicating a clinical presentation. An additional 37 worldwide (25 US) without information indicating a clinical presentation or with insufficient information to determine the state of the device at explant.	< 400 Worldwide (< 100 United States)	0.79% Worldwide 1.40% (United States)	1.1%
Sigma Pacemakers			·	
14,900 Implanted Worldwide (est.) (3,700 United States)	229 Worldwide (47 United States) with information indicating a clinical presentation. An additional 65 worldwide (16 US) without information indicating a clinical presentation or with insufficient information to determine the state of the device at explant.	2,400 Worldwide (600 United States)	1.97% Worldwide 1.70% (United States)	4.8%

6930, 6931, 6948, 6949 Sprint Fidelis Defibrillation Leads Original Date of Advisory: October 2007

Potential Conductor Wire Fracture

Product

All Model 6930, 6931, 6948, and 6949 implantable defibrillation leads

Advisory

There are two primary locations where chronic conductor fractures have occurred on Sprint Fidelis leads: 1) the distal portion of the lead, affecting the anode (ring electrode) and 2) near the anchoring sleeve tie-down, predominantly affecting the cathode (helix tip electrode), and occasionally the high voltage conductor. These two locations account for approximately 90% of the chronic fractures identified in Returned Product Analysis (RPA). The remaining 10% of chronic fractures occurred in the DF-1 connector leg and the proximal portion of the RV coil. High voltage conductor fractures could result in the inability to deliver defibrillation therapy. Anode or cathode conductor fractures (at either location) may present clinically as increased impedance, oversensing, increased interval counts, multiple inappropriate shocks, and/or loss of pacing output.

Patient Management Recommendations (Updated April 2011)

The Lead Integrity Alert (LIA) provides three days advance notice prior to inappropriate therapy to 76% of patients with lead fractures.¹ As a result, we strongly recommend that all Sprint Fidelis patients who have the ability to upgrade to Lead Integrity Alert do so promptly. Also ensure that high voltage lead impedance alerts (maximum of 100 ohms) are programmed. When a lead fracture is suspected or confirmed, immediate patient attention is strongly recommended. Physicians should inform their patients to seek medical attention without delay if they experience unexpected shocks

- If a Fidelis lead fracture of any type has occurred, we recommend implanting a new high voltage lead with or without extraction of the Fidelis lead.
- In patients with normal device function and no manifestation of lead fracture, no action is recommended. The risk of prophylactic intervention appears to be greater than serious injury resulting from lead fracture even for pacemaker dependent patients, except in select individual patient circumstances as determined by the physician.
- In the event of a device change-out or upgrade procedure, with no manifestation of lead fracture, consider the patient age and lead model data above, as well as patient life expectancy, co-morbidities, ease of extraction related to implant time, patient preference, etc., for the following options:
 - Leave a properly performing lead intact.
 - Implant a new ICD lead without extraction of the existing lead.

- Carefully consider all factors before prophylactic placement of a pace-sense lead. Data shows an increased risk of high voltage conductor fracture if a pace-sense conductor fracture has previously occurred. This data is available at www.medtronic.com/fidelis
- Individual patient circumstances may warrant extracting and implanting a new ICD lead. If warranted, Medtronic's Independent Physician Quality Panel recommends the lead extraction procedure be performed by a physician with extensive lead extraction experience.²

Status Update

As of February 11, 2013, of the initial implant population of 205,600 in the United States, approximately 90,800 remain implanted. According to Product Surveillance Registry results, lead survival is estimated to be 81.0% (+4.3/-5.4) at 81 months. As the implanted population ages and the sample size increases for each time interval, the accuracy of the estimated survival probability will increase as shown by tighter confidence intervals.

- ¹ Swerdlow C, Gunderson B, Ousdigian K, et al. Downloadable Algorithm to Reduce Inappropriate Shocks Caused by Fractures of Implantable Cardioverter-Defibrillator Leads, *Circulation*. November 2008;118:2122-2129.
- ² Wilkoff B, Love C, Byrd C, et al. Transvenous Lead Extraction: Heart Rhythm Society Expert Consensus on Facilities, Training, Indications, and Patient Management. *Heart Rhythm.* July 2009;6:1085-1104.

continued

6930, 6931, 6948, 6949 Sprint Fidelis Defibrillation Leads

Original Date of Advisory: October 2007

Potential Conductor Wire Fracture, continued

Keeping Physicians Informed

The most recent Sprint Fidelis lead performance information, including survival curves, physician letters, and subpopulation data, can be found at www.medtronic.com/fidelis and will be updated semi-annually. Medtronic's website also has a selected list of peerreviewed publications related to Fidelis lead performance and extraction. Medtronic is committed to answering your questions and keeping you informed. If you have any questions or concerns, please contact your Medtronic Representative or Medtronic Technical Services at 1 (800) 723-4636 (US).

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Additional information about the Sprint Fidelis lead is available at: www.medtronic.com/fidelis.
279,500 Worldwide	5,992 Worldwide	125,000 Worldwide	
(205,600 United States)	(4,174 United States)	(90,800 United States)	

Sigma Implantable Pulse Generators

Original Date of Advisory: November 2005

Potential Separation of Interconnect Wires (2005)

Product

A specific subset of Sigma series pacemakers may fail due to separation of interconnect wires from the hybrid circuit. Go to <u>www.medtronic.com/CRDMProductPerformance</u> to determine if a specific device is affected.

Advisory

This subset of Sigma series pacemakers that may fail due to separation of interconnect wires from the hybrid circuit may present clinically as loss of rate response, premature battery depletion, intermittent or total loss of telemetry, or no output.

Separation of redundant interconnect wires has been observed on hybrid terminal blocks. Device failure occurs only where both interconnect wires separate from a hybrid terminal block. In October 2005, testing and analysis identified the root cause of these failures and the affected population. Hybrid circuits used in this subset of devices were cleaned during manufacturing with a particular cleaning solvent that could potentially reduce the strength of the interconnect wire bond over time.

No provocative testing can predict which devices may fail.

Patient Management Recommendations

Recommendation for the management of patients who have pacemakers affected by this advisory were changed in May 2009. Current recommendations are:

We realize that each patient requires unique clinical consideration and we support your judgment in caring for your patients. After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following recommendations for patients in the 2005 Sigma advisory:

- Physicians should advise their patients to seek medical attention immediately if they experience symptoms (e.g., fainting or lightheadedness).
- Physicians should consider device replacement for patients who are both pacemaker dependent and who have been implanted with a device in the affected subsets. Medtronic will offer a supplemental device warranty if the device is not already at elective replacement time.
- Physicians should continue routine follow-up in accordance with standard practice for those patients who are not pacemaker dependent.

Status Update

Patient management recommendations remain unchanged. As of February 25, 2013, 796 devices out of approximately 40,000 devices worldwide have been confirmed as having experienced interconnect wire separation.

Four hundred twenty-three (423) of the Sigma devices (1.01%) were returned with information indicating a problem with the patient's pacing system prior to explant. The remaining 363 Sigma devices (0.90%) were returned with no information indicating a potential malfunction while implanted or with insufficient information to determine the state of the device at explant. Lacking definite information indicating proper operation until explant, these remaining devices are conservatively categorized as having experienced interconnect wire separation while implanted.

Our original modeling predicted a failure rate from 0.17% to 0.30% over the remaining lifetime of these pacemakers. However, as of May 2009 updated updated modeling now predicts a failure rate of 3.9% over the remaining device life of those devices still in service at that time.

Out of the initial advisory population of 40,000 worldwide, approximately 7,200 remain implanted. Approximately 1,700 of these are in the United States.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed and Unconfirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still in Service as of May 2009
40,000 Implanted Worldwide (est.) (9,900 United States)	423 Worldwide (82 United States) with information indicating a clinical presentation.An additional 363 Worldwide (66 US) without information indicating a clinical presentation or with insufficient information to determine the state of the device at explant.	7,200 Worldwide (1,700 United States)	2.00% Worldwide 1.49% (United States)	3.9%

7274 Marquis DR 7278 Maximo DR 7230 Marguis VR

7232 Maximo VR

7277 InSync Marquis 7289 InSync II Marquis

7279 InSync III Marquis 7285 InSync III Protect

Original Date of Advisory: February 2005

Potential Premature Battery Depletion Due to Battery Short

Product

The specific subset of Marquis family ICD and CRT-D devices having batteries manufactured prior to December 2003 is affected. Devices manufactured with batteries produced after December 2003 are not affected. Go to www.medtronic.com/CRDMProductPerformance to determine if a specific device is affected.

Advisory

Medtronic Marquis family of ICD and CRT-D devices having batteries manufactured prior to December 2003 may experience rapid battery depletion due to a specific internal battery short mechanism. Battery design changes were implemented in December 2003 that eliminate the possibility of this internal shorting mechanism.

Highly accelerated bench testing indicated the rate of this shorting mechanism may increase as the battery is depleted. As of February 2005, the rate of shorting was approximately 1 in 10,000 (0.01%); bench test data indicated the rate may increase to between 0.2% and 1.5% over the second half of device life.

No provocative testing can predict which of these devices will experience this issue. Once a short occurs, battery depletion can take place within a few hours to a few days. After depletion the device ceases to function. It is also possible that as the battery depletes quickly, patients may experience temporary warmth in the area surrounding the ICD.

Patient Management Recommendations

We recommend you consider the following patient management options:

· Conduct quarterly (i.e., every 3 months) follow-up procedures

- Inform patients that should they experience warmth in the area surrounding the ICD to seek follow-up care promptly
- Program Low Battery Voltage ERI Patient Alert to "On-High." This will result in an audible, alternating tone in the limited circumstances where a battery depletes slowly over a number of days. Data indicates most shorts will occur rapidly and will not be detected by this feature.
- Provide a hand-held magnet to patients to check device status and program the Low Battery Voltage ERI Patient Alert to "On-High." Device operation may be monitored periodically (e.g., daily) by patients placing the magnet over the device for 1-2 seconds. If the device is functional, a steady tone will sound for approximately 20 seconds. If no tone is heard, follow-up care should be sought promptly.

Status Update

The Marquis Family device performance related to the battery shorting mechanism continues to be within Medtronic's engineering projections. As of February 11, 2013, 192 Marquis Family devices have been confirmed as having this internal battery shorting mechanism. One hundred fifteen (115) of these devices were returned from the United States.

Out of the initial advisory population of 87,000 worldwide, approximately 2,700 remain implanted. Approximately 2,400 of these are in the United States.

The Patient Management Recommendations set forth in the advisory remain unchanged.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still Implanted Population
87,000 Implanted Worldwide (76,000 United States)	192 Worldwide (115 United States)	2,700 Worldwide (2,400 United States)	0.22% Worldwide (0.15% United States)	Consistent with Medtronic projections, the observed rate of shorting may increase to between 0.2% and 1.5% over the second half of device life.

Performance Notes

Dual Chamber Pacemakers with Measurement Lock-up ERI Kappa 600, 700, 800, 900, EnPulse, Adapta, Versa, Sensia, Relia, and Vitatron Models E50A1, E60A1, and G70A1

Purpose of this Information

This Performance Note describes a rare measurement lock-up issue that impacts the Medtronic dual chamber pacemakers listed above. If this measurement lock-up occurs, the device will trigger a false Elective Replacement Indicator (ERI). A reset is available to clear this condition and there is no need to explant the device. This issue does not impact battery longevity.

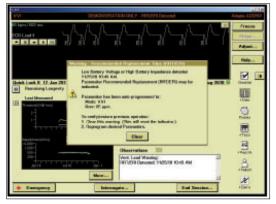
Background

If this rare measurement lock-up occurs in the pacemaker, it causes the device to read a value of zero for battery voltage. After four measurements of zero, the device will trigger ERI and revert to a VVI pacing mode at 65 bpm. There is no loss of ventricular pacing and the output voltage will remain the same.

Programmer Software Reset Method (Adapta, Versa, Sensia, Relia, Vitatron Series E and G)

Programmer software is available which can differentiate a regular ERI and an ERI caused by the measurement lock-up issue. Upon interrogation of a device with the measurement

Example 1 – Programmer Software Detects Measurement Lock-up ERI



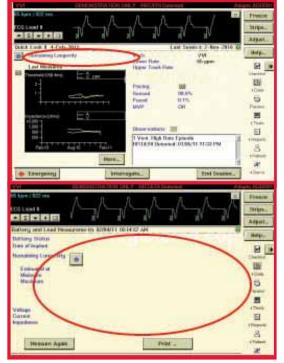
lock-up ERI, the programmer software recognizes the issue and guides the clinician to clear the ERI (Example 1). Following an ERI reset, the device parameters should be reviewed and reprogrammed to clinician specifications.

Reset Method for Kappa and EnPulse

A service tool continues to be available through Medtronic Technical Services to clear the measurement lock-up issue for Kappa and EnPulse devices.

The issue can be identified using the programmer or via CareLink transmission; the battery voltage measurements and remaining longevity will appear as blank values (Example 2). If this measurement lock-up occurs, contact Medtronic Brady Technical Services at 1-800-505-4636 for assistance.





Helix Retraction of the Sprint Quattro Secure S 6935 and Sprint Quattro Secure 6947

Purpose of this Information

This performance note is intended to provide guidance regarding retraction of the helix of Sprint Quattro Model 6935 or 6947 leads.

Background

In certain cases, over-retraction of the helix, during initial implant or subsequent repositioning, may result in the inability to extend the helix. This does not impact acute or chronic performance of successfully implanted leads.

The root cause is over-retraction of the helix mechanism beyond the retraction stop, resulting in the inability to extend the helix in a subsequent attempt.

Recommendations

Consistent with the Technical Manual, the following steps can be used to mitigate this issue.

- Fluoroscopy should be used to confirm when the helix is fully retracted.
- Rotation of fixation tool should be stopped once full helix retraction is visually verified.
- If helix is unable to extend, replace with a new lead and report the issue to Medtronic.

Fully Retracted – Stop Rotation



Potential Malfunction of CRT, ICD, and IPG Products due to Anomalies in MOSFET Integrated Circuit Technology

Medtronic has detected a specific pattern of MOSFET IC malfunctions in its Concerto, Virtuoso and EnRhythm family of devices. As of July 2009, Medtronic has confirmed twenty-eight (28) malfunctions related to this pattern out of 115,000 EnRhythm and 233,000 Concerto/Virtuoso products distributed worldwide. Reliability analysis of this pattern shows the probability of occurrence decreases with time and over 90% of the malfunctions related to the pattern had occurred within the first twelve months after implant. With process improvements in place, Medtronic expects few additional malfunctions related to this pattern.

The pattern involves metal-oxide-semiconductor fieldeffect transistors (MOSFET). A MOSFET is an electronic circuit used to amplify or switch electronic signals. MOSFETs have been used in the electronics industries for decades and MOSFET technology is the most widely used type of integrated circuit. Medtronic uses this technology in the circuitry of its CRT, ICD, and IPG products. Each product contains thousands of MOSFETs in its electronic circuitry.

Each MOSFET depends on a layer of insulating material to electrically isolate its components. The integrity of this insulating layer is important to the operation of the MOSFET. Variation in the thickness of the insulating layer can cause the MOSFET to operate in an undesirable manner. Process variations for electronic circuits can affect the integrity of the insulating material, and can lead to MOSFET malfunction. Medtronic's quality system strives to control process variation and detect undesired anomalies that are characteristic of all MOSFET manufacturing. In addition, Medtronic's post-market vigilance activities monitor malfunctions and may implement screening and testing improvements when a pattern of related malfunctions is identified. The pattern with the Concerto, Virtuoso and EnRhythm models has presented clinically as high lead impedance, sensing difficulty, loss of pacing therapy and/or early battery depletion due to higher than normal battery drain. The degree of battery drain varies case by case, such that the time from the onset to battery depletion has ranged from several days to several months. If not detected by normal patient follow-up procedures, the use of patient alerts or CareLink remote monitoring, the battery will fully deplete, leaving the patient without therapy.

As of March 2009, Medtronic has implemented additional electrical screening and stress tests to address this specific pattern for products being sold.

Since these rates of malfunction are low and the probability of occurrence decreases with time, Medtronic recommends physicians continue following patients in accordance with standard practice.

Clinical Management of VCM near Elective Replacement

Background

Medtronic Technical Services has received reports of devices going to ERI or end of life (EOL) sooner than expected after a normal follow-up in which the device longevity was projected to be approximately 18 months. It has been noted that these cases typically involve Kappa 700 devices where Ventricular Capture Management set the ventricular lead to high output (5 V, 1 ms), which occurs by device design when a high threshold is measured. It is important for physicians and allied professionals to understand VCM behavior as it relates to longevity so that they can, in turn, understand how this affects management of the device and follow-up visits as VCM equipped IPGs near the end of their expected longevity.

Device Longevity and VCM Behavior

Ventricular Capture Management is a feature that uses evoked response sensing to determine the stimulation threshold needed to capture the ventricular chamber. Proper detection of the evoked response is crucial to the VCM algorithm determining an accurate capture threshold. There are rare conditions, however, during which the VCM algorithm will not be able to measure the evoked response accurately.¹ When this occurs, for safety reasons the VCM algorithm will reprogram the output to 5 V, 1 ms until the subsequent VCM measurement.

If the device has considerable remaining longevity, these occasional excursions to high output do not substantially affect remaining longevity. However, if the device has less than approximately 18 months remaining longevity, there is the possibility that the high output condition caused by the 5 V, 1 ms output will drain the battery and trigger ERI.

When ERI is declared by the device, VCM is disabled and the outputs are left at 5 V, 1 ms until the device is reprogrammed at an in-office follow-up. This increased current drain of a high output condition will speed depletion of the device, possibly resulting in the device getting to the EOL (battery voltage ≤ 2.15 V).

Please note that the following parameter changes occur when the device goes to ERI:

Parameter	Value
Pacing Mode	VVI
Lower Rate	65 bpm
Single Chamber Hysteresis	OFF
Sleep Function	OFF
Ventricular Capture Management	OFF
Atrial Sensing Assurance	OFF
Ventricular Sensing Assurance	OFF

Kappa 700 is Medtronic's first-generation VCM algorithm, which has a relatively higher incidence of evoked response undersensing compared to subsequent algorithms, resulting in more frequent high output conditions. Therefore, Kappa 700 products are the primary focus of this note. It should be noted that IPGs equipped with the second-generation VCM algorithm (Kappa 900, EnPulse, Adapta/Versa/Sensia, and Relia) have not been observed with evoked response undersensing in the general population, though the items listed in "Follow-Up Considerations" may also be used on these devices.

Follow-Up Considerations

- Estimated longevity in the event the device goes to high output can be determined by the following steps. This allows the clinician to determine follow-up frequency if he or she is concerned the device may go to ERI due to high output.
 - Program the ventricular channel to 5 V, 1 ms
 - Navigate to Data/Battery and Lead Measurements
 - When the message stating "Warning Old Data" is displayed, select "Yes" to measure battery voltage and lead impedance at the new ventricular outputs
 - An updated remaining longevity estimate will be calculated on the elevated outputs. Note the "Minimum Remaining Longevity." Clinical decisions can be based on this value.
 - Program the Amplitude and Pulse Widths back to their original values before leaving the session
- If the capture trends and lead impedance trends are stable, VCM can be programmed to "Monitor Only" for the remaining device life. This should be considered only if remaining longevity is 18 months or less.
- Follow-up frequency can be increased for those patients who do not have stable capture or lead impedance trends. This can be done via a CareLink Home Monitor, or in-office.

¹ Medtronic, Inc. (2001). Medtronic Kappa 700/600 Series Pacemaker Reference Guide (Chapter 4, p. 27). Can be retrieved from http://manuals.medtronic.com.

Ensuring the Accuracy of Battery Longevity Estimates

Purpose of This Information

This article is intended to help the clinician understand how Medtronic estimates CRT-D, ICD, and IPG device longevity and Medtronic's performance against these estimates.

Device Longevity and Battery Depletion

The device service life ends when the usable battery capacity is depleted. The time to battery depletion depends on three factors:

- The amount of electrical energy expended in providing therapy to the patient
- The amount of energy consumed by the electronic circuitry to perform the functions of the device (e.g., operating the microprocessor, telemetry, memory, and charging component)
- The energy capacity of the battery

Medtronic has developed a statistical model for device longevity that accounts for each of these factors, and has validated the model with real time clinical performance. During the development of its products, Medtronic engineers characterize device longevity using this model. Testing begins during development and continues after market release to ensure the accuracy of device longevity estimates.

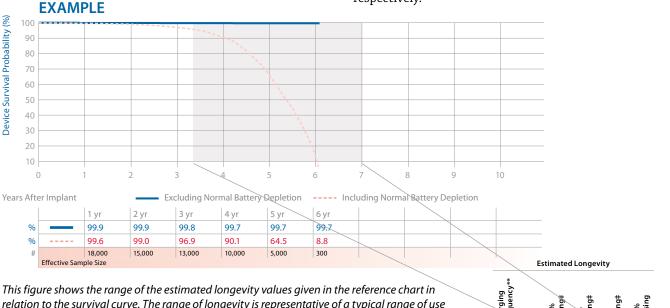
Using Survival Curves to Assess Longevity

The survival curves in the Product Performance Report represent the composite experience of thousands of devices over a wide range of programming options and patient use conditions. While the curves are useful for understanding the overall performance of a population of devices, they cannot be used to accurately predict the longevity of a specific device in a specific patient. To get a longevity prediction for a specific device, the longevity model must be used. The model is available by contacting Medtronic's Technical Services Department.

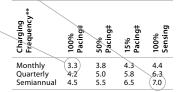
Because the survival curves are an aggregate result, the Reference pages in the Product Performance Report include several longevity estimates for a range of use conditions. These longevity estimates are mean values calculated for the parameters given. This range of longevity estimates can be compared to the survival curve including normal battery depletion to assess the overall clinical performance of a device model against the original longevity estimates.

If most of a device model's population is being used at nominal parameters and conditions, the time at which the survival curve including normal battery depletion equals 50% should approximate the midpoint in the range of longevity estimates.

If devices tend to be used at conditions that consume more or less energy than nominal, then the time at which the survival curve equals 50% should tend toward the lower or higher end of the range of longevity estimates, respectively.



This figure shows the range of the estimated longevity values given in the reference chart in relation to the survival curve. The range of longevity is representative of a typical range of use values, not the absolute minimum or maximum longevities possible. In this example, the survival curve including normal battery depletion is approaching 50% at approximately the mid-point of the range of longevity values.



AT500 Pacing System Follow-Up Protocol

Purpose of This Information

This article is intended to provide clinical guidance regarding follow-up practice and patient management when the AT500 battery voltage approaches the Elective Replacement Indicator (ERI) level of 2.6 volts.

Background

Many AT500 pacing systems are now reaching their ERI voltage level (2.6 volts). This is expected since the battery used has an approximate longevity of 5-6 years under normal conditions (100% DDD pacing, 3 volts, 0.4 ms).

Technical Services has received reports of battery voltage levels below end of life (EOL of 2.2 volts) where EGM prestorage is programmed ON, or higher outputs and/or pacing rates are necessary. It is important for physicians and allied professionals to understand battery depletion characteristics between ERI and EOL so that they, in turn, can understand how this affects management of follow-up visits for the AT500 as this device nears the end of its expected longevity.

AT500 Battery and Longevity Information

In contrast to other IPGs, the AT500 does not change its mode, stimulation rate, or any other parameter when the battery voltage drops below the ERI level of 2.6 volts (with or without magnet applied). The Threshold Margin Test (TMT) is also not available.

Therefore, it is not possible to perform transtelephonic assessment of AT500 battery status. This must be done during an in-clinic follow-up session. A warning will be displayed on the Quick Look screen at the beginning of a programmer (follow-up) session when the ERI battery level occurs. The measured battery voltage will also appear on the programmer display and on printouts.

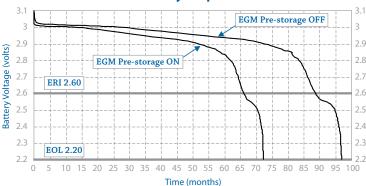
Battery depletion curves are shown in Figure 1, with special focus on device longevity when programming EGM prestorage ON or OFF.

Medtronic's review of ongoing AT500 battery life test data matches our original longevity modeling and so meets our expectations. However, when using longer durations between follow-up periods (> 3 months), clinicians should consider the following in setting their remaining longevity expectations.

- Enabling the "EGM Pre-storage On" capability will increase current and reduce device longevity by approximately
 9 days for each month pre-storage is ON
- Longevity decreases with an increase in pacing rate, an increase in pacing amplitude or pulse width, a decrease in pacing impedance, a higher ratio of paced to sensed events, or extended use of the Atrial Preference Pacing, EGM prestorage, or Holter Telemetry features

Recommendations

Follow-up frequency should always be accelerated as devices reach ERI voltage levels to ensure device explant/replacement occurs prior to end of life voltage levels. With the wide variety of follow-up schedules being used, Medtronic recommends a 3-month follow-up frequency for the AT500 pacing systems. This is particularly important for patients in whom EGM prestorage is programmed ON, or higher outputs and/or pacing rates are necessary.



AT500 Battery Depletion Curve

Figure 1

AT500 battery depletion curve for common parameter settings of DDDR, LR 70 ppm, UR 120 ppm, 100% pacing, Atrial – 2 V, 0.4 ms, 600 ohms, Ventricle – 2 V, 0.6 ms, 900 ohms, and EGM Pre-storage ON versus OFF.

Insertion of the Lead into the Device

The implantable system consists of a pulse generator and at least one lead. The system operation depends on proper electrical and mechanical operation. With the advent of internationally recognized connector standards, the challenge of ensuring proper mechanical fit between the lead and device connectors has been simplified, although the international connector standard does not address all aspects of the procedure for connecting a lead to the device.

If the lead connector is not fully installed, oversensing may result as described in the connector problems section of the performance note, "Clinical Management of High Voltage Lead System Oversensing."

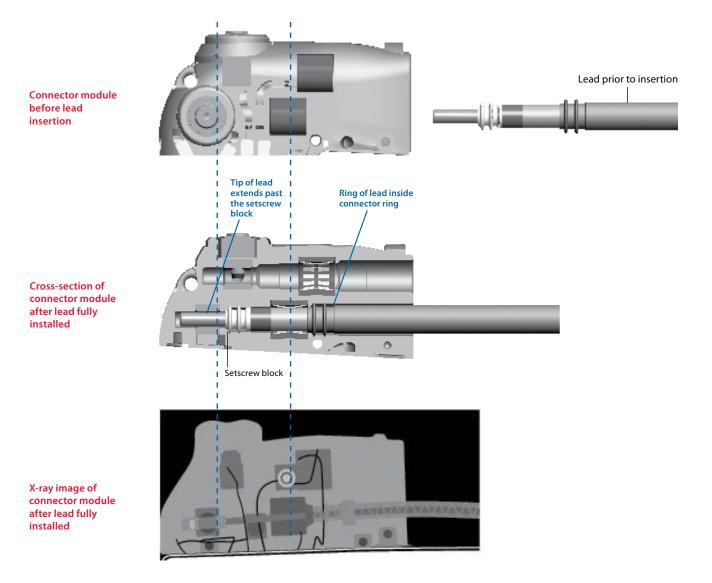
Performing the following steps can be used for each lead connection during the implant procedure:

1 Insert the torque wrench into the appropriate setscrew. For easier lead insertion, insert the lead closest to the device first.

- 2 Look down the connector port to verify that the port is not obstructed. If the port is obstructed, retract the setscrew to clear the bore. Take care not to disengage the setscrew from the connector block.
- **3** Push the lead into the connector port until the lead pin is clearly visible beyond the setscrew block.
- **4** Hold the lead in position while tightening the setscrew until the torque wrench clicks.
- **5** Tug gently on the lead to confirm a secure fit.

Current publications may provide additional information on implant procedures used by others, e.g., radiographic evaluation of the terminal pin beyond the terminal post.¹

¹ Pickett RA III, Saavedra P, Ali MF, Darbar D, Rottman JN. Implantable cardioverter-defibrillator malfunction due to mechanical failure of the header connection. *J Cardiovasc Electrophysiol*. September 2004;15(9):1095-1099.



GEM II DR/VR and GEM III DR/VR/AT ICD Battery Discharge Behavior

Medtronic manufactured and utilized a unique lithium/ silver vanadium oxide battery in the GEM II/III family of ICDs. This battery has a distinctive voltage discharge with two regions of constant voltage at 3.2 volts and 2.6 volts.

The battery discharge curve (see curve below) is characterized by a significant decrease in the battery voltage approaching middle of life (MOL), followed by a plateau (MOL to ERI) where the battery voltage remains around 2.6 volts. The transition to the plateau could be easily misinterpreted as the battery rapidly approaches ERI, which occurs at 2.55 volts, when the battery may in fact have several years remaining until ERI.

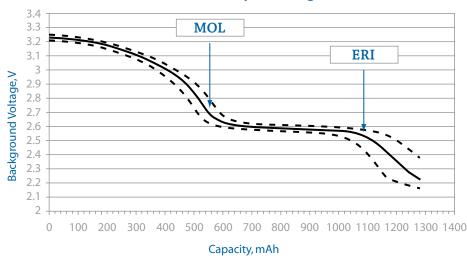
It is important to understand that this battery voltage decrease in the GEM II/III family of ICDs is a normal

characteristic of the battery function in these devices and should not create a need for additional follow-up or monitoring.

As a general rule of thumb, the longevity from implant to MOL = MOL to ERI.

The design of the battery in subsequently released models has been modified to present a more linear battery discharge curve.

If you are concerned about early ERI in your patient's device, you can utilize the battery trend measurements stored in the save-to-disk file, which can be accessed and interpreted through the Medtronic Technical Services at 1 (800) 723-4636.



GEM II/III Battery Discharge Curve

General Follow-Up and Replacement of ICD Leads

Implanted leads operate in the challenging biochemical environment of the human body and the body's response to foreign objects. Implanted leads are also subject to mechanical stresses associated with heart motion, body motion, and patient anatomy.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. Unlike implantable cardioverter defibrillators (ICDs), a lead's longevity cannot be predicted nor are there simple indicators that a lead is approaching the end of its service life. The determination that a lead may be approaching end of service life requires follow-up of the chronically implanted lead and thorough evaluation of lead integrity at ICD replacement.

Follow-Up of Chronically Implanted Leads

The frequency of follow-up for ICD patients will depend on a number of factors including the patient's medical condition, ICD system implant time, hospital/clinic follow-up practice, and Medicare guidelines. In all cases, it is important to assess the functionality of the ICD system and the integrity. For newly implanted leads, it is beneficial to establish a baseline of chronic performance parameters once the lead has stabilized, generally within 6 to 12 months after implant. These performance parameters should include pacing and sensing thresholds and impedance. During routine patient follow-up, these procedures can be used to evaluate lead integrity.

- Measure pacing and sensing threshold and compare to the chronic baseline. Significant increases or decreases may be indicative of lead failure, dislodgement, perforation, exit block, etc.
- Measure pacing impedance where possible and compare to the chronic baseline. Decreases of 30% or more or pacing impedances below 200-250 ohms may be indicative of insulation failure. Sudden and significant increases in pacing impedance may be indicative of conductor fracture.
- High voltage lead circuit impedance should be between 10-75 ohms at system implant. Chronic measurements below 10 and above 200 ohms may be indicative of high voltage lead circuit failure.
- Carefully review ECGs or the nonsustained detection log on Medtronic ICDs for indications of pacing and/or sensing abnormalities such as oversensing, undersensing, and loss of capture
- Elicit and investigate any patient complaints/symptoms that may be suggestive of potential lead failure

Where routine follow-up indicates, additional tools should be used to further evaluate performance. Tools include radiographic data, ICD electrograms, ICD Patient Alert and performance information from the Product Surveillance Registry (PSR).

The final decision on the functional integrity and continued use of an implanted lead must be a matter of medical judgment based on these factors as well as specific patient conditions.

General Criteria for Lead Replacement

The evaluation of a chronically implanted lead is an important part of the decision to continue to use the lead with a new ICD. However, these results alone do not necessarily predict the future integrity of that lead. With the expected longevity of today's ICDs varying between approximately 5 and 10 years, a physician replacing a device should consider a number of factors, including those listed below.

Factors that should be considered in a decision to replace or continue to use include:

- Pacing and sensing thresholds should be evaluated for the potential to maintain acceptable levels
- Pacing impedance should be measured. Bear in mind that pacing impedance below 250 ohms results in excessive battery current drain, which may seriously compromise ICD longevity, regardless of lead integrity.
- The physical appearance of the lead should be examined for insulation cracks, breaches, or other indications of lead wear or degradation
- Medtronic System Longevity Study data should be referenced. Actuarial survival of the lead and the observed lead failure mechanisms are specific factors to consider. Use of a new lead should be considered if failure mechanisms suggest an increased time dependency as suggested in the shape of performance curve for the specific lead model.
- Current publications may provide additional information on the clinical management of leads.¹⁻³ Ultimately, the decision to replace an implanted lead involves medical judgment.
- ¹ Hauser RG, Cannom D, Hayes DL, et al. Long-term structural failure of coaxial polyurethane implantable cardioverter defibrillator leads. *PACE.* June 2002;25(6):879-882.
- ² Ellenbogen KA, Wood MA, Shepard RK, et al. Detection and management of an implantable cardioverter defibrillator lead failure: incidence and clinical implications. *J Am Coll Cardiol.* January 1, 2003;41(1):73-80.
- ³ Hauser RG, Kallinen LM, Almquist AK, Gornick CC, Katsiyiannis WT. Early failure of a small-diameter high-voltage implantable cardioverter-defibrillator lead. *Heart Rhythm.* July 2007;4(7):892-896.

Clinical Management of High-Voltage Lead System Oversensing

Appropriate sensing by an ICD system refers to the sensing of cardiac events that may or may not require therapy delivery. ICD systems must sense relatively large QRS complexes while avoiding sensing of smaller T waves, yet continue to sense often small variable amplitude ventricular fibrillation. Thus, ICD systems attempt to dynamically adjust sensing of electrical events and discriminate between them based on detection algorithms and programmed settings.

Inappropriate sensing can occur when an ICD system classifies events of non-cardiac origin as QRS/VF events, or senses and counts T and far-field P waves as ventricular depolarizations. This is often referred to as "oversensing," and may result in delivery of inappropriate high-voltage therapies. This is due, in part, to the desire to err on the side of delivering lifesaving high voltage therapy rather than withholding it. Thus, an ICD system that is experiencing oversensing issues will continue to deliver therapeutic shocks as required, but may also subject the patient to unnecessary shocks.

Oversensing can be difficult to manage, in that the precipitating cause of the oversensing can be problematic to isolate. Oversensing can be caused by many factors, including myopotentials/farfield sensing, electromagnetic interference, T wave sensing, connector issues, incomplete or complete conductor fractures, and insulation breaches. While the individual physician must exercise medical judgment in determination of appropriate clinical management of ICD systems, the chart below may assist in the process of causal factor differentiation and possible intervention.

Phenomenon	Causal Factors	Characteristics	Management/Comments
Myopotentials/ Far-field sensing	Diaphragmatic muscle potentials in breathing, wide tip-to-ring (coil on integrated bipolar leads) spacing	Nonphysiological sensed event on EGM, which may confuse detection potentially resulting in false positive shocks	Check R waves for deterioration. Reprogram sensitivity. Try repositioning lead. Consider change-out to true bipolar lead, or if true bipolar lead in use, one with closer tip-to-ring spacing than current lead.
EMI (Electro-Magnetic Interference)	Arc welders, electrical generators, store walk-through security scanners, poorly insulated electrical equipment	Multiple and consecutive short intervals (< 140 ms) independent of underlying sinus beats. Associated with proximity to the EMI source.	Avoid EMI areas. True bipolar leads less susceptible.
T-wave sensing	Drugs, ischemic tissue, exercise, Long QT syndrome, electrolyte imbalance	Sense markers seen on EGM related to T wave. False positive detection.	Check for R wave deterioration and characteristics. If R wave > 3.0 mV, reprogram sensitivity. If R wave < 3.0 mV, reposition/replace lead. Address causal factor (e.g., drugs [if appropriate/medically viable]).
Connector problems	Loose setscrew, cross-threaded setscrew, incomplete lead insertion into header	This is an acute phenomenon seen within 6 months of implant (usually sooner)	Requires invasive check of connections. May be reproducible with pocket manipulation.
Incomplete conductor fracture	One or more filars of a multifilar conductor fracturing while leaving enough filars intact to provide a conduction circuit	Characterized by chaotic oversensing related to motion of the fracture site	Check EGMs and x-rays. Manipulate lead at suspected fracture site if possible as a provocative test. If confirmed, replace lead.
Lead insulation breach	Cuts, tears, metal ion oxidization, abrasion, cold flow, environmental stress cracking	Characterized by cyclical and/or erratic, intermittent, spontaneous oversensing; often post-pace or post-shock can cause false positives	Replace lead. If acute, usually secondary to implant damage/replacement damage. If late, material characteristic.
Oversensing during interrogation with programming head (not wireless telemetry) with complete lead fracture	Interrogation with a programming head in combination with complete lead fracture that creates an open circuit can induce noise on the sensing circuitry inside the ICD can	Nonphysiologic sensed event on EGM. If detection is enabled during interrogation, oversensing may result in inappropriate therapy.	Quickly remove the programming head. CANCEL the interrupted interrogation and manually load the software for the specific device model. Reposition the programmer head over the device and immediately select SUSPEND. Device will resume detection when programming head is removed, or when RESUME is selected. Replace lead.

Technical Services is available at all times to advise clinicians in the troubleshooting and management of Medtronic products. For assistance in the United States, please call 1 (800) 723-4636. In other countries, please contact your local Medtronic representative.

Tests and Observations for Clinical Assessment of Chronic Pacing Leads

Test/Observation	Possible Insulation Failure	Possible Conductor Failure	Possible Other System Failure	Effect on Test/ Observation
Pacing Impedance (Telemetered or Measured Invasively)	Sudden and Significant Decrease	Sudden and Significant Increase	Dislodgement. Perforation. Electrolyte Imbalance. Improper IPG/Lead Connection	Increase or Decrease Increase or Decrease
Pacing Thresholds (Telemetered/Programmed or Measured Invasively)	Sudden and Significant Increase, Especially in Bipolar System	Sudden and Significant Increase	Dislodgement. Exit Block. Infarct at Electrode Site. Perforation. Improper IPG/Lead Connection	Increase Increase Increase
Electrograms (Telemetered or Measured Invasively)	Sudden and Significant Decrease in Amplitudes and/or Slew Rates for P and/or R Waves	Sudden and Significant Decrease or Disappearance of Amplitudes and/or Slew Rates for P and/or R Waves	Dislodgement. Perforation Infarct at Electrode Site Electrolyte Imbalance Improper IPG/Lead Connection	Decrease Decrease .Decrease
Waveform Analysis (Oscillographs of Pacer Artifact from ECG Electrodes)	Sudden Increase in Ratios of Leading-Edge Voltages to Trailing-Edge Voltages (i.e., over 25% increase)	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)	Improper IPG/Lead Connection	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)
Radiographs (Post-Implant, Recent, Current)	Not Discernible	Visual Observation of Conductor/Connector/ Electrode Fracture (Sometimes Discernible)	Dislodgement or Perforation. Improper IPG/Lead Connection.	Sometimes Discernible
Visual Inspection (Invasive)	Insulation Breach and/or Degradation, or Ligature Cut-Through	Not Easily Discernible	Connector Defect or Connector Pulled Apart. Improper IPG/ Lead Connection.	Sometimes Discernible
Pectoral Muscle Stimulation	Sudden Onset, Especially in Bipolar System		Connector Defect in Bipolar or Unipolar. Hypersensitivity to Unipolar Pulse Generator Can. Anti-Stim Coating or Protection Deficient.	
Phrenic Nerve/ Diaphragmatic Stimulation	Sudden Onset in Bipolar or Unipolar Systems		Perforation or Displacement of Atrial Lead (Phrenic Nerve)	
Pacemaker ECG Stimulus Artifact Size and Morphology Change (May Not Be Possible with Digital ECG)	Sudden Onset and Significant Change, Especially in Bipolar System (Increase in Size)	Sudden Changes, Usually a Decrease in Size	Perforation or Dislodgement. Connector Defect. Improper IPG/ Lead Connection.	Sometimes Discernible
Oversensing (Intermittent or Continuous)	Sudden Onset, Especially in Bipolar Systems		Physical Contact between the Electrode(s) on the Lead and that of Another Lead. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	Sometimes Discernible
Undersensing (Intermittent or Continuous)	Sudden Onset in Either Unipolar or Bipolar Systems	Sudden Onset in Either Unipolar or Bipolar Systems	Dislodgement or Perforation. Infarct at Electrode Site. Electrolyte Imbalance. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	Sometimes Discernible
Loss of Capture	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	

Performance Notes

Mailer Kits Available for Returning Product

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use. The procedures for returning products vary by geographic location.

Mailer kits with prepaid US postage are available for use within the United States to send CRT, ICD, IPG, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet US postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of devices from non-clinical sources, such as funeral homes, and will assume responsibility for storage and disposal of the product once received.

Mailer kits can be obtained by contacting the Returned Product Lab.

CRDM Returned Product Analysis Laboratory Phone: 1 (800) 328-2518, ext. 44800 Email: crdm.returnedproduct@medtronic.com



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